

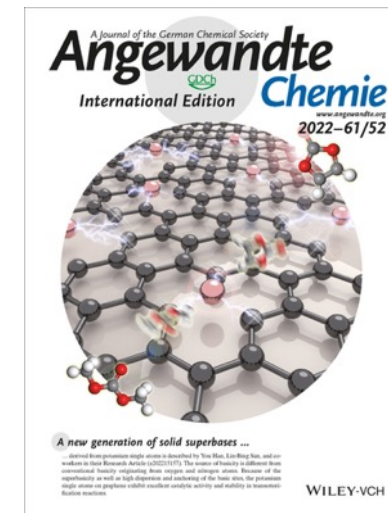
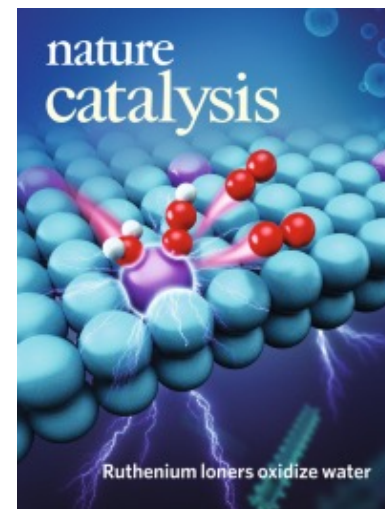
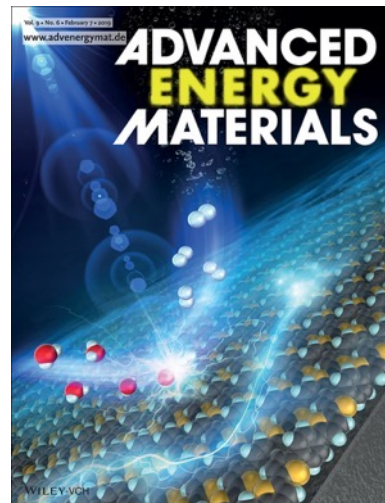
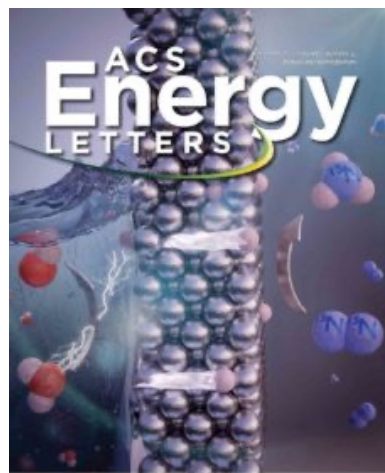
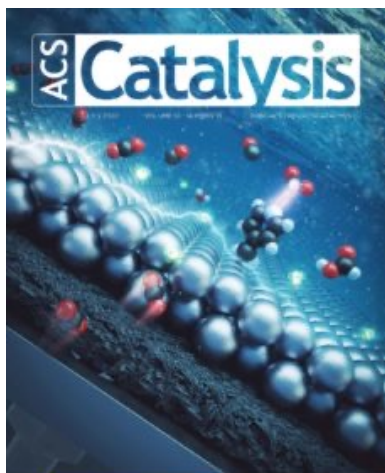
X-ray Photoelectron Spectroscopy (XPS)

Ira Waluyo

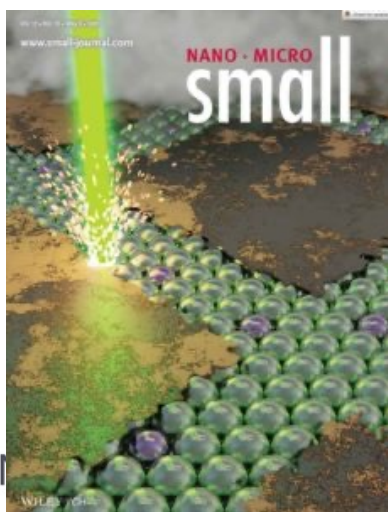
IOS (23-ID-2) Lead Beamline Scientist

NSLS-II, Brookhaven National Laboratory

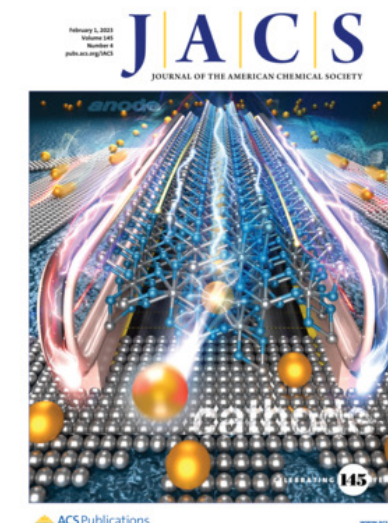
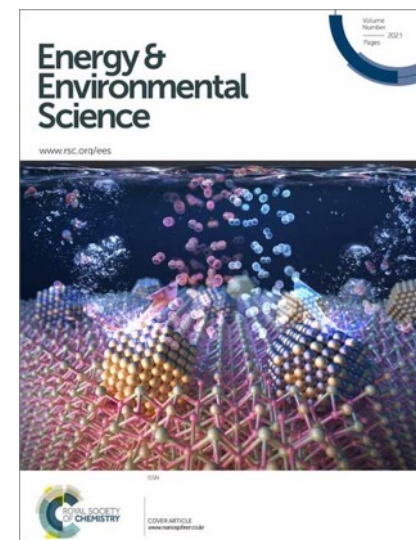
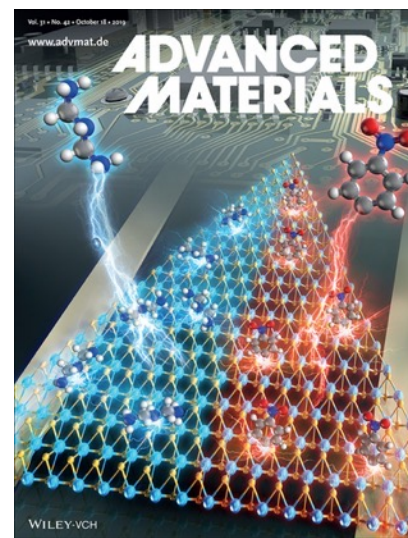
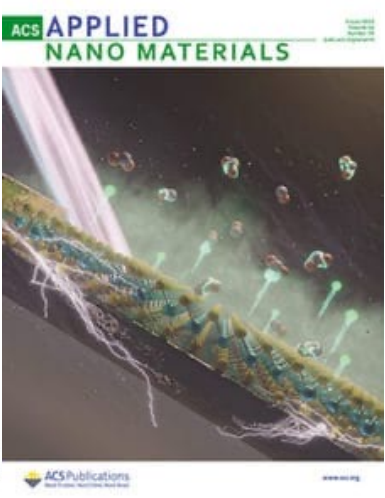
iwaluyo@bnl.gov



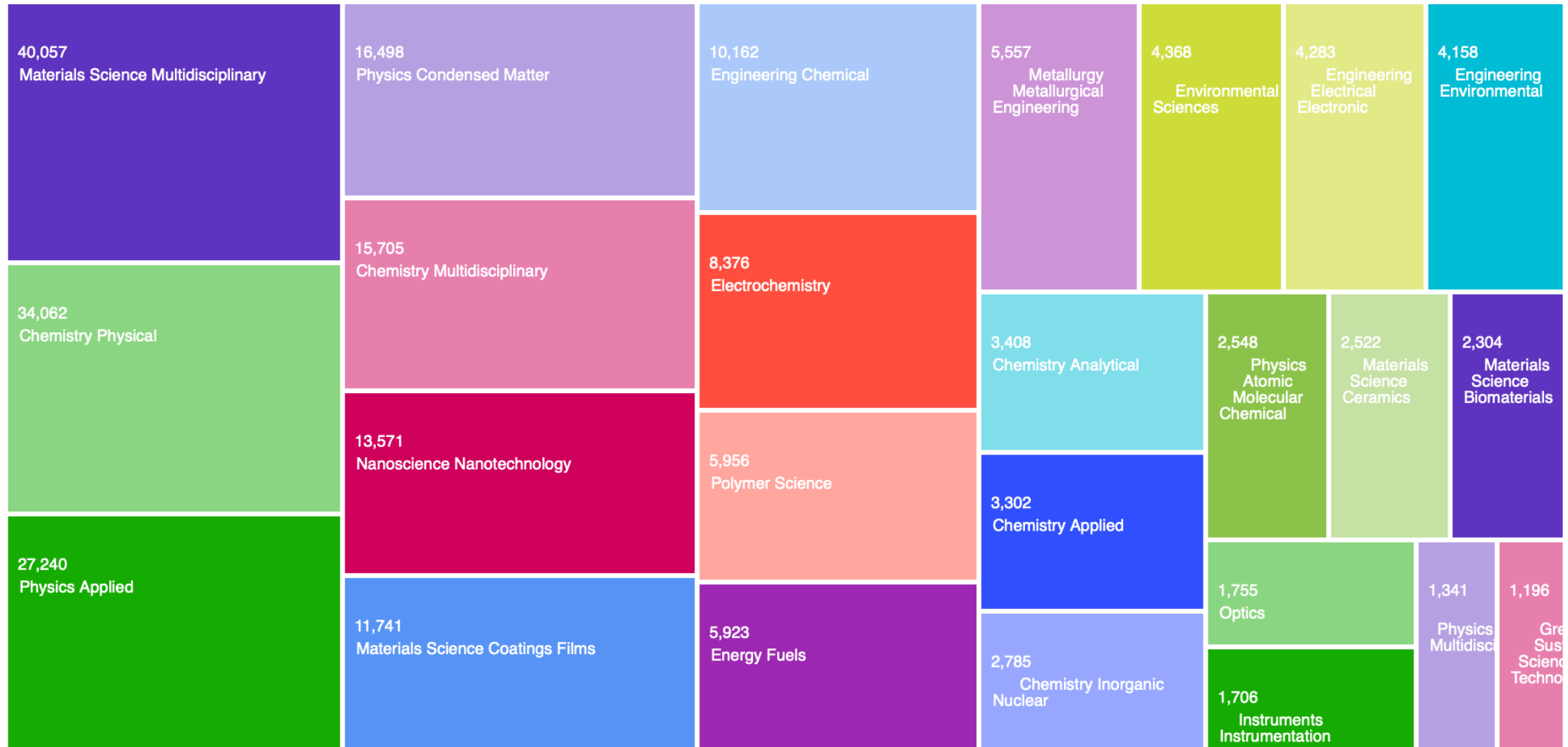
X-ray photoelectron spectroscopy (XPS) was featured in all of these research



Lig

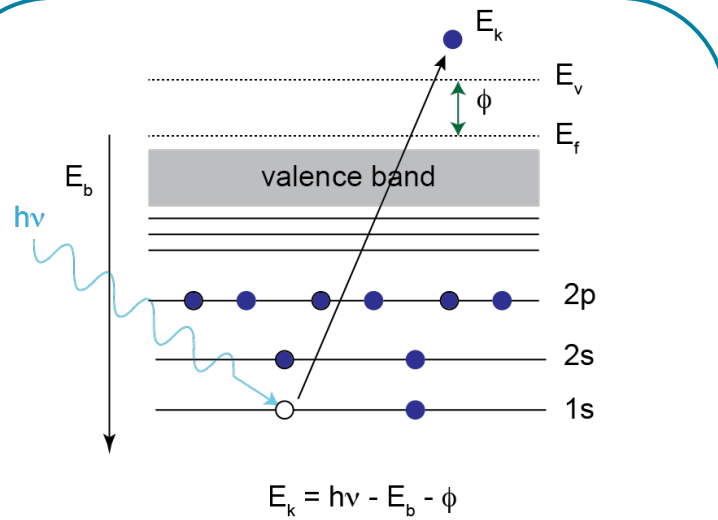


XPS is a powerful and versatile technique for studying the chemical and electronic state of surfaces as well as understanding phenomena and processes occurring on surfaces

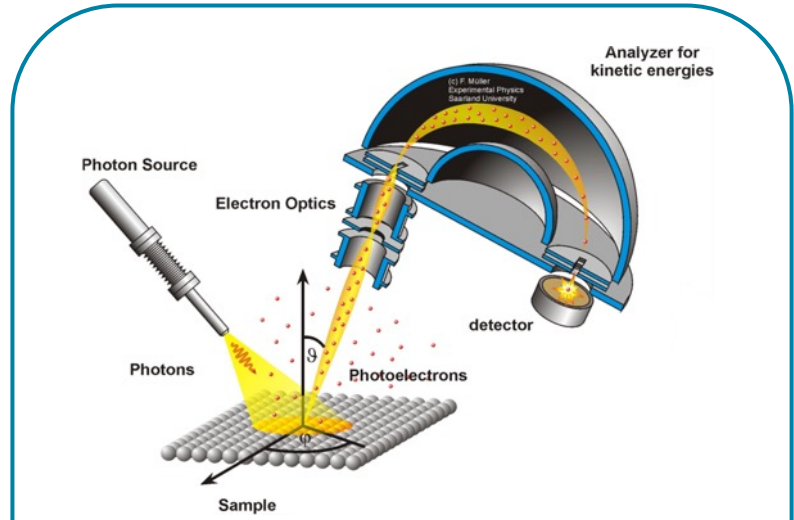


Webofscience.com search result from 2003-2023

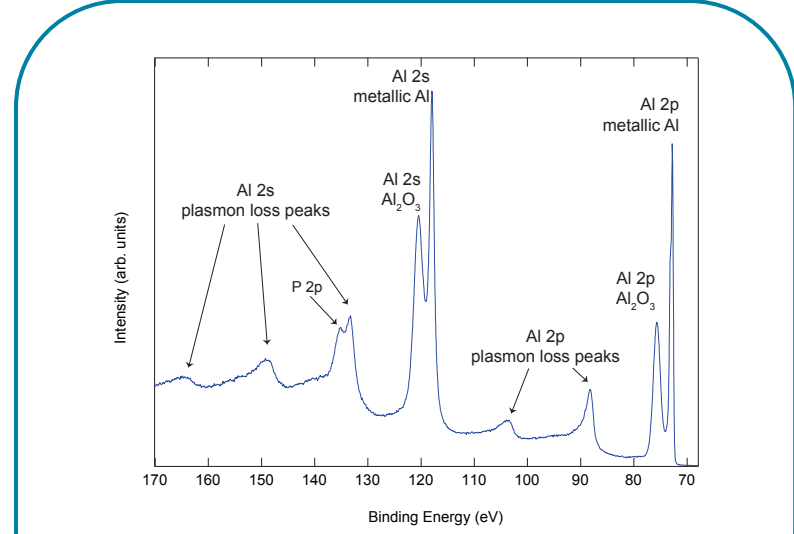
What will you learn today?



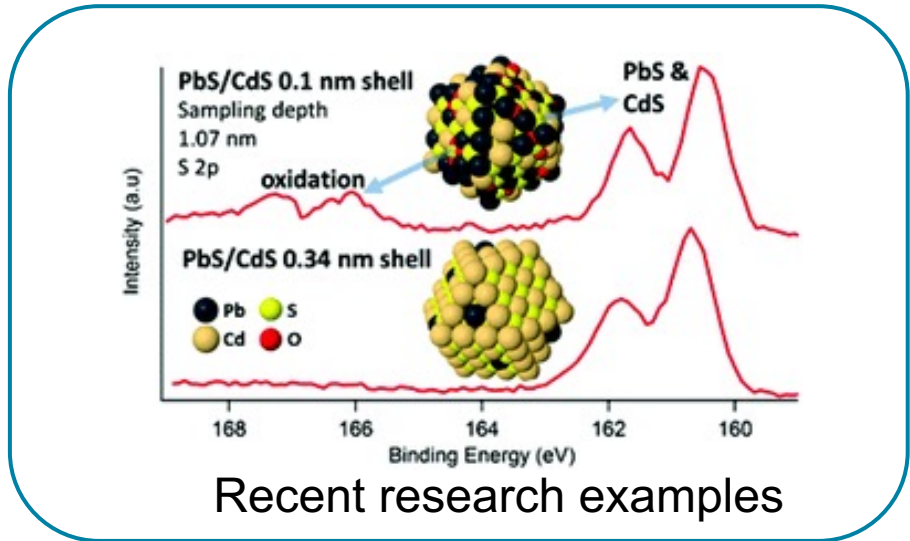
Fundamental principles of XPS



Basic instrumentation and experimental planning



How to interpret XPS data



Recent research examples

Part 1

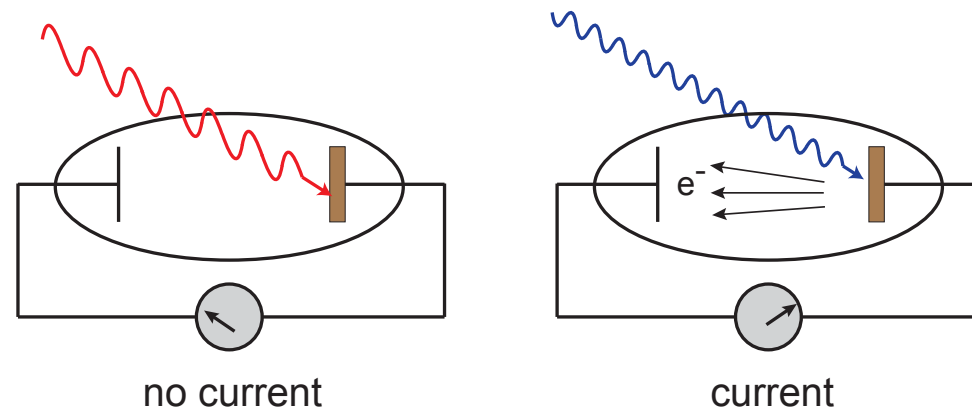
Basic Principles of XPS and Instrumentation

A little history: From the photoelectric effect...

1887 – Heinrich Hertz observed sparks when UV light hits metal electrodes.

1899 – J. J. Thomson discovered that UV light causes particles to be emitted. The particles were the same as the ones found in cathode rays (i.e. electrons).

1902 – Philipp Lenard found that the energy of the emitted electrons depend on the color (i.e. frequency) of the light, not intensity.



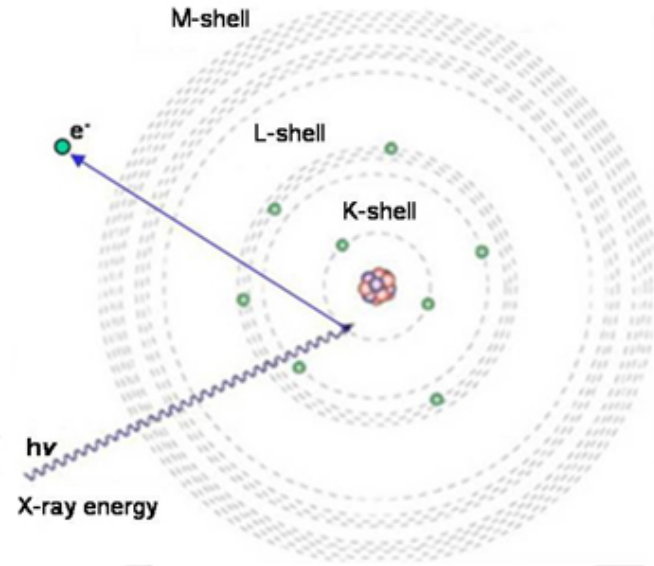
1905 – Albert Einstein explained this phenomenon. Light is composed of discrete packets of energy called “quanta” (later “photons”) – Nobel Prize in Physics (1921).

...to Modern XPS

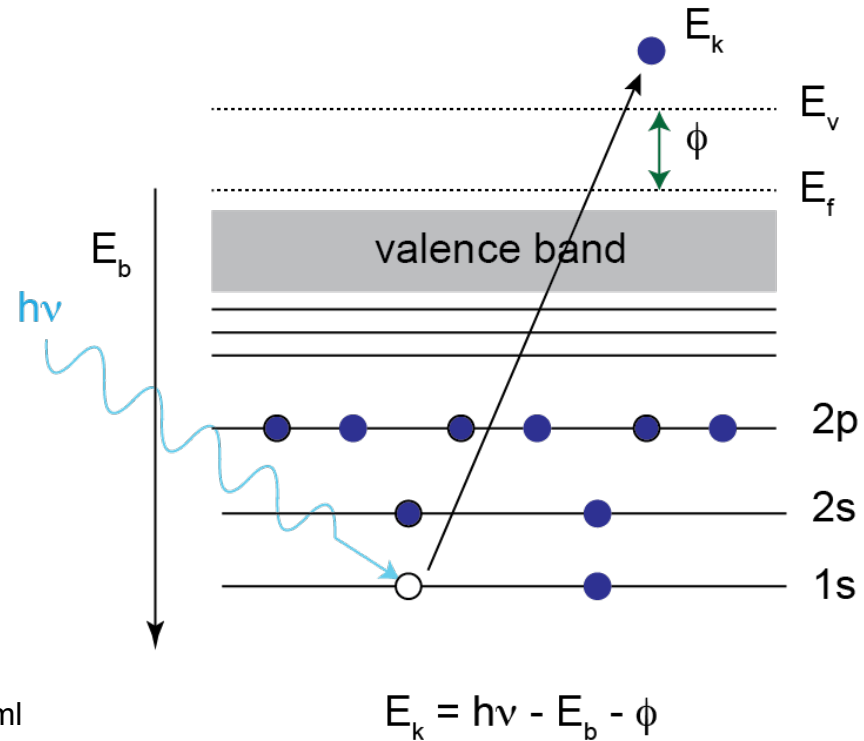


- Kai Siegbahn developed an instrument for analyzing emitted photoelectrons and used it for chemical analysis
- The technique was called Electron Spectroscopy for Chemical Analysis (ESCA)
- Awarded Nobel Prize in Physics in 1981

Basic Principle of XPS

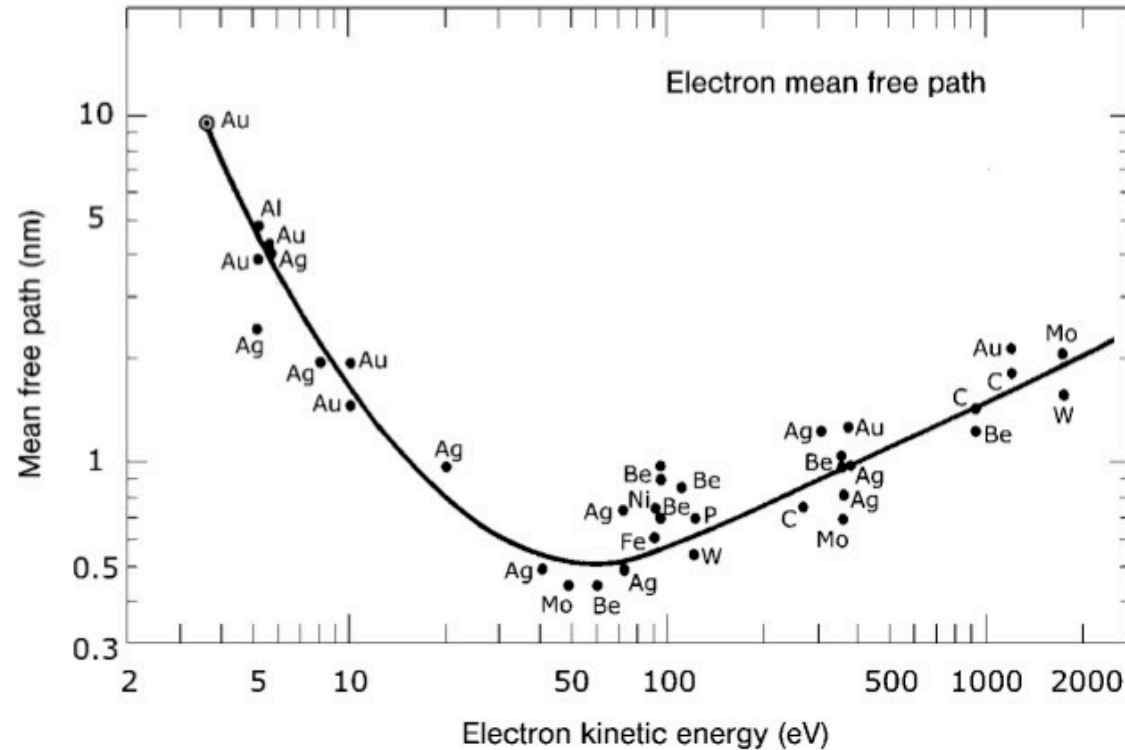


<https://www-ssrl.slac.stanford.edu/nilssongroup/corelevel.html>



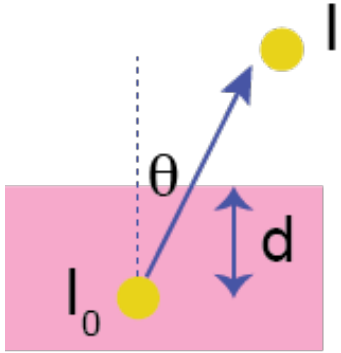
- X-ray photon ionizes an atom and causes the emission of a photoelectron.
- Kinetic energy of the photoelectrons depends on:
 - Energy of the incident X-ray photons
 - Binding energy of the electron
 - Work function of the sample (in practice we use the work function of the spectrometer)

Why is XPS Surface Sensitive?



- Inelastic mean free path (IMFP): how far can an electron travel before losing energy
- IMFP depends on electron energy and density of the material
- The “Universal Curve” shows the typical IMFP for electrons in a solid
- Typical IMFP (λ) is 5-20 Å for soft X-ray excitation

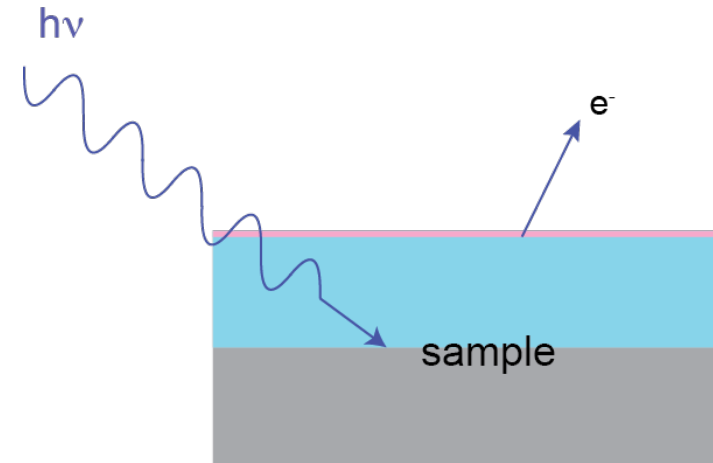
Sampling Depth



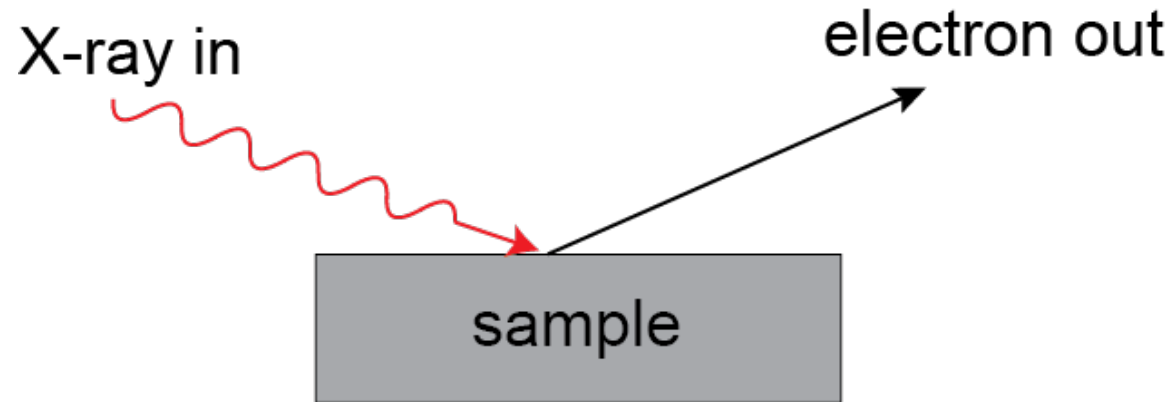
$$I = I_0 e^{-d/\lambda \cos \theta}$$

- Assuming normal takeoff angle ($\theta = 0$, $\cos \theta = 1$)
- For $d = 3\lambda$, $I = \sim 0.05 I_0$
- This means 95% of electrons come from depth of 3λ
- Typical sampling depth = 1-5 nm

- Photons have greater penetration depth than electrons
- Photons: 100's nm for soft X-ray (<2000 eV)
- But you can only get electrons from the first top 1-5 nm
- This makes XPS highly surface sensitive



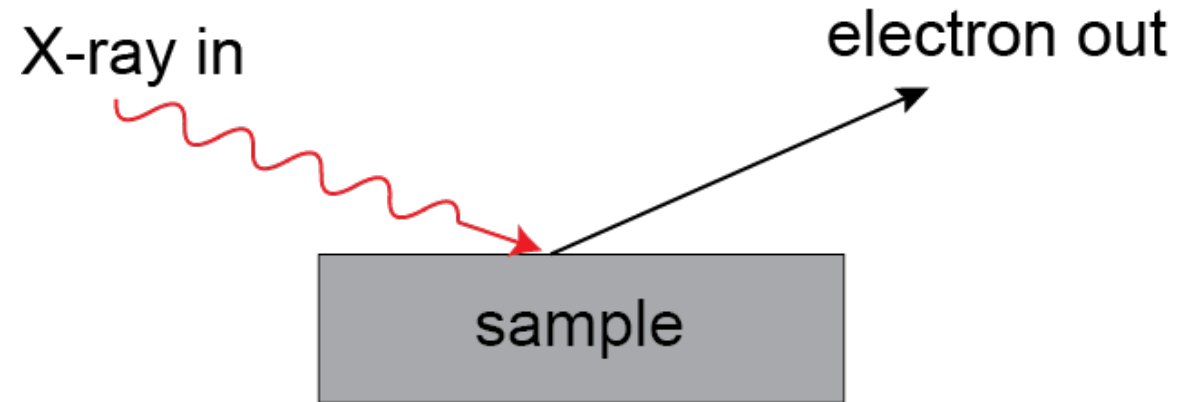
Basic Instrumentation



Three basic requirements:

1. We need an X-ray source
2. We need to be able to detect the electrons
3. We need the appropriate experimental environment

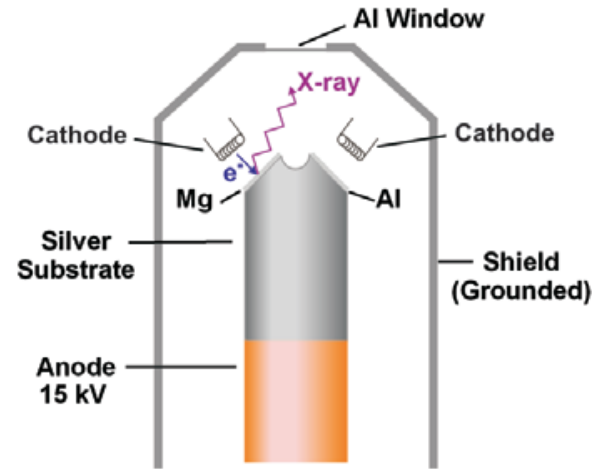
Basic Instrumentation



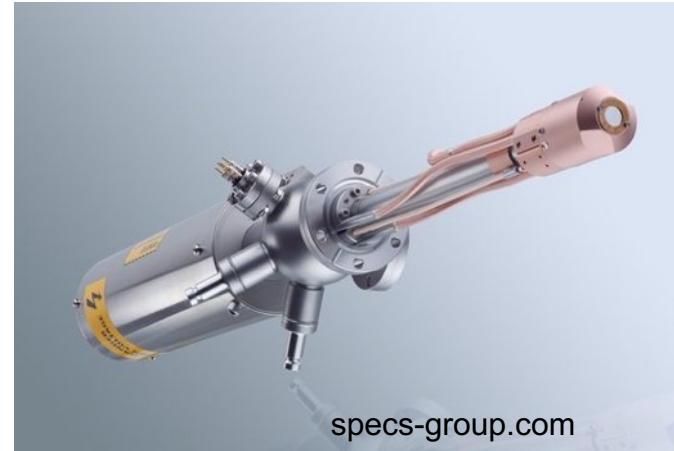
Three basic requirements:

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X-ray Source – X-ray anode (“lab source”)



thermofisher.com



Pros:

- Cheaper than building a synchrotron
- Commonly available in research labs and shared university facilities

Cons:

- Fixed energy - various consequences
- Lower flux
- Poorer resolution

ANODE	RADIATION	ENERGY (EV)	LINE WIDTH (EV)
Mg	K α	1253.6	0.7
Al	K α	1486.8	0.85
Zr	L α	2042.4	1.6
Ag	L α	2984.3	2.6

thermofisher.com

X-ray Source - Synchrotron

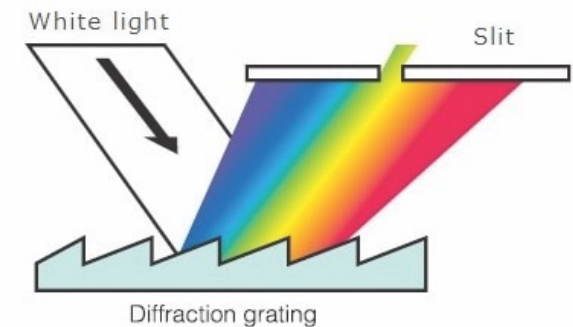


Pros:

- Tunable energy, usually 100-2000 eV for soft XPS, 2000-6000 eV for HAXPES
- Higher flux
- Higher resolution
- Beamtime is free

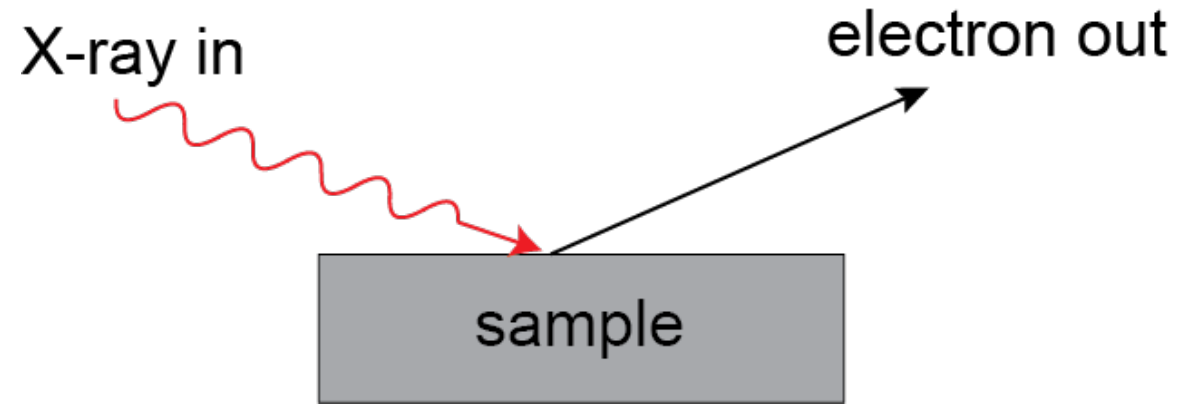
Cons:

- Not too many facilities available
- Beamtime can be competitive (you need to do good science!)



shimadzu.com

Basic Instrumentation

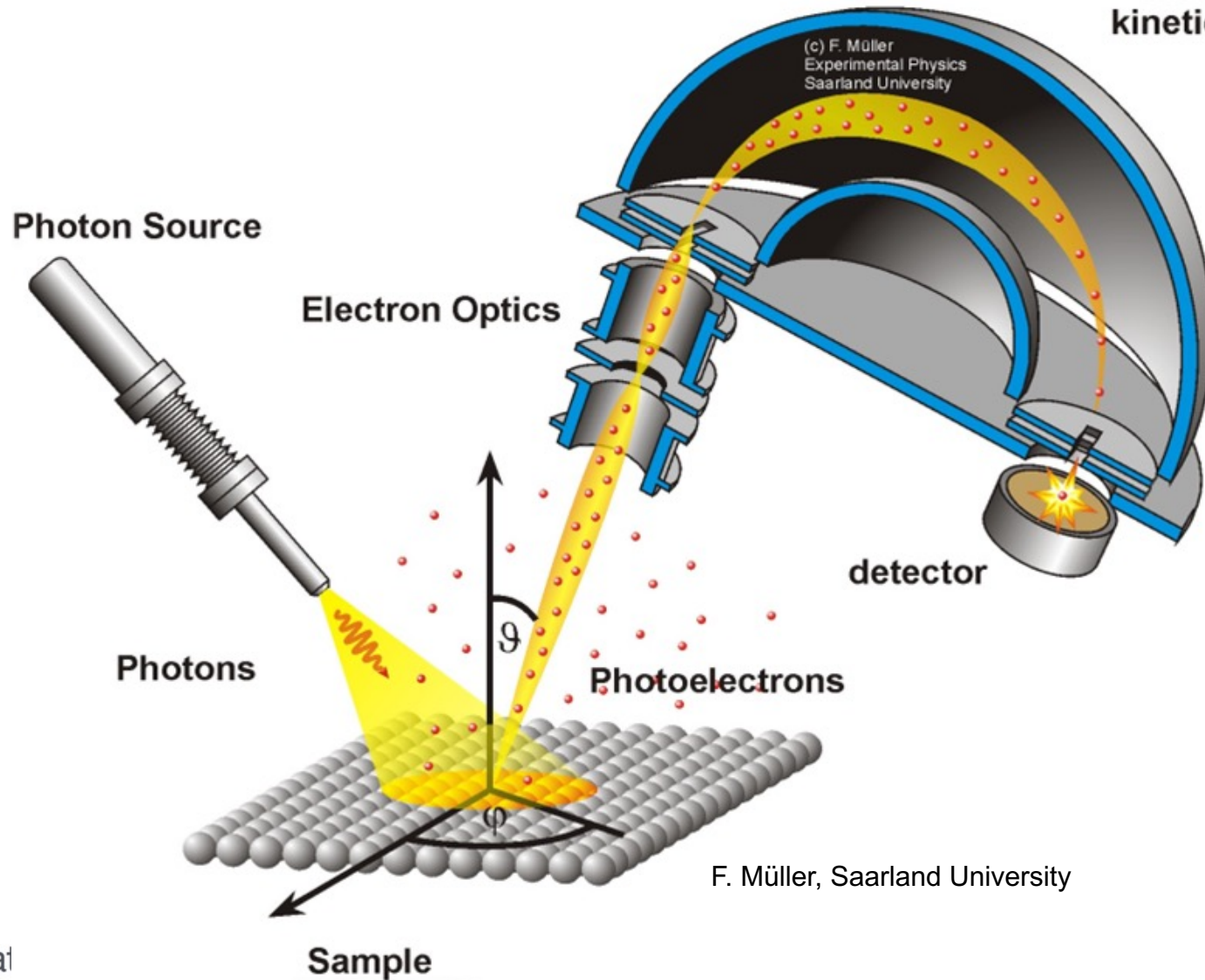


Three basic requirements:

1. We need an X-ray source
2. We need to be able to detect the electrons
3. We need the appropriate experimental environment

Detecting Electrons

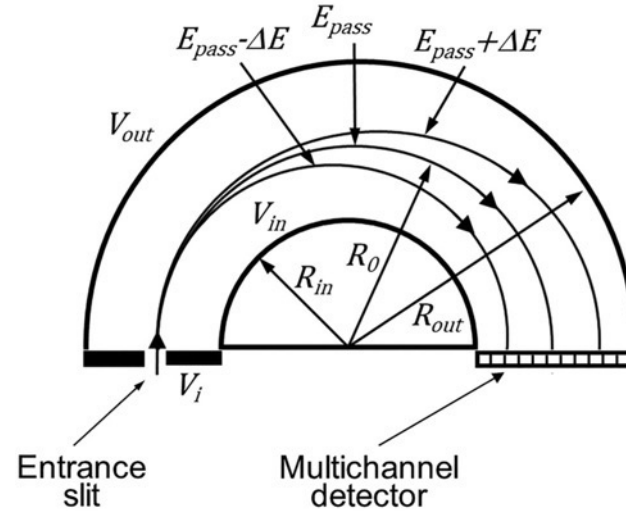
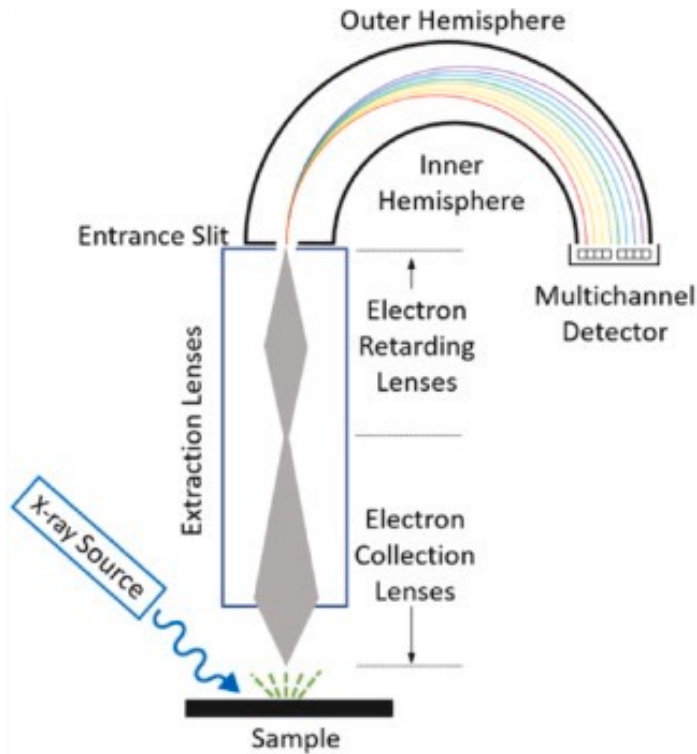
Analyzer for kinetic energies



The most common electron spectrometer:
Hemispherical electron analyzer



Hemispherical Electron Analyzer



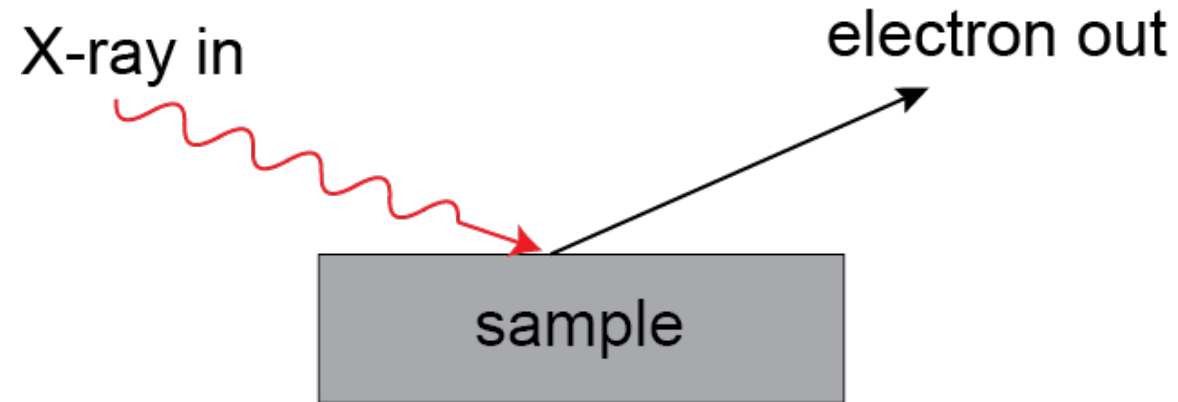
$$\Delta E = E_0 \left(\frac{W}{2R} + \frac{\alpha^2}{2} \right)$$

ΔE = energy resolution
 E_0 = electron energy
 W = slit width
 R = mean radius
 α = acceptance angle

- Electrostatic lenses focus electron to the detector
- Electron kinetic energy is adjusted to the same pass energy (E_p)
- To improve resolution, you need to:
 - Use lower pass energy
 - Decrease slit width

$$\Delta E = E_p \left(\frac{W}{2R} + \frac{\alpha^2}{2} \right)$$

Basic Instrumentation



Three basic requirements:

1. We need an X-ray source
2. We need to be able to detect the electrons
3. We need the appropriate experimental environment

Sample Environment

- Electrons can't travel very far in a gas environment (short mean free path)
- A 200 eV electron can only travel 1 mm in 1 Torr gas (atmospheric pressure is 760 Torr)
- Need to minimize collision between electrons and gas molecules
- XPS needs ultra-high vacuum chamber (10^{-8} - 10^{-10} Torr)
- Sample surface also needs to be kept clean from surface contamination



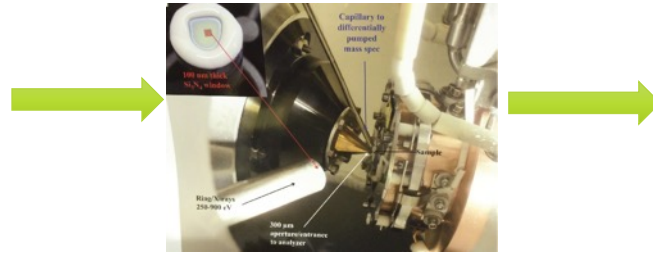
vacgen.com

Ambient Pressure XPS

XPS needs vacuum, but vacuum is not real life!



UHV surface science ($<10^{-9}$ Torr)



Ambient pressure XPS

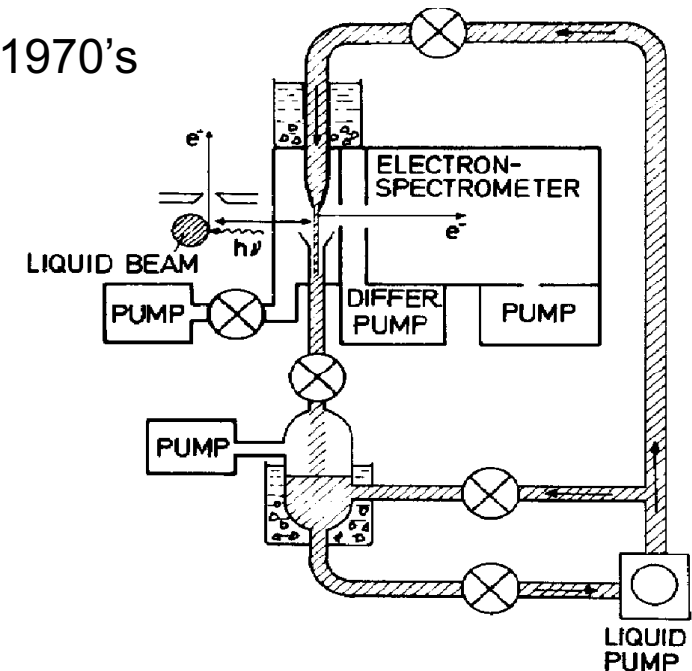


Industry (> 760 Torr)

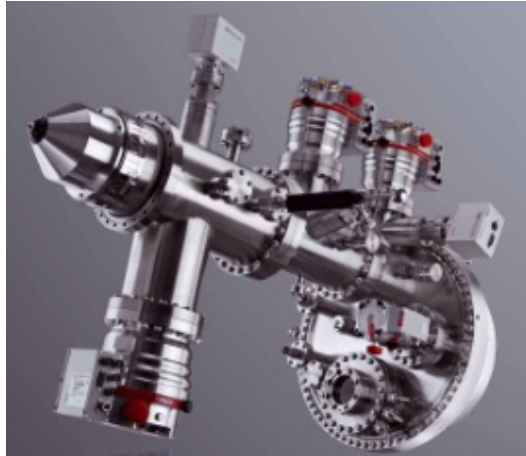
The first AP-XPS instrument was built by Kai Siegbahn's group in the 1970's (H. Siegbahn and K. Siegbahn, J. Electron. Spectrosc. Relat. Phenom. 2, 319 (1973))

Applications in:

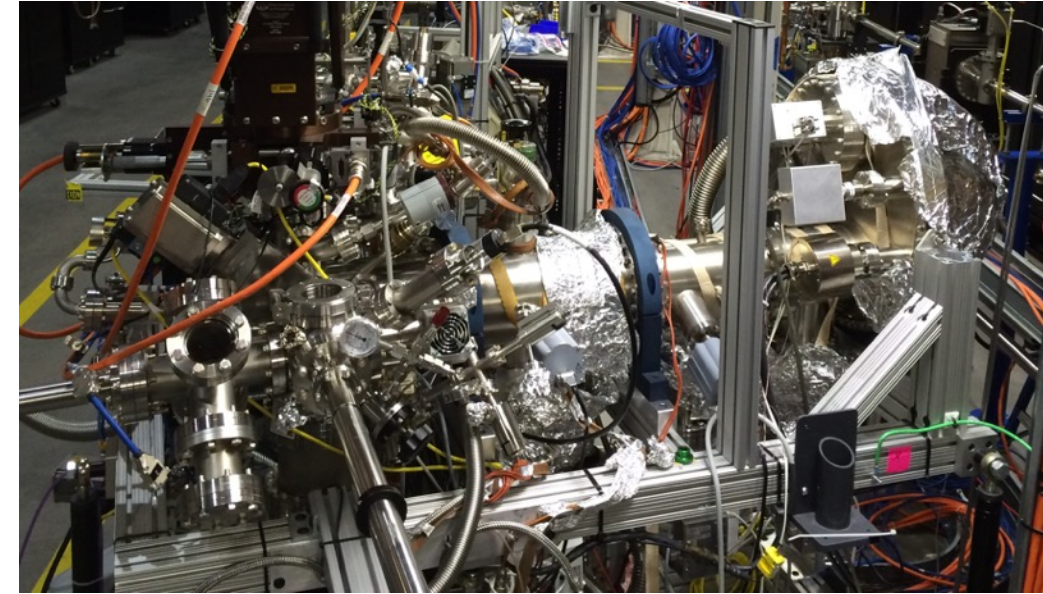
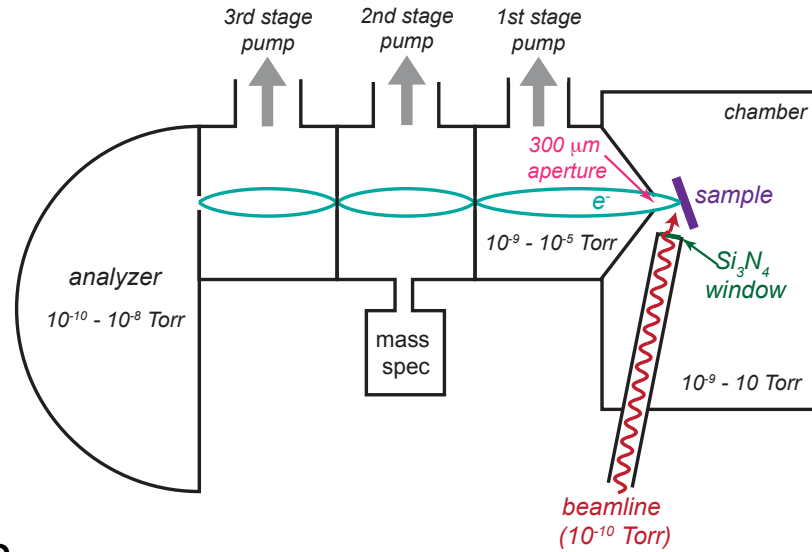
- Heterogeneous catalysis
- Electrochemistry
- Energy storage
- Corrosion science
- Quantum information science
- Environmental science
- Atmospheric chemistry
- and many more...



AP-XPS Instrumentation



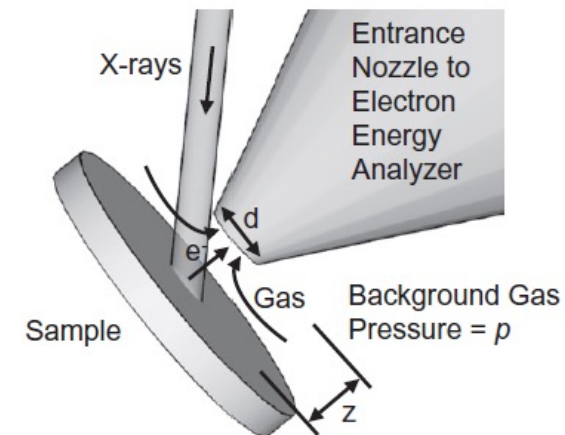
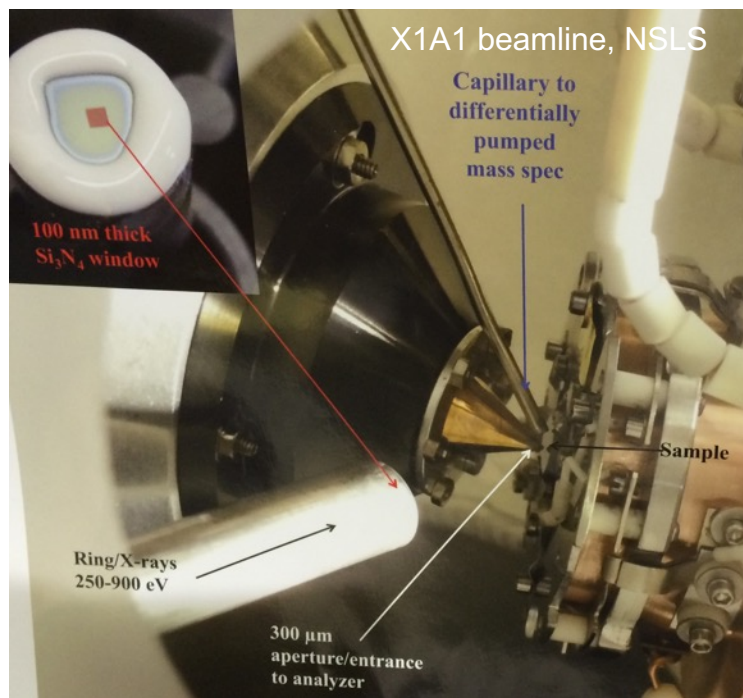
SPECS Phoibos 150 NAP
specs-group.com



AP-XPS endstation at IOS beamline, NSLS-II

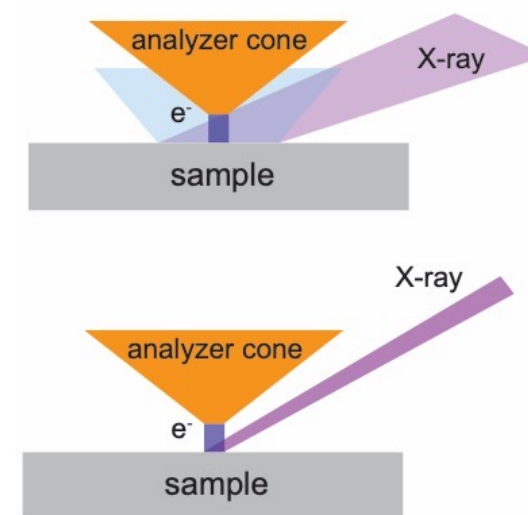
- By differentially pumping the electron analyzer, the pressure in the chamber can be raised while maintaining UHV in the analyzer
- Electrostatic focusing lenses needed to focus electrons to the analyzer

AP-XPS Experimental Setup



Starr et al. DOI:10.1002/9781118355923.ch12

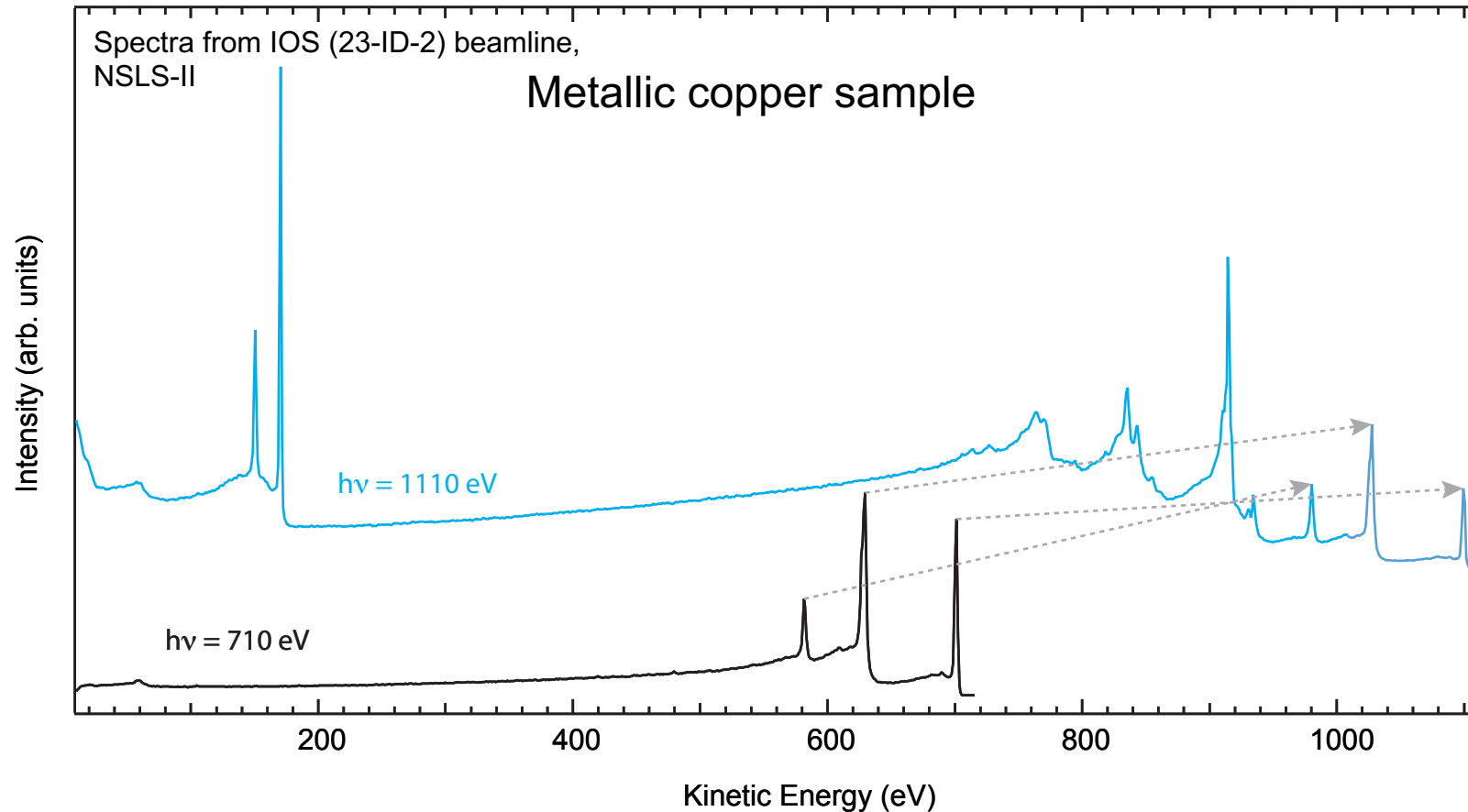
- A small aperture is needed to restrict the flow of gases into the analyzer
- Aperture diameter $\sim 100 \mu\text{m}$ to $500 \mu\text{m}$ (smaller aperture \rightarrow higher pressure)
- Sample needs to be close to aperture to minimize scattering by gases
- Small beam size is important!
- Chamber and beamline are separated by 100 nm thick Si_3N_4 window



Part 2

Understanding XPS Spectra

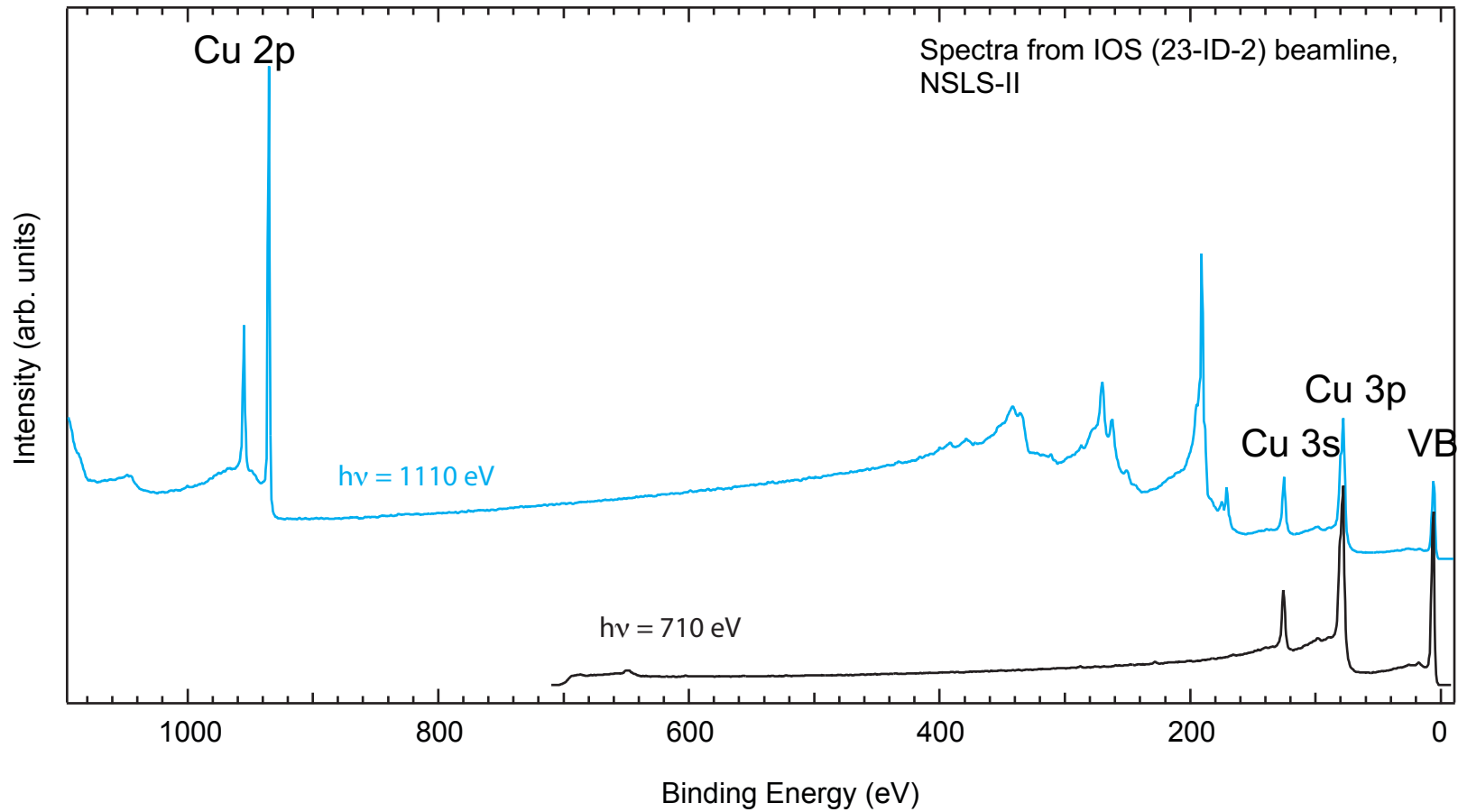
What do you get from the analyzer?



If you change the energy of the X-ray, the electron kinetic energy also changes

Convert to binding energy

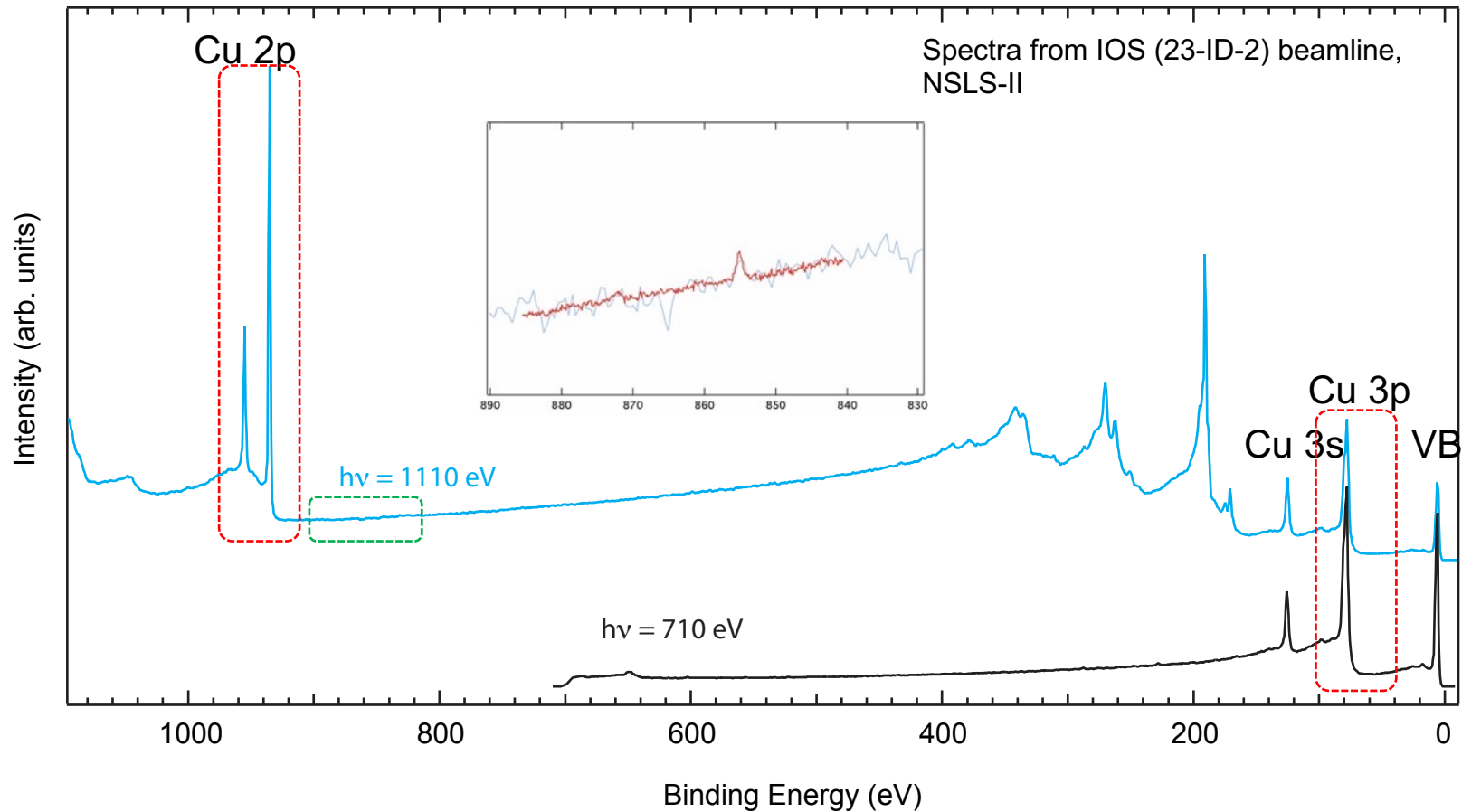
$$E_b = h\nu - E_k - \phi$$



Electron binding energy is fixed at any photon energy

Convert to binding energy

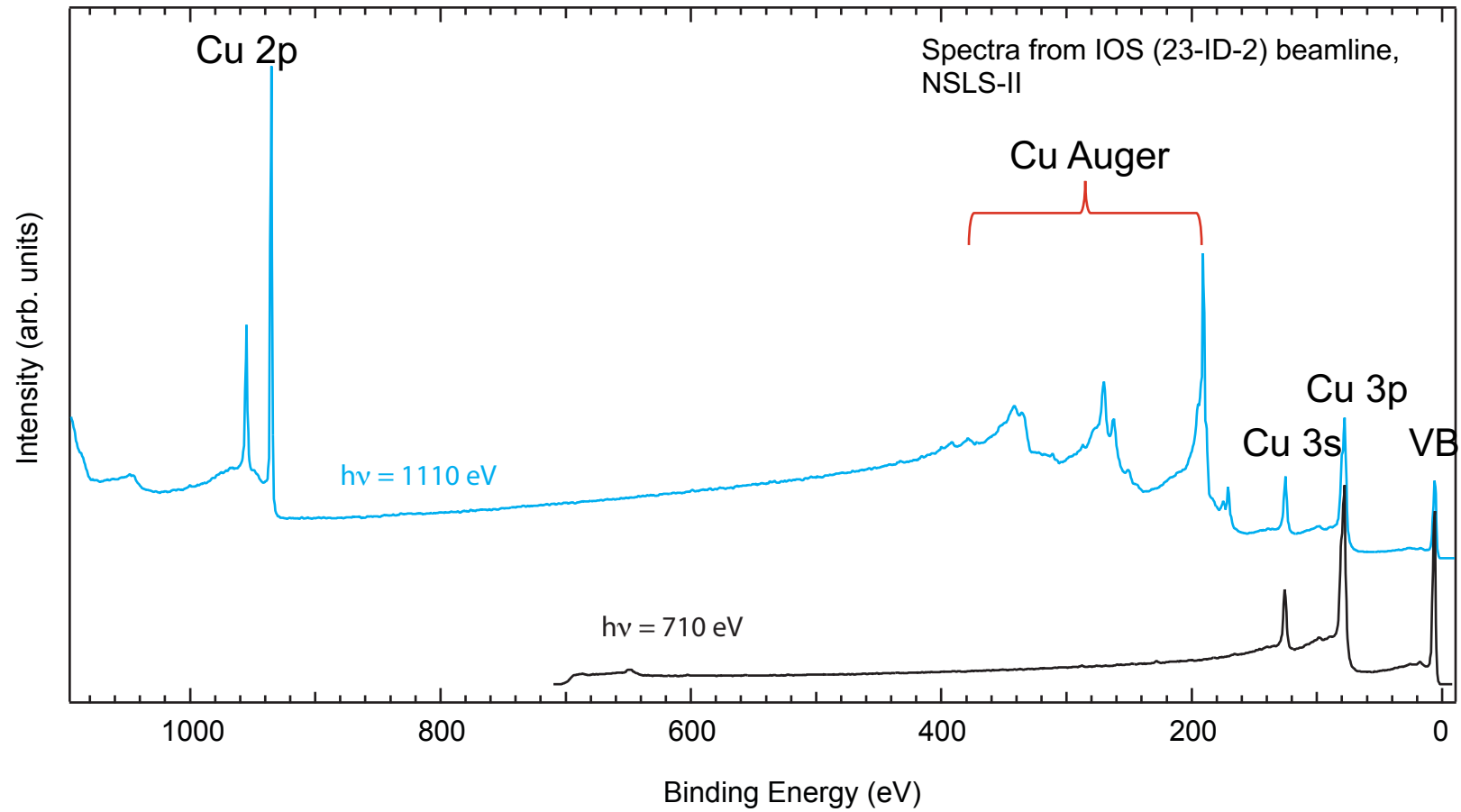
$$E_b = h\nu - E_k - \phi$$



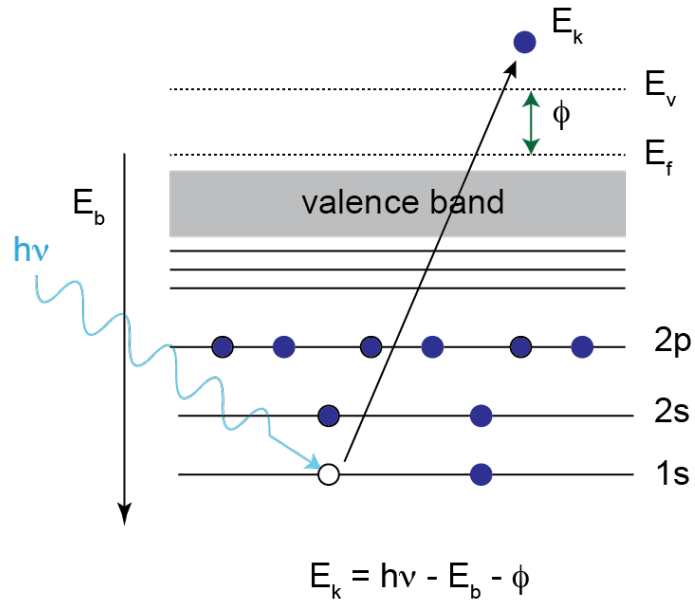
Select your scan regions, scan at smaller step size, and take multiple scans to improve signal-to-noise ratio

Auger Peaks

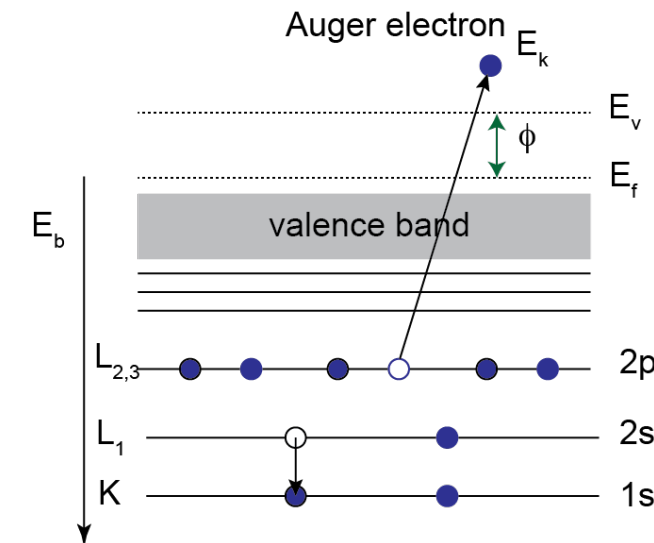
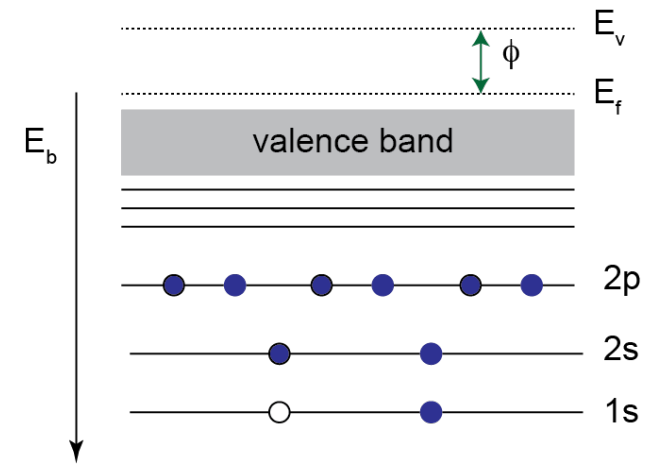
$$E_b = h\nu - E_k - \phi$$



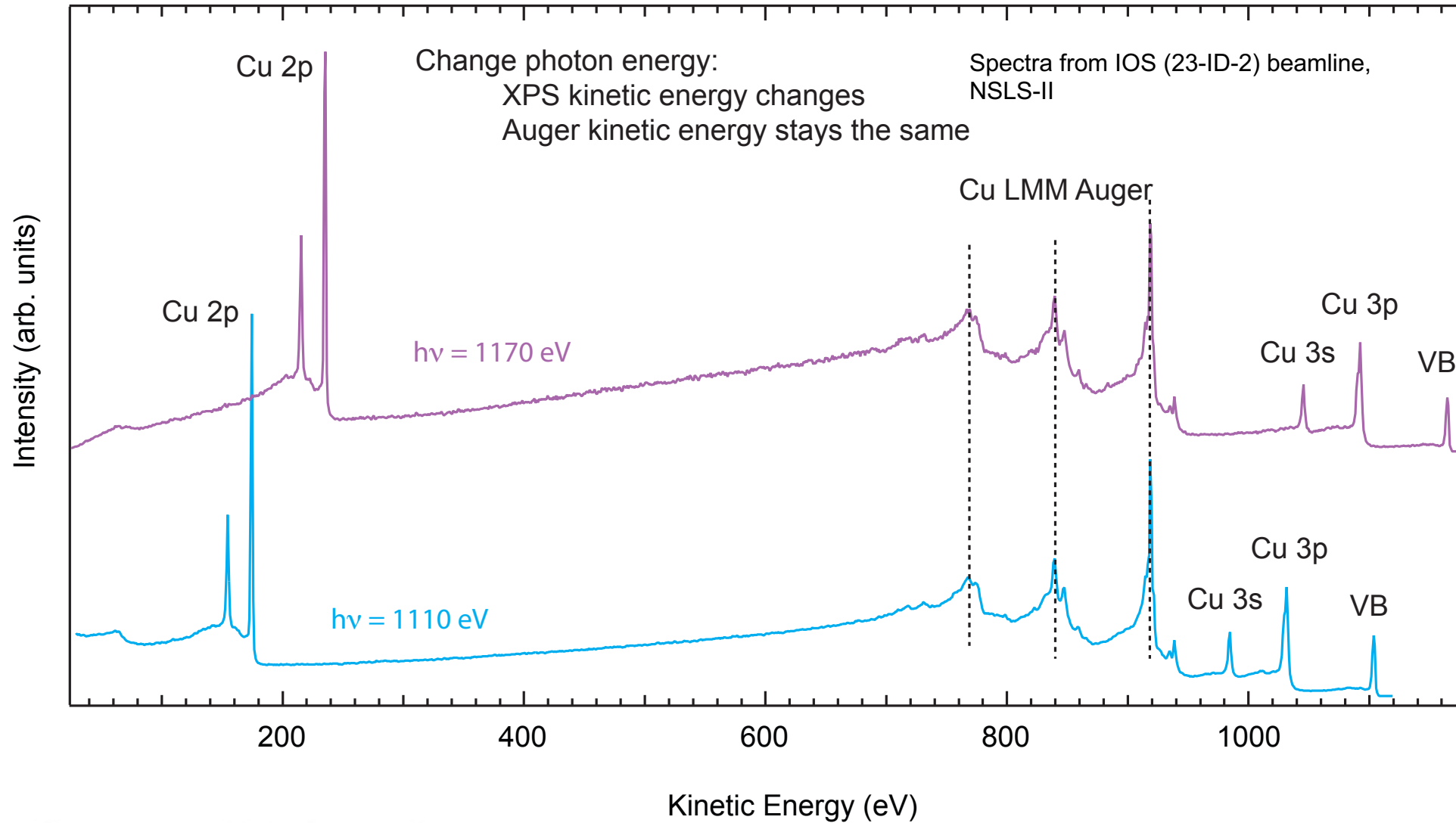
Auger Electrons



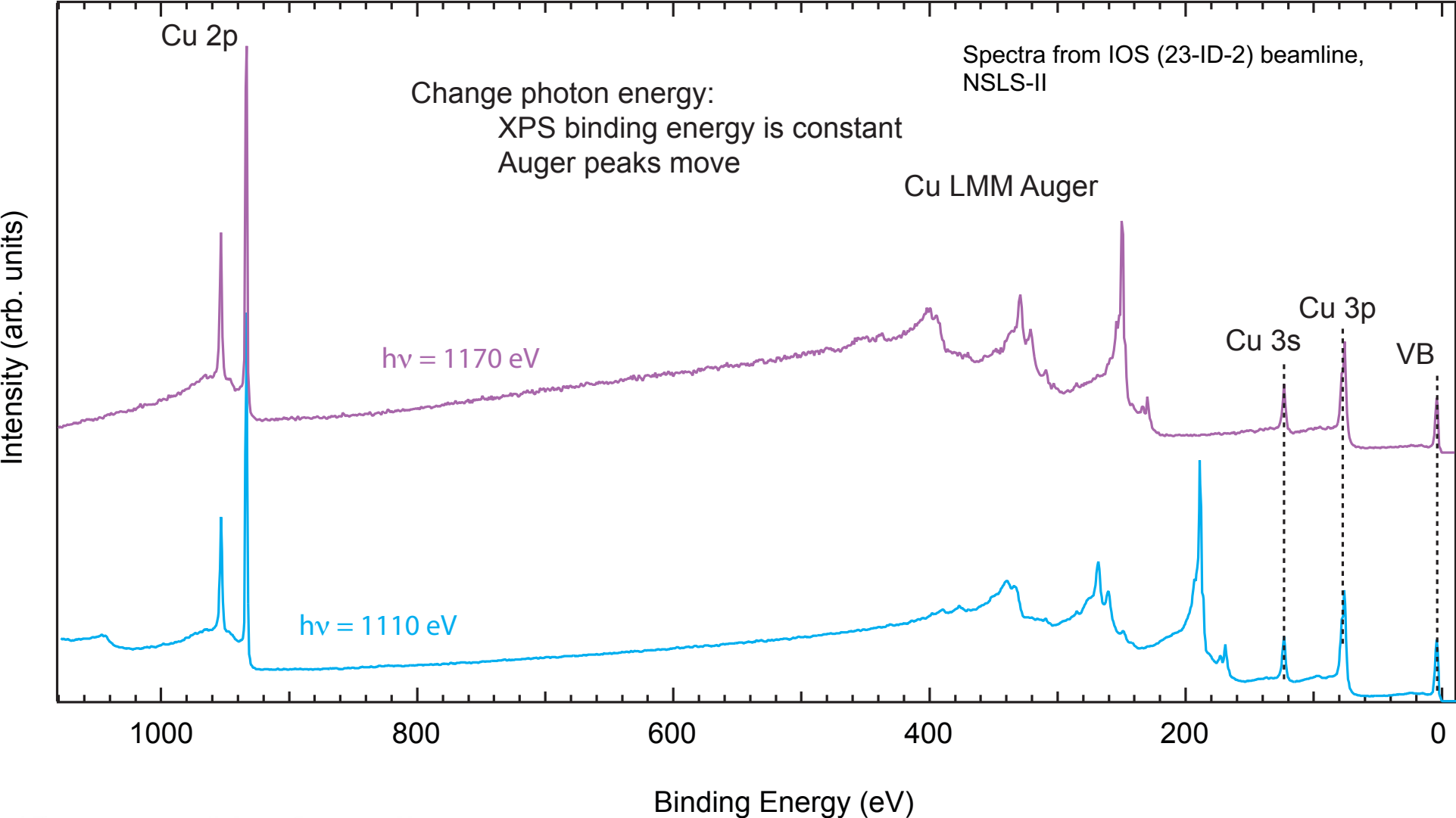
- XPS leaves a core hole
- An electron from a higher energy orbital fills the hole
- The released energy results in the emission of another electron
- Auger kinetic energy is not photon energy dependent



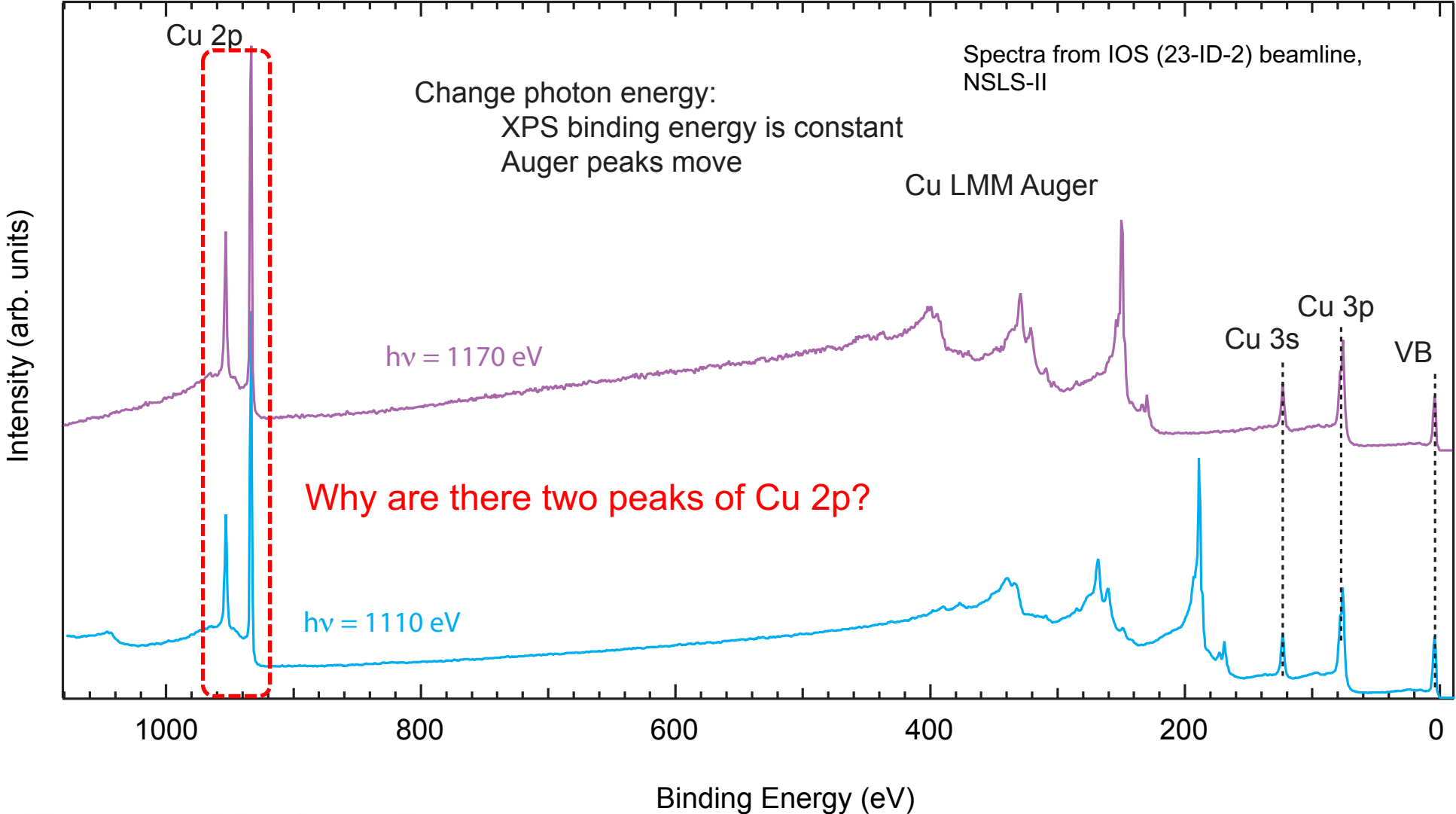
Identifying Auger Peaks



Identifying Auger Peaks

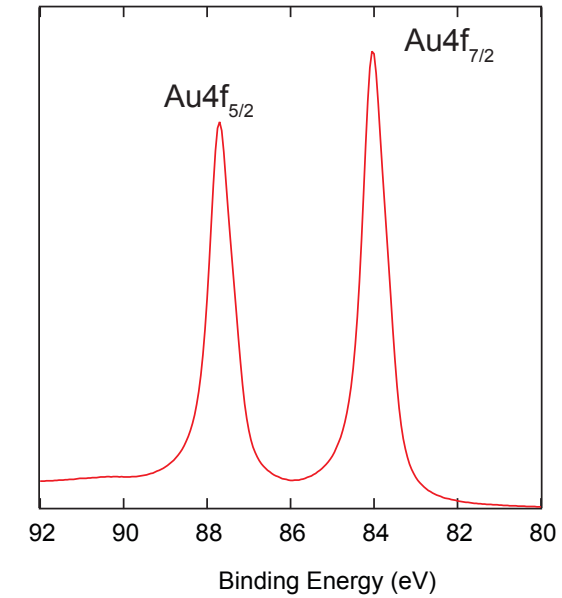
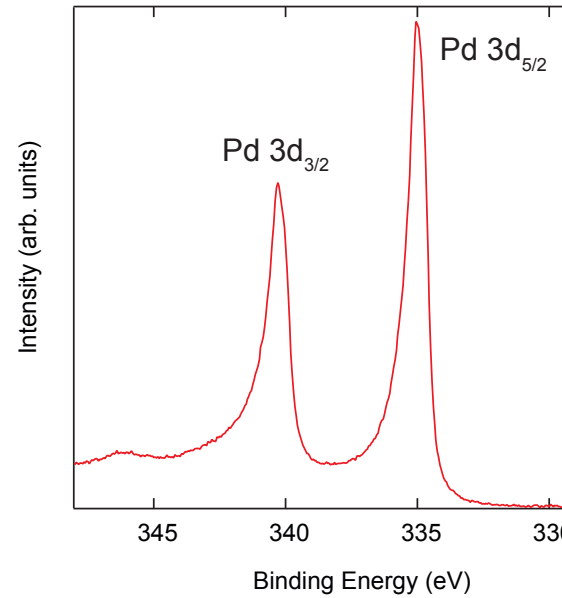
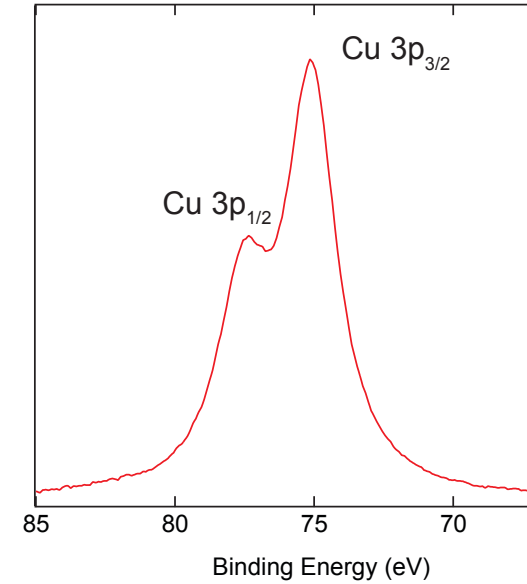
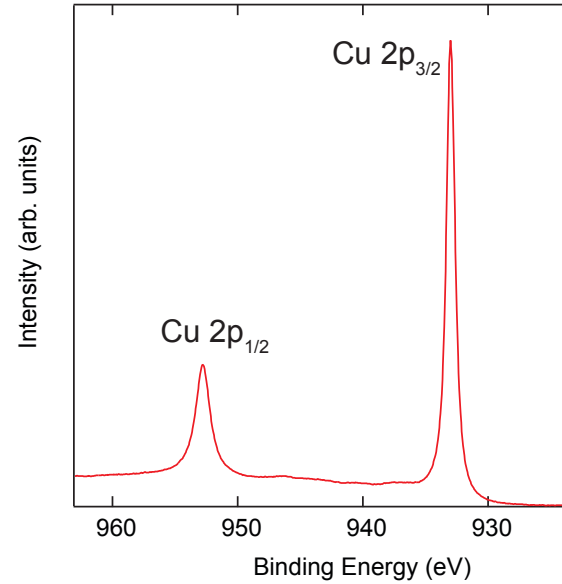


Spin-Orbit Splitting



Spin-Orbit Splitting

Doublets (two peaks) are always observed for p, d, f orbitals



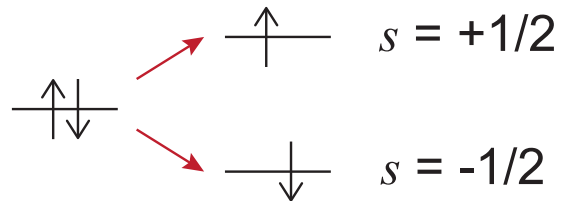
Spin-Orbit Splitting

l = orbital angular momentum quantum number
(0 = s, 1 = p, 2 = d, 3 = f)

$2p_{1/2}$ j = total angular momentum quantum number
 $j = |l + s|$

n = principal quantum number (1, 2, 3,...)

s = spin quantum number (-1/2 or +1/2)



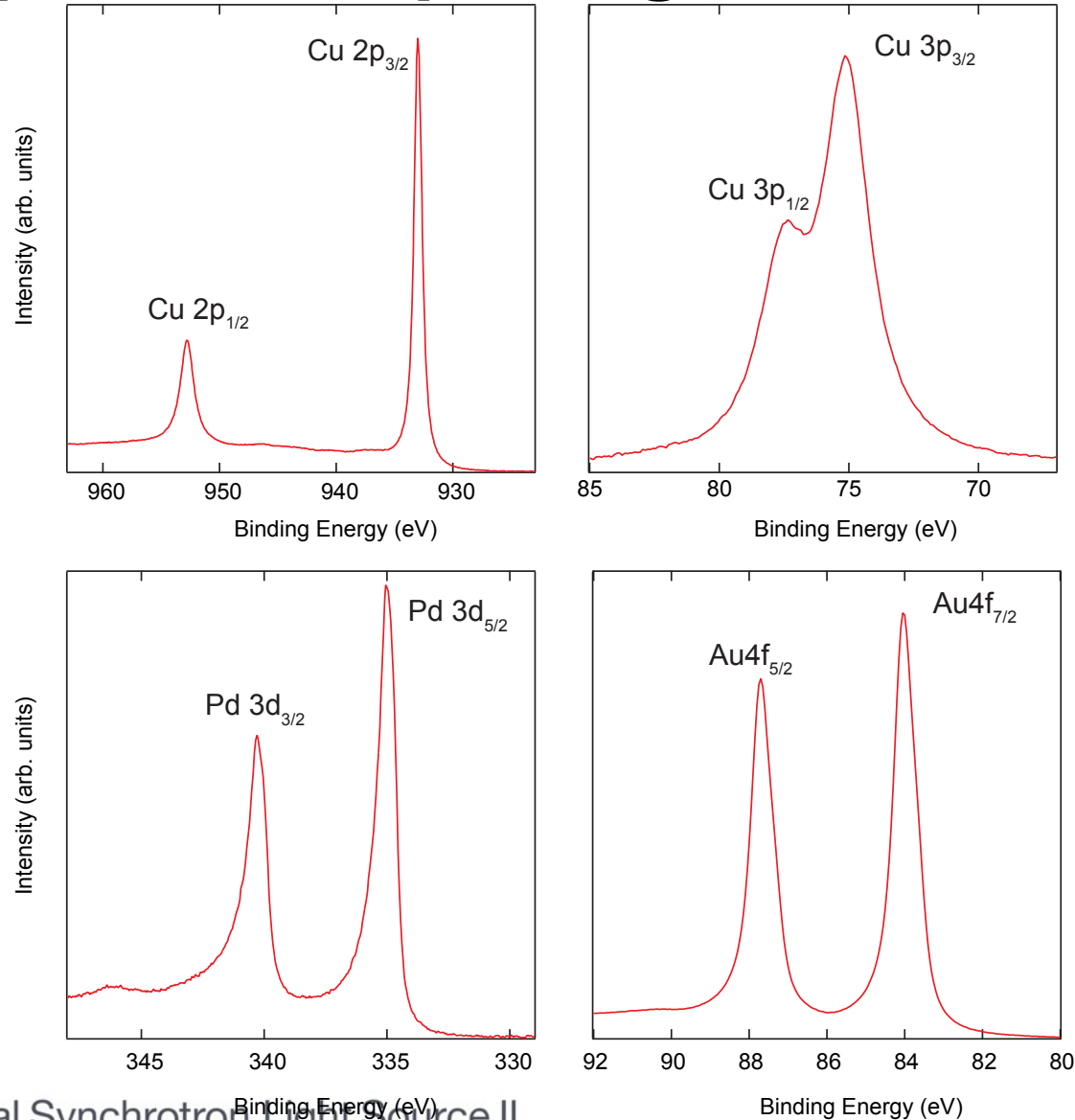
s : $l = 0$, no splitting

p : $l = 1$, $j = 1/2, 3/2$

d : $l = 2$, $j = 3/2, 5/2$

f : $l = 3$, $j = 5/2, 7/2$

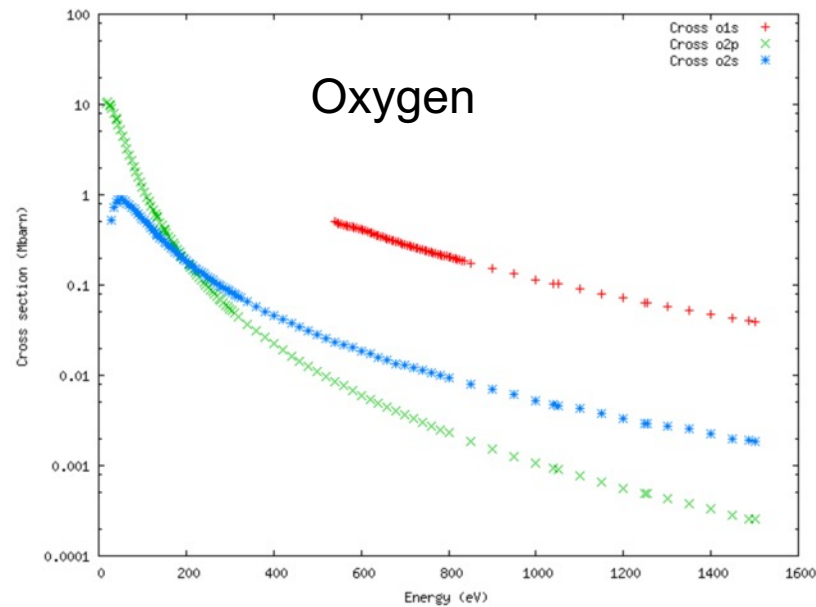
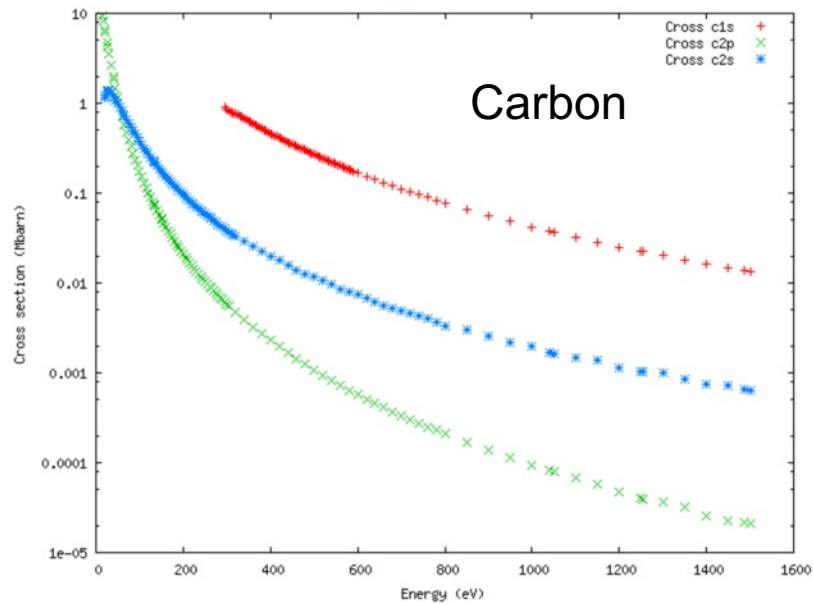
Spin-Orbit Splitting



- Spin orbit splitting helps us identify peaks
- Energy splitting is always the same for the same core level of the same element
- Peak area ratio is determined by degeneracy $2j+1$
 - $p_{3/2}:p_{1/2} = 2:1$
 - $d_{5/2}:d_{3/2} = 3:2$
 - $f_{7/2}:f_{5/2} = 4:3$

Photoionization Cross-section

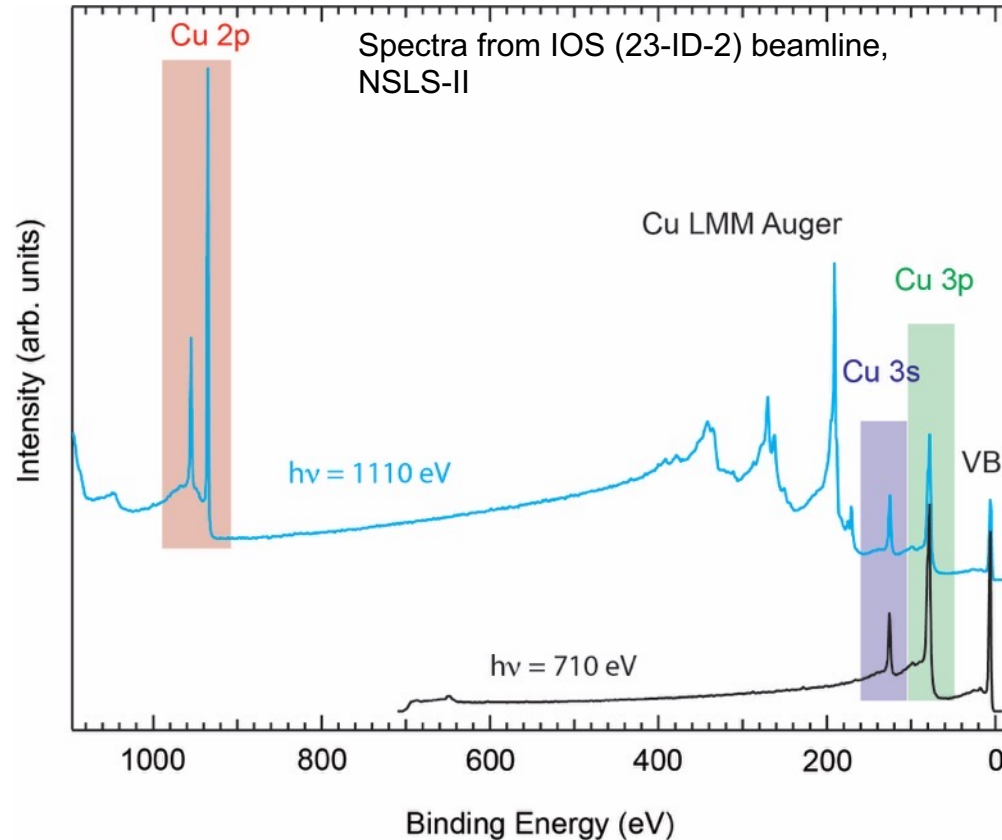
- The probability of a photon ionizing the atom and causing the emission of an electron
- It varies for different elements
- It varies for different core levels of the same element
- It varies with photon energy for the same core level of the same element
- Need a synchrotron to tune energy to optimize cross-section



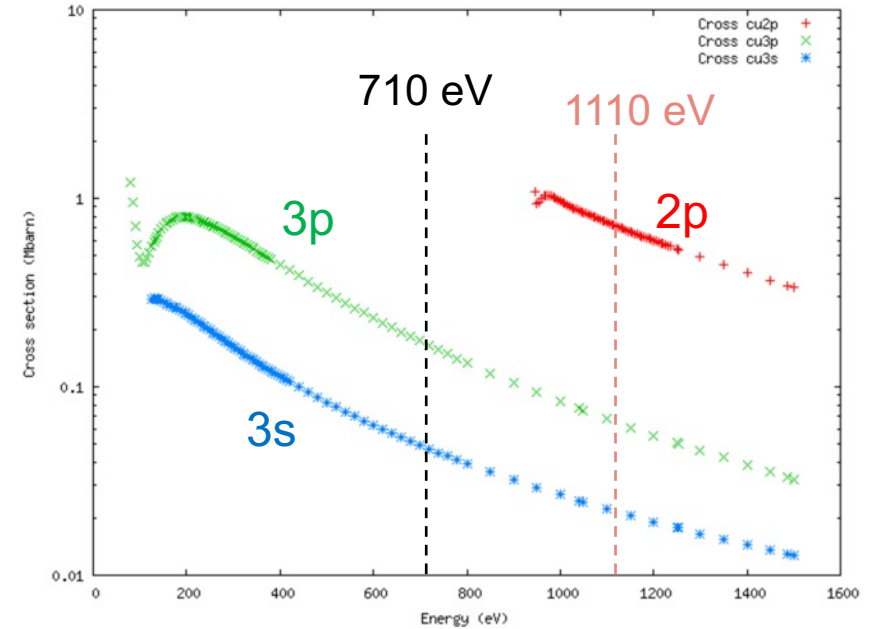
<https://vuo.elettra.eu/services/elements/WebElements.html>

Photoionization Cross-section

Copper survey XPS spectra



Photoionization Cross-section of copper



<https://vuo.elettra.eu/services/elements/WebElements.html>

What information can you get from XPS?

- **Elemental specificity**

What elements do you have in the sample?

- **Chemical sensitivity**

What is the chemical environment of each element in the sample?

- **Depth profiling**

Where are the elements in the sample?

- **Quantitative analysis**

How much is there of each element in the sample?

What information can you get from XPS?

- **Elemental specificity**

What elements do you have in the sample?

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What is the chemical environment of each element in the sample?

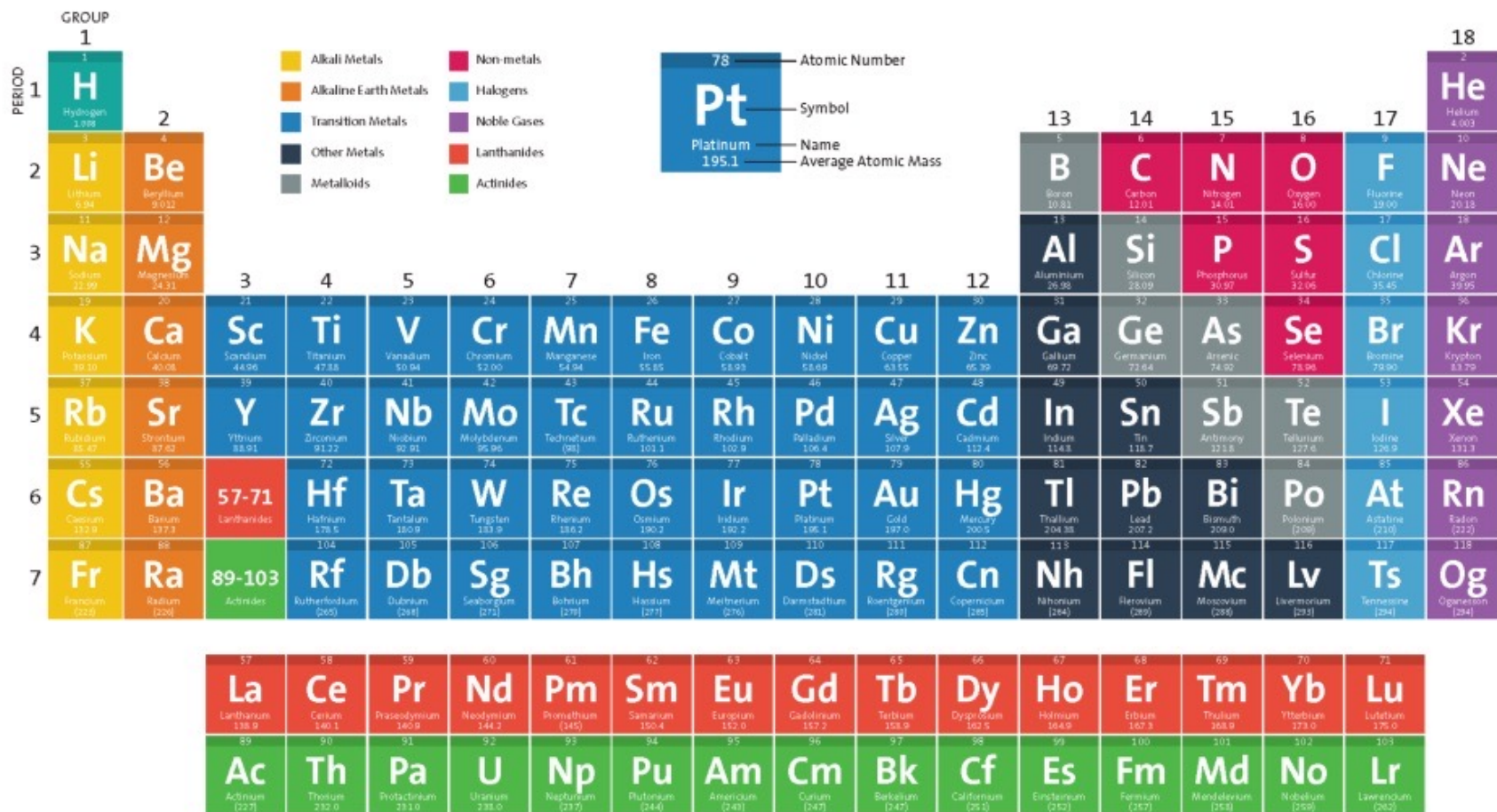
- **Depth profiling**

Where are the elements in the sample?

- **Quantitative analysis**

How much is there of each element in the sample?

Elemental Specificity



American Chemical Society

www.acs.org/outreach

Each element has a unique set of electron binding energies

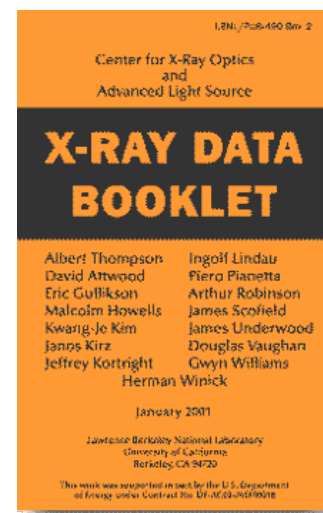
Electron Binding Energy Table

Table 1-1. Electron binding energies, in electron volts, for the elements in their natural forms.

Element	K 1s	L ₁ 2s	L ₂ 2p _{1/2}	L ₃ 2p _{3/2}	M ₁ 3s	M ₂ 3p _{1/2}	M ₃ 3p _{3/2}	M ₄ 3d _{3/2}	M ₅ 3d _{5/2}	N ₁ 4s	N ₂ 4p _{1/2}	N ₃ 4p _{3/2}
1 H	13.6											
2 He	24.6*											
3 Li	54.7*											
4 Be	111.5*											
5 B	188*											
6 C	284.2*											
7 N	409.9*	37.3*										
8 O	543.1*	41.6*										
9 F	696.7*											
10 Ne	870.2*	48.5*	21.7*	21.6*								
11 Na	1070.8†	63.5†	30.65	30.81								
12 Mg	1303.0†	88.7	49.78	49.50								
13 Al	1559.6	117.8	72.95	72.55								
14 Si	1839	149.7*b	99.82	99.42								
15 P	2145.5	189*	136*	135*								
16 S	2472	230.9	163.6*	162.5*								
17 Cl	2822.4	270*	202*	200*								
18 Ar	3205.9*	326.3*	250.6†	248.4*	29.3*	15.9*	15.7*					
19 K	3608.4*	378.6*	297.3*	294.6*	34.8*	18.3*	18.3*					
20 Ca	4038.5*	438.4†	349.7†	346.2†	44.3 †	25.4†	25.4†					
21 Sc	4492	498.0*	403.6*	398.7*	51.1*	28.3*	28.3*					
22 Ti	4966	560.9†	460.2†	453.8†	58.7†	32.6†	32.6†					

https://xdb.lbl.gov/Section1/Table_1-1.pdf

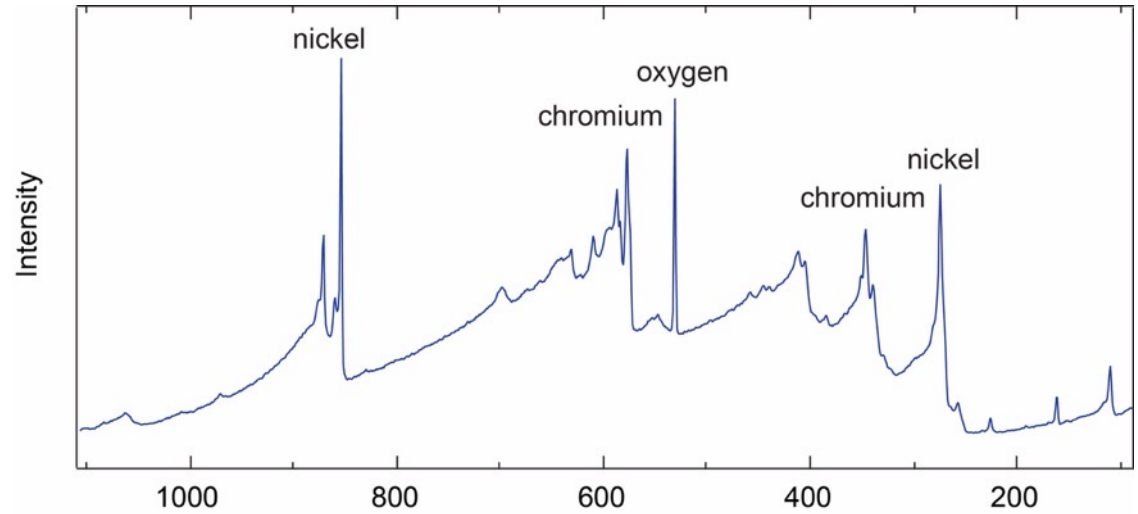
From X-ray Data Booklet: <https://xdb.lbl.gov>



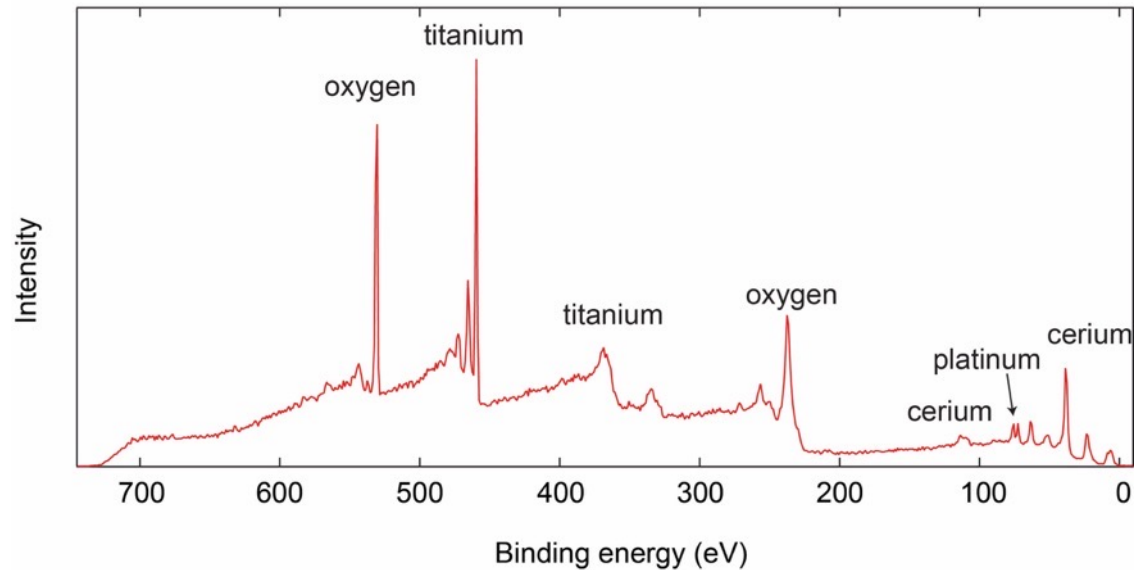
Elemental Specificity

Nickel-Chromium alloy –
corrosion resistant material

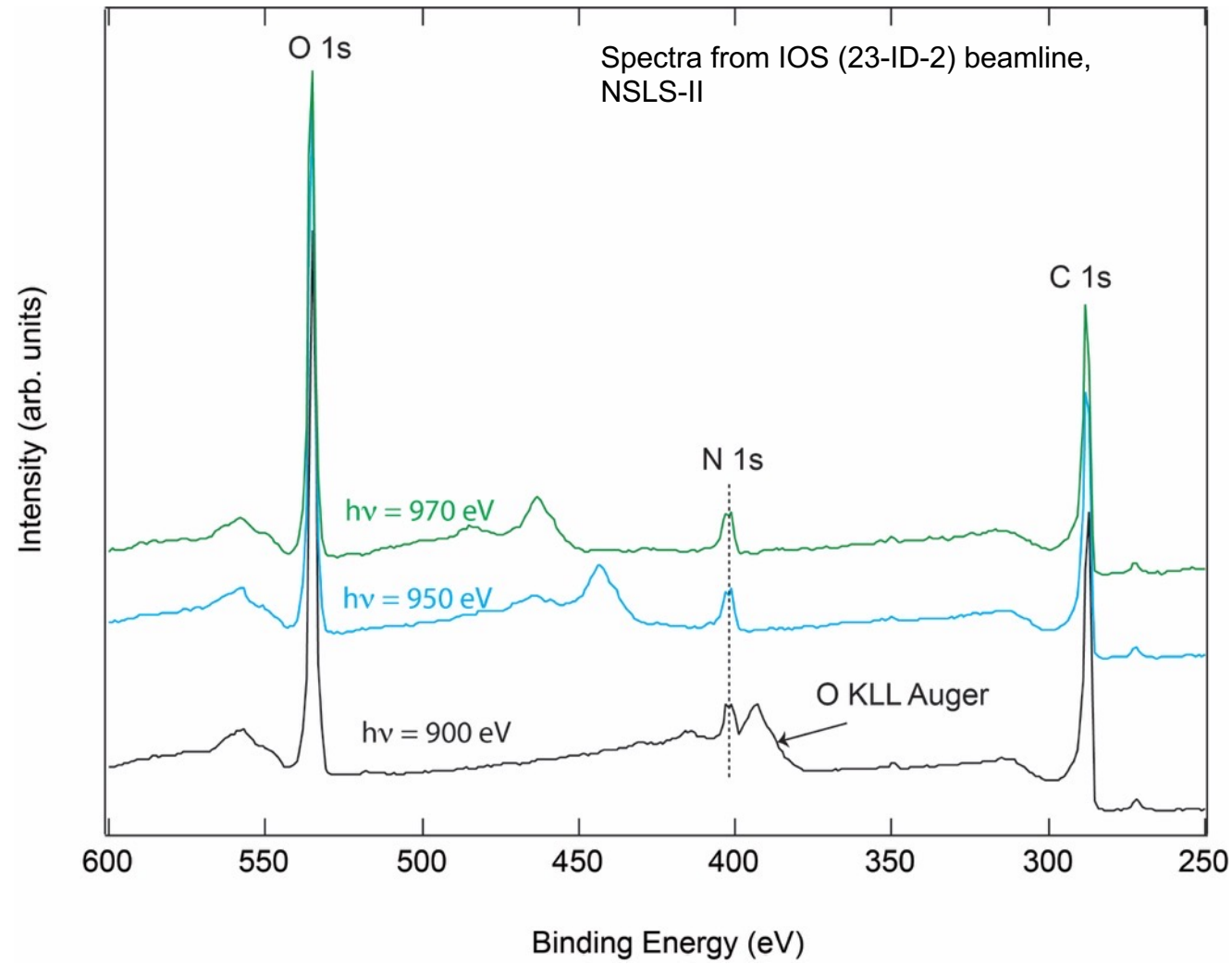
Spectra from IOS (23-ID-2) beamline, NSLS-II



Pt/CeO₂/TiO₂
catalyst for methanol production



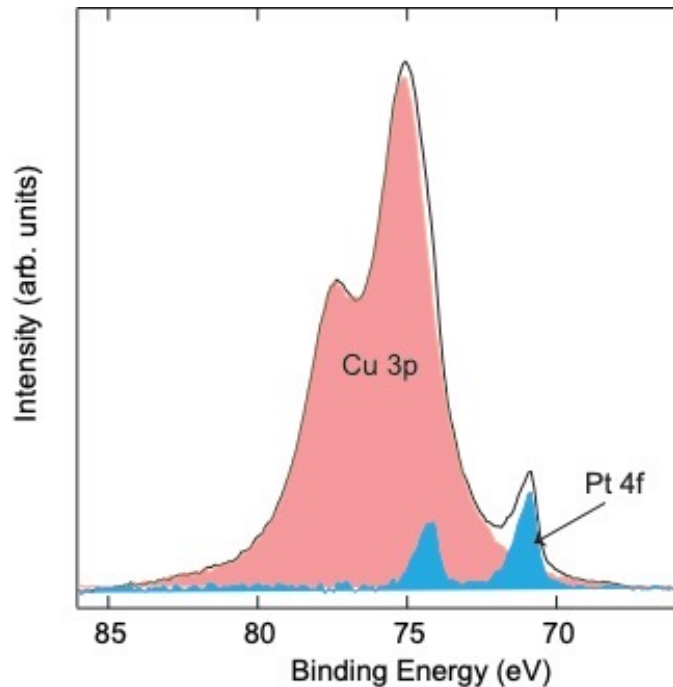
Overlaps with Auger Peaks



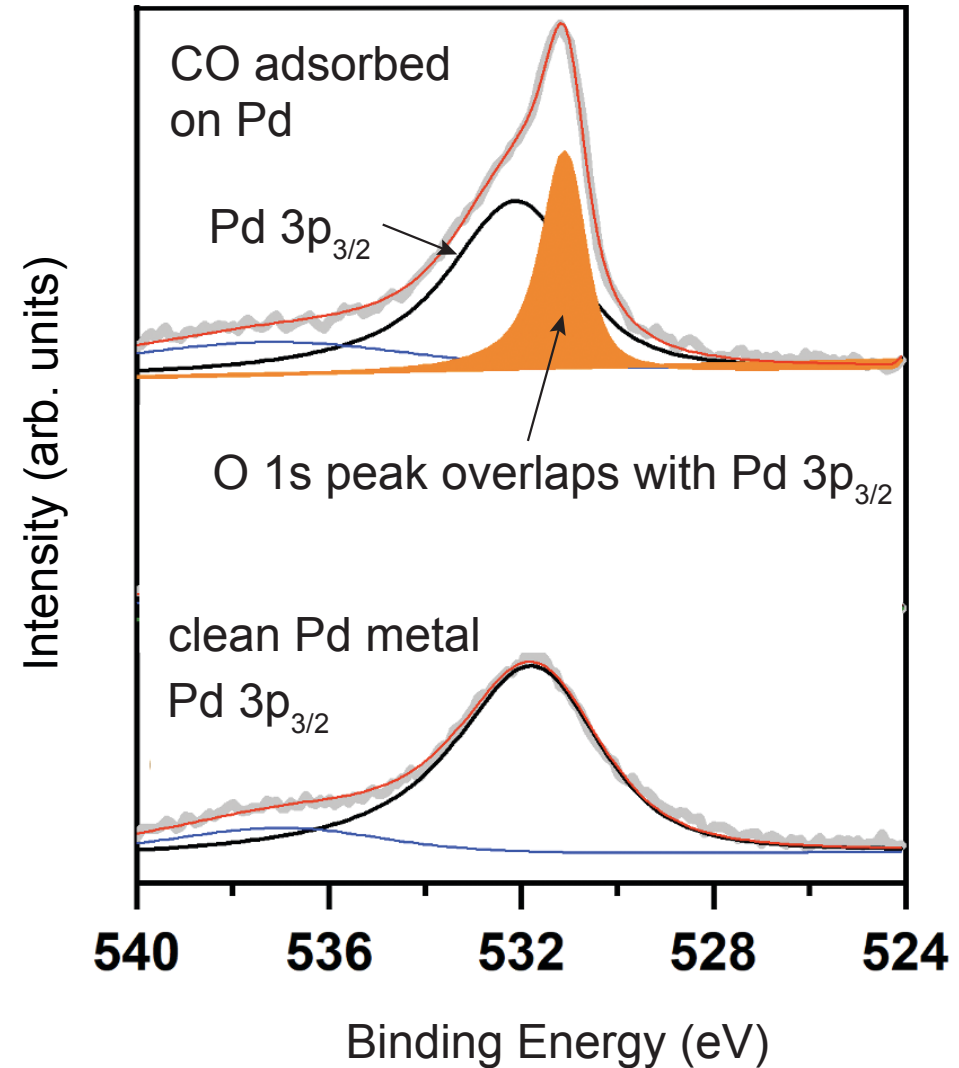
Overlapping Auger peaks can be shifted away by changing photon energy

Things are not always that simple...

- Some XPS peaks of different elements may still overlap partially or completely
- You need to look at other peaks to identify the element
- Peak fitting is important for separating peaks from different elements



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Spectra from IOS (23-ID-2) beamline,
NSLS-II

What information can you get from XPS?

- **Elemental specificity**

What elements do you have in the sample?

- **Chemical sensitivity**

What is the chemical environment of each element in the sample?

- **Depth profiling**

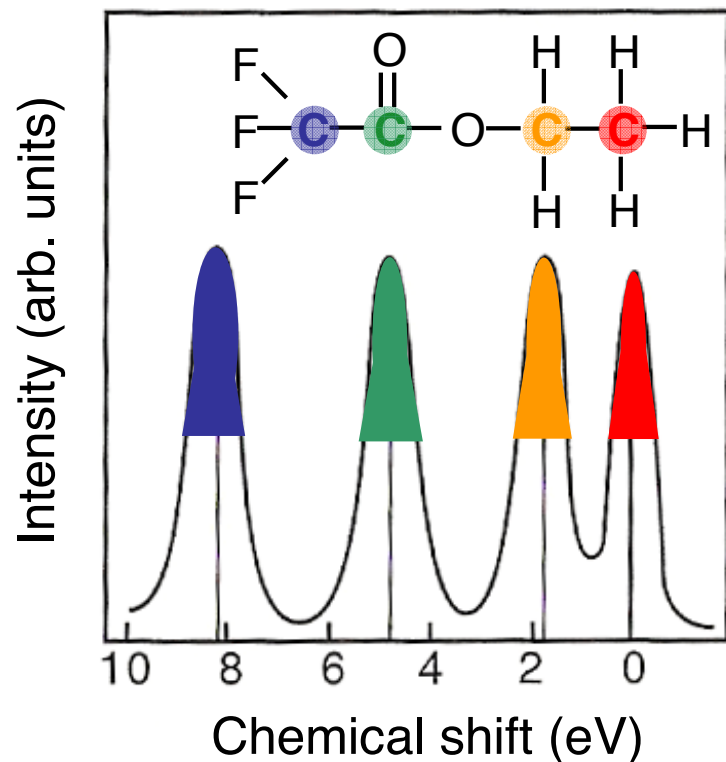
Where are the elements in the sample?

- **Quantitative analysis**

How much is there of each element in the sample?

Sensitivity to Chemical Environment

C 1s XPS Ethyl trifluoroacetate

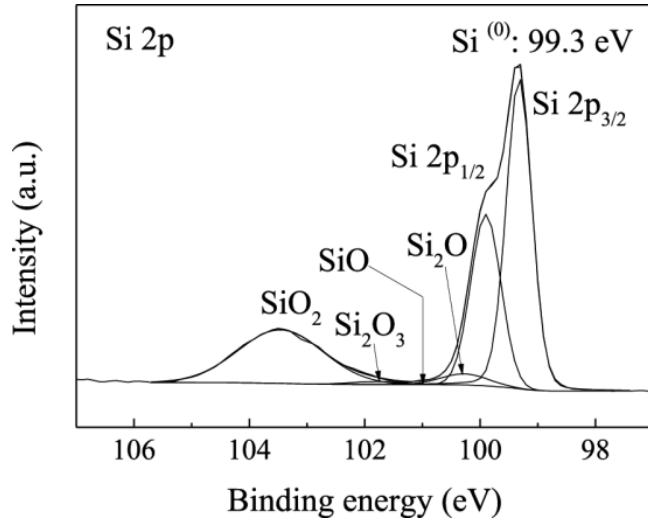


- Binding energy of an electron is affected by the chemical environment of the atom
- Energy shift can be up to 10 eV
- This makes XPS a powerful tool for chemical analysis
- You can tell the chemical bonding of the probed atom
- Bonding to a more electronegative atom → shift to higher binding energy

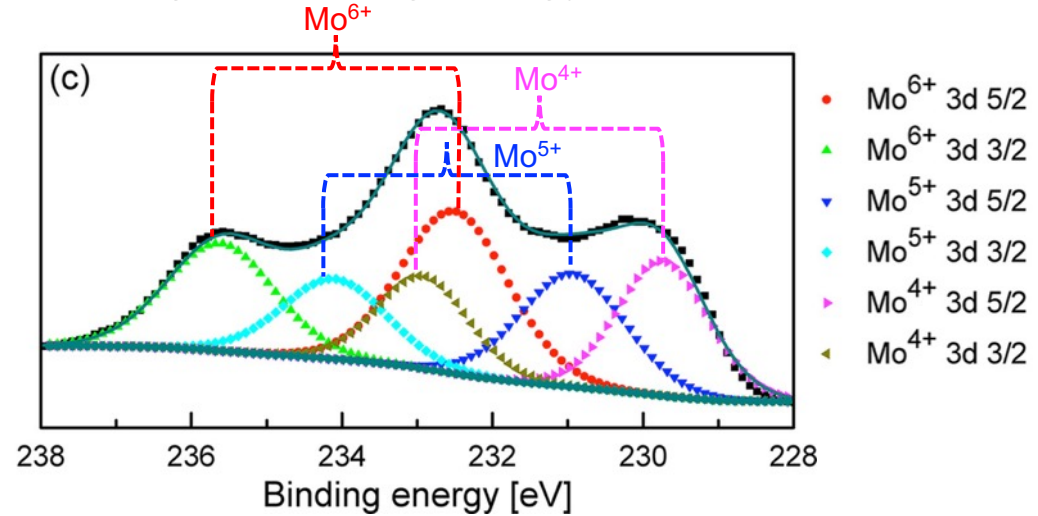
K. Siegbahn, J. Electr. Spectrosc. Relat. Phenom., 5, 3 (1974)

Core Level Shift due to Oxidation State

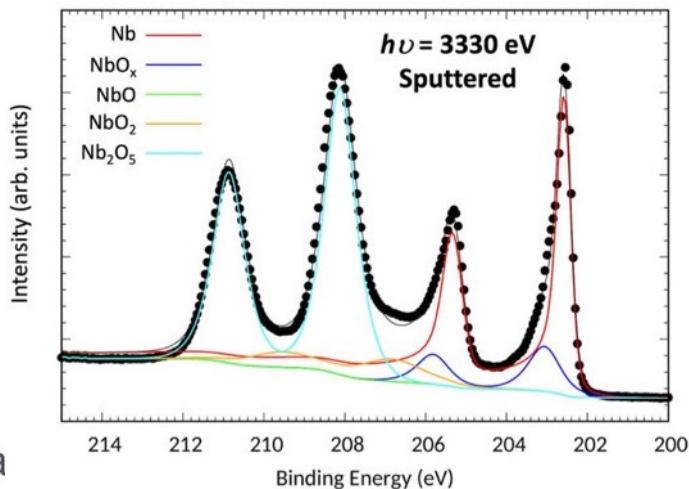
- In general, higher oxidation state causes a shift to higher binding energy



Zhang et al. IEEE Trans. Instrum. Meas., 66 1297 (2017)

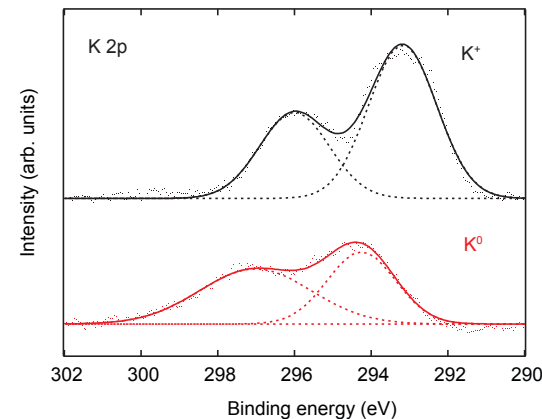


M. Ponce-Mosso et al. Catal. Today, 349, 150 (2020)



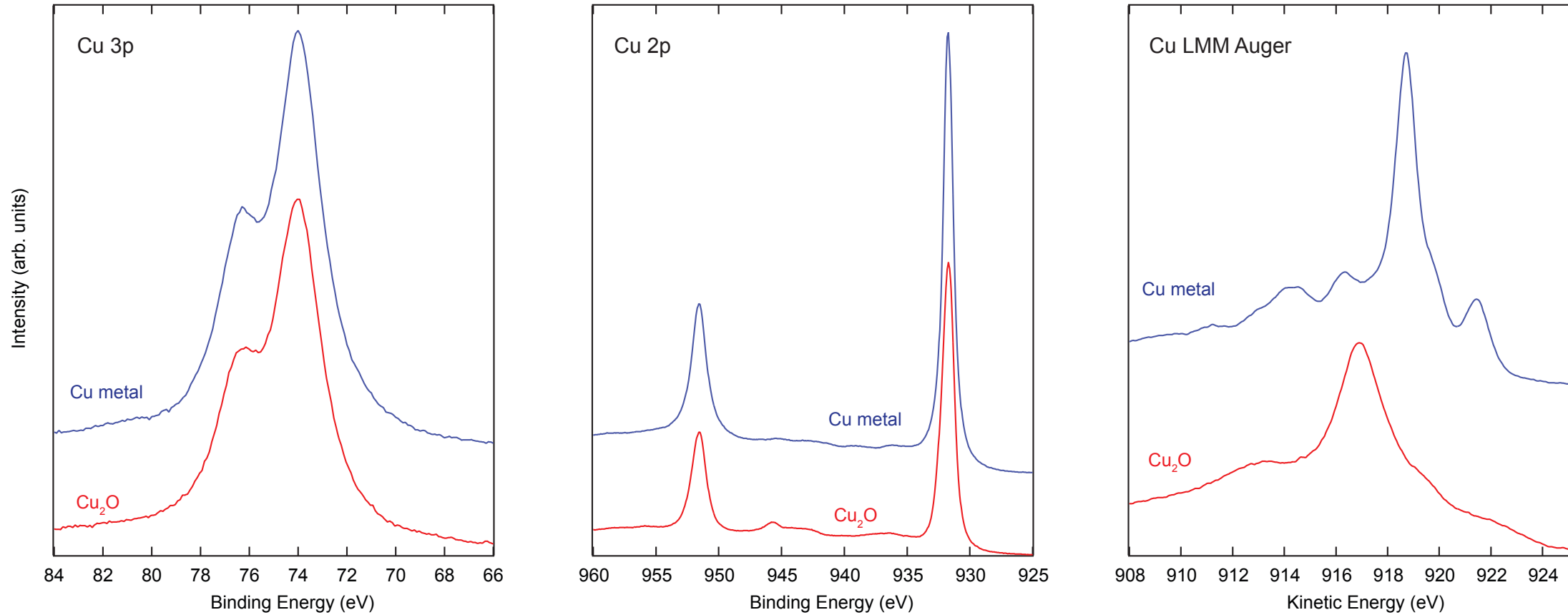
Premkumar et al. Comm. Mater., 2, 72 (2021)

But... alkali metals behave the opposite way



spectra from IOS beamline, NSLS-II

Sometimes it's not that clear...

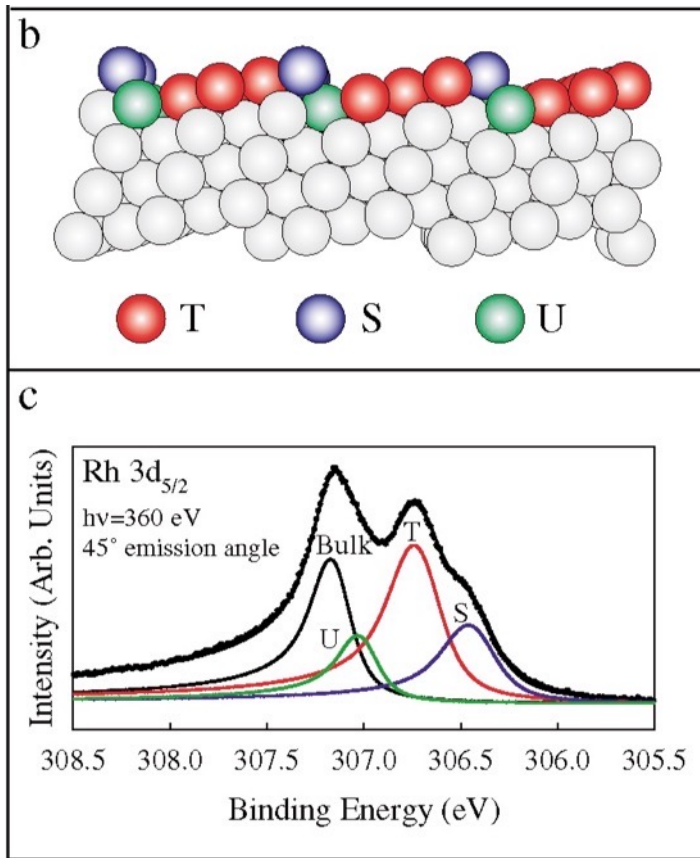


Spectra from IOS (23-ID-2) beamline, NSLS-II

National Synchrotron Light Source II

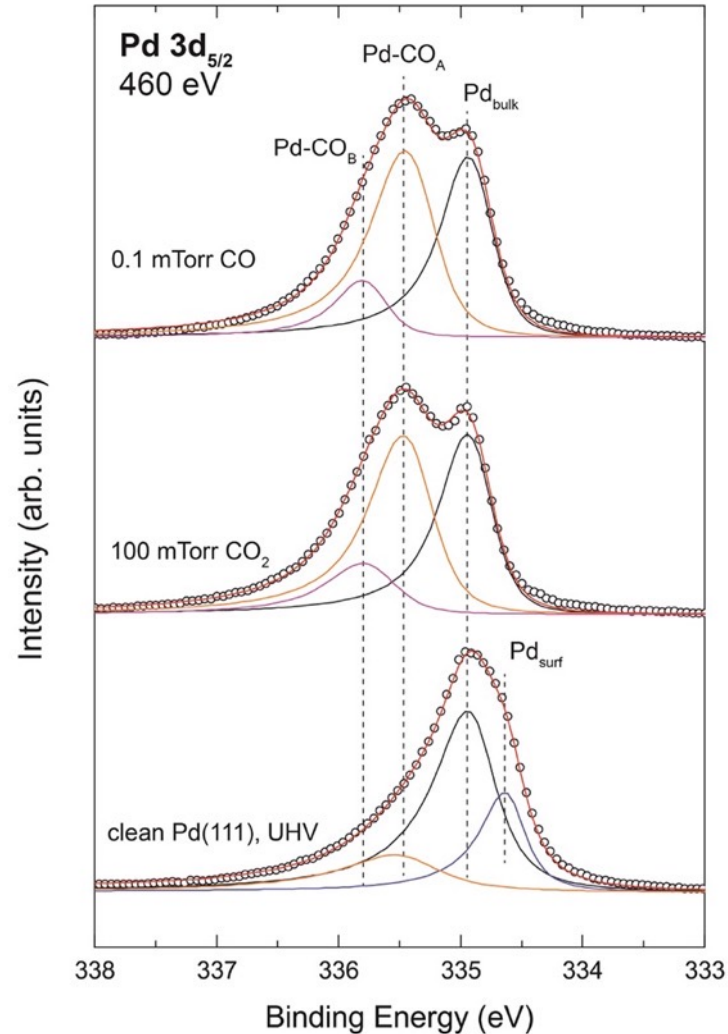
Surface Core Level Shift

Surface atoms of a metal can have distinct binding energy from the bulk atoms

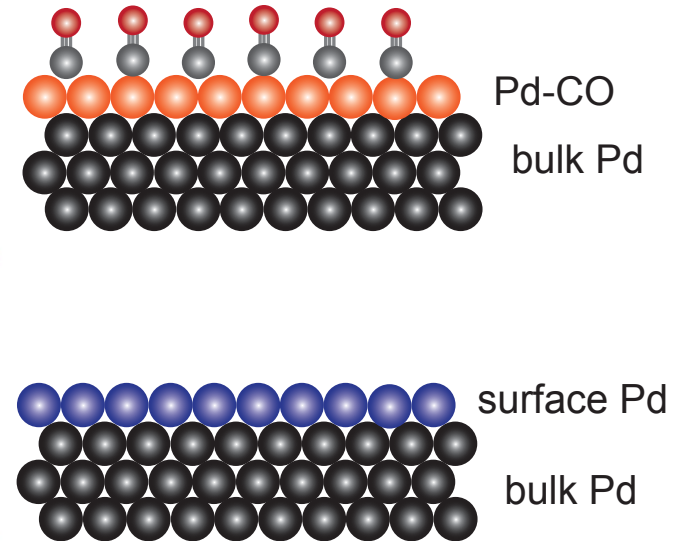


Gustafson et al. Phys. Rev. Let. 91, 056102 (2003)

National Synchrotron Light Source II



Surface peak is shifted by adsorbed molecules

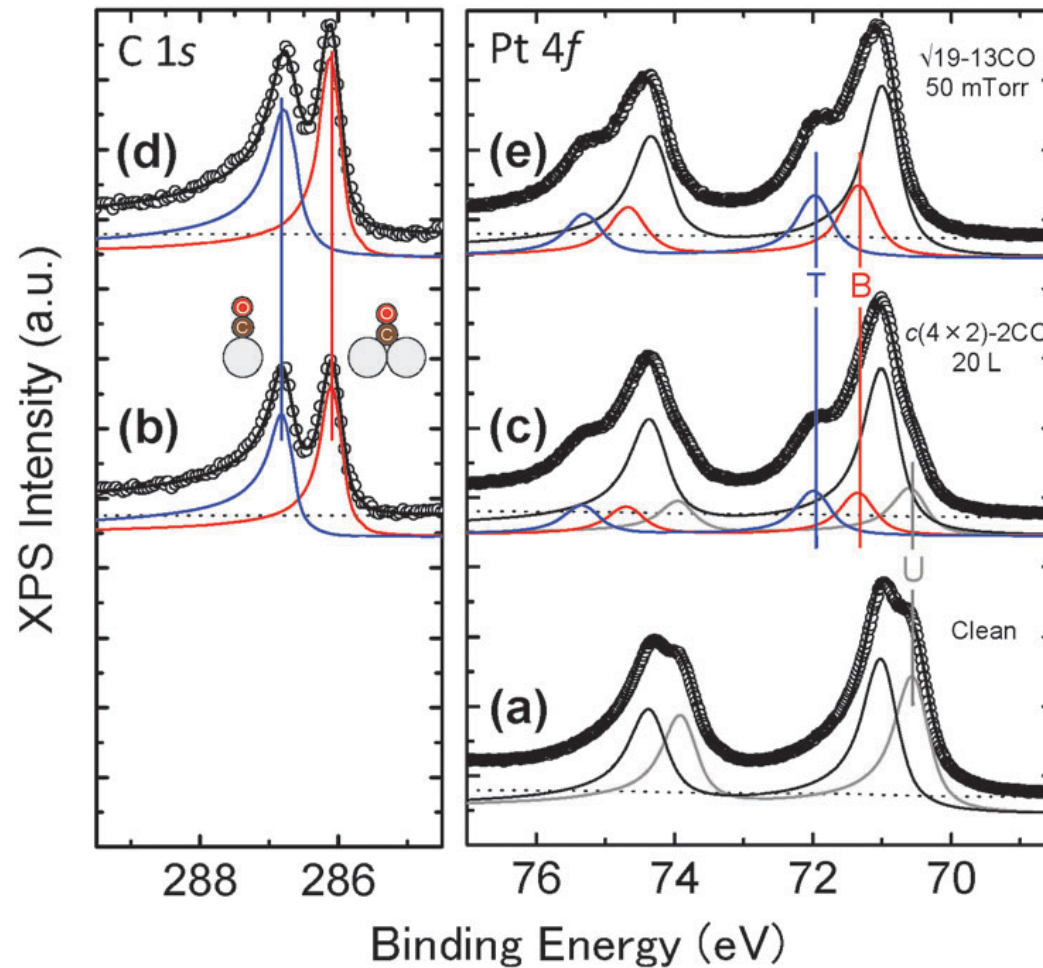
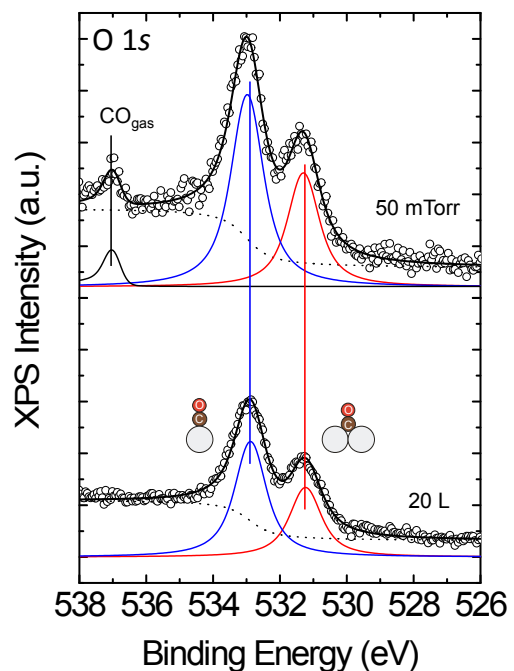
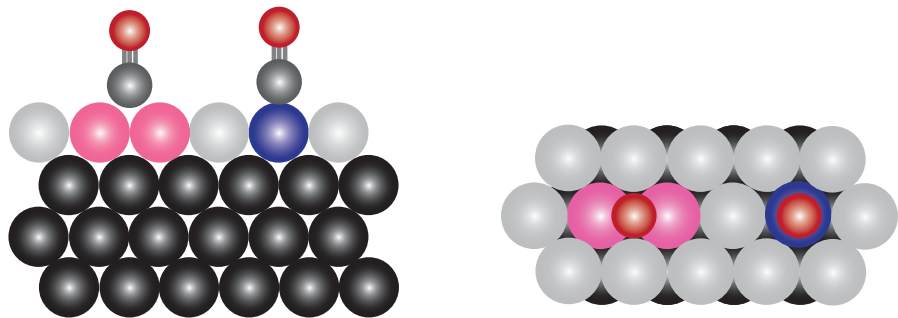


Simonovis et al. J. Phys. Chem. C 126, 7870 (2022)

Distinguishing Different Adsorption Sites

“bridge CO”

“top” CO



What information can you get from XPS?

- **Elemental specificity**

What elements do you have in the sample?

- **Chemical sensitivity**

What is the chemical environment of each element in the sample?

- **Depth profiling**

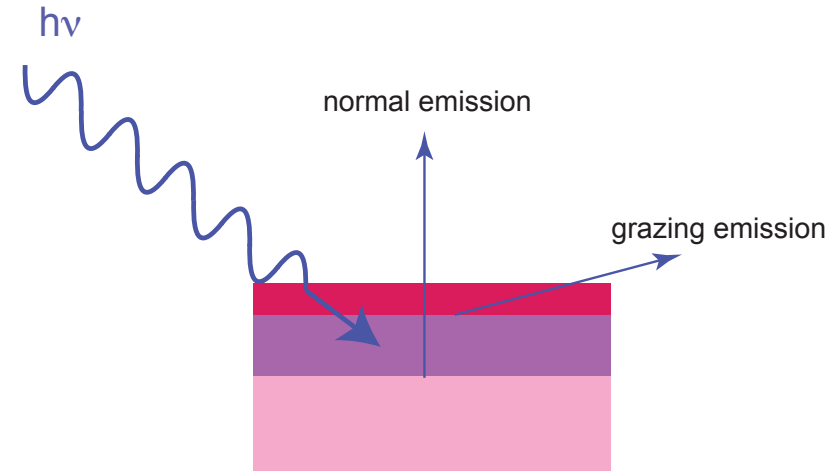
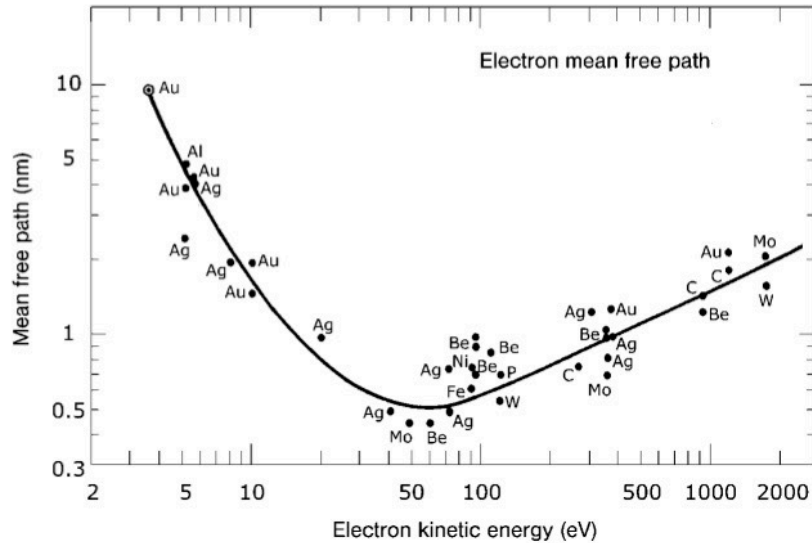
Where are the elements in the sample?

- **Quantitative analysis**

How much is there of each element in the sample?

Depth Profiling

You can tune the sampling depth of XPS (non-destructively) in two ways:



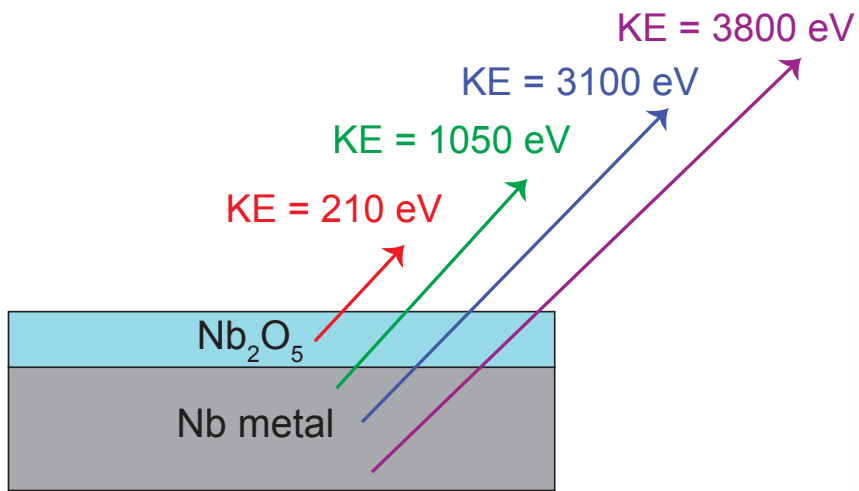
1. Change the photon energy \rightarrow lower E_k means lower IMFP and more surface sensitive

2. Change emission angle \rightarrow more grazing emission is more surface sensitive

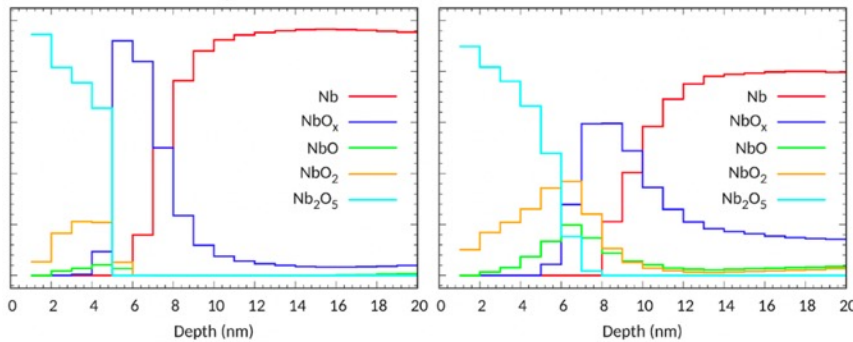
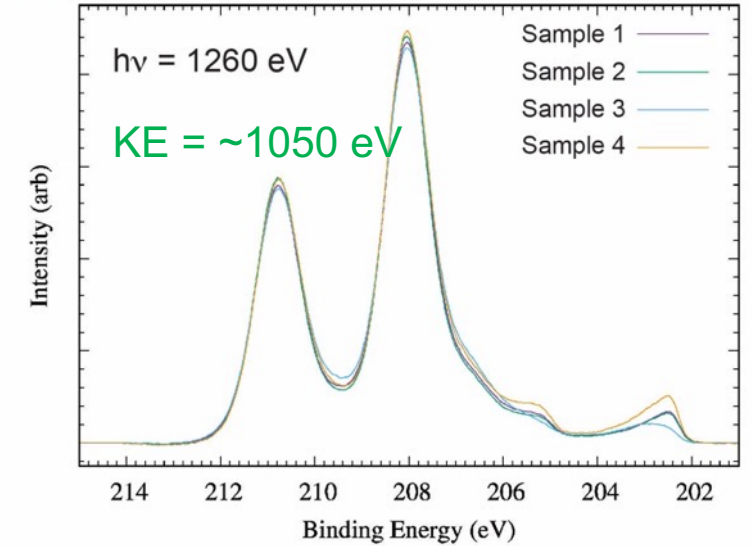
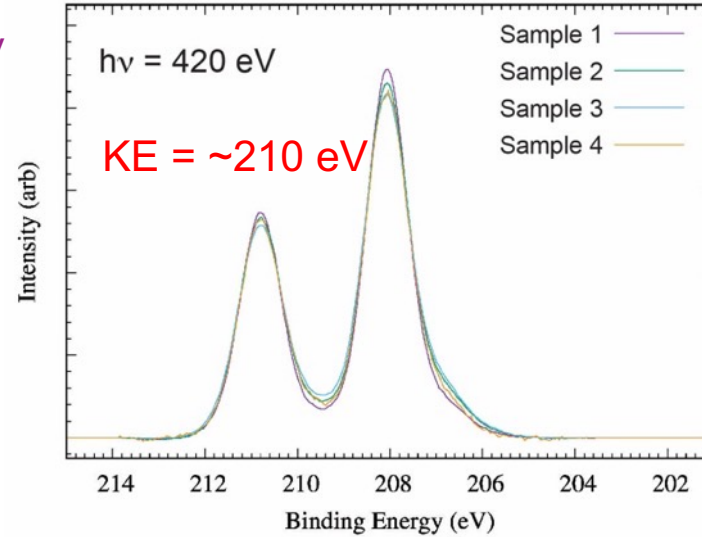
You can also depth-profile by sputtering (i.e. remove materials layer by layer) but that is destructive



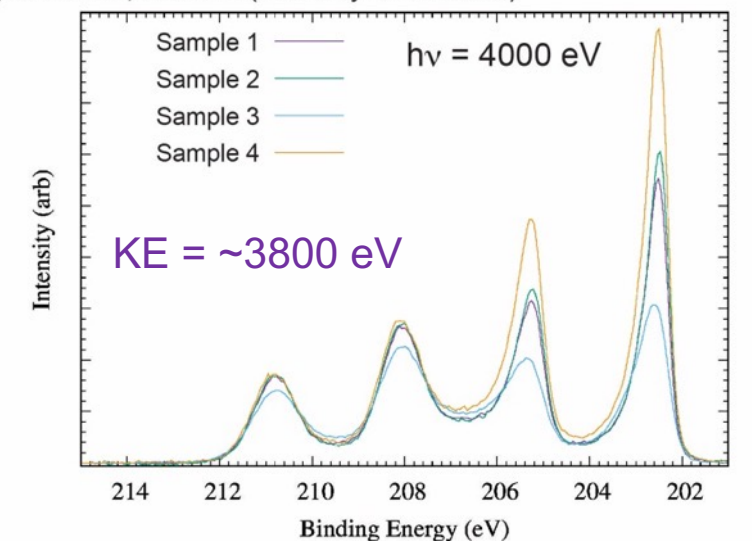
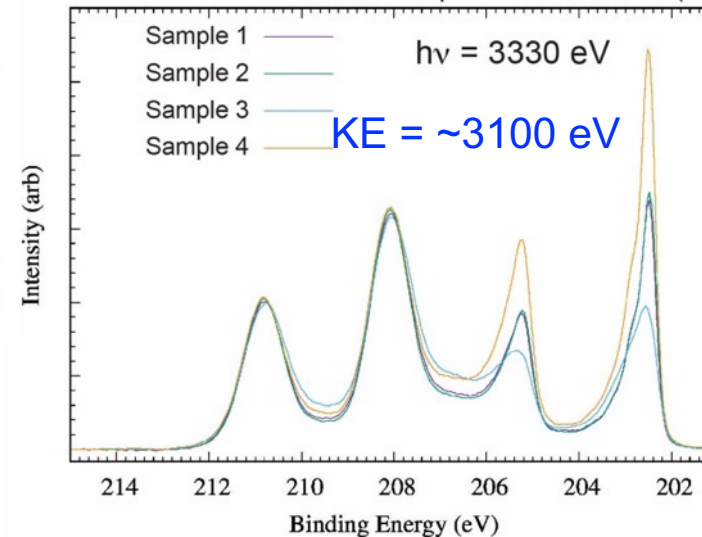
Depth Profiling Example



soft XPS spectra from IOS (23-ID-2) beamline, NSLS-II



HAXPES spectra from SST-2 (7-ID-2) beamline, NSLS-II (courtesy C. Weiland)



Premkumar et al. Commun. Mater. 2, 72 (2021)

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What information can you get from XPS?

- **Elemental specificity**

What elements do you have in the sample?

- **Chemical sensitivity**

What is the chemical environment of each element in the sample?

- **Depth profiling**

Where are the elements in the sample?

- **Quantitative analysis**

How much is there of each element in the sample?

Quantitative Analysis

$$I_x = JN_x\lambda\sigma K$$

I_x = peak intensity of element x

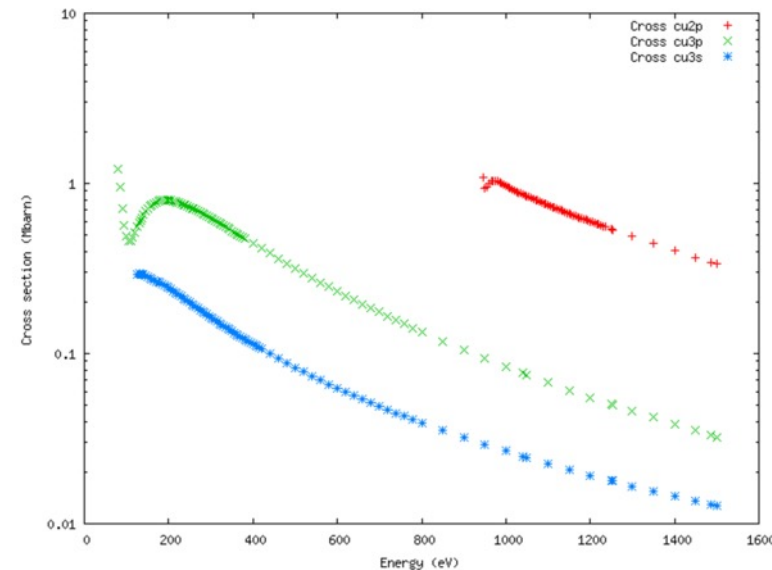
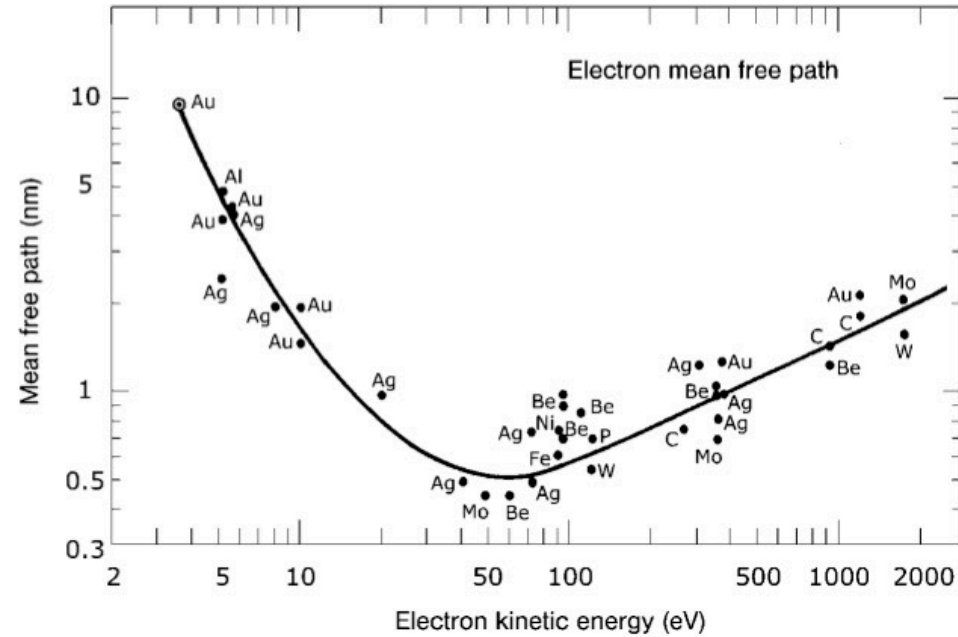
J = photon flux

N_x = concentration of element x in the sample

λ = inelastic mean free path

σ = photoionization cross-section

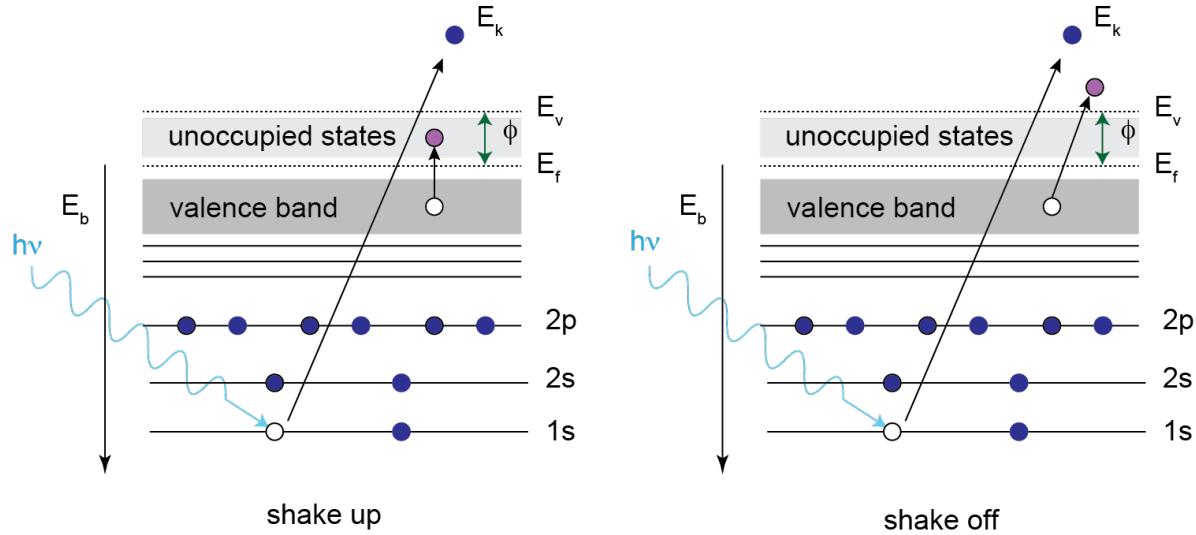
K = instrumentation factors



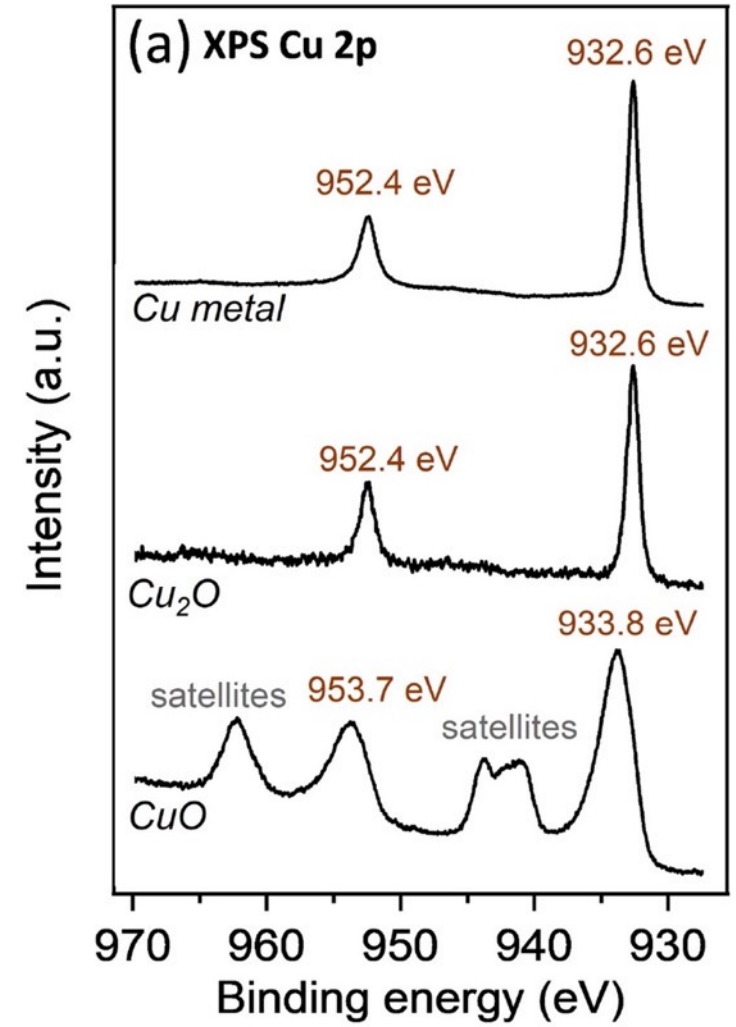
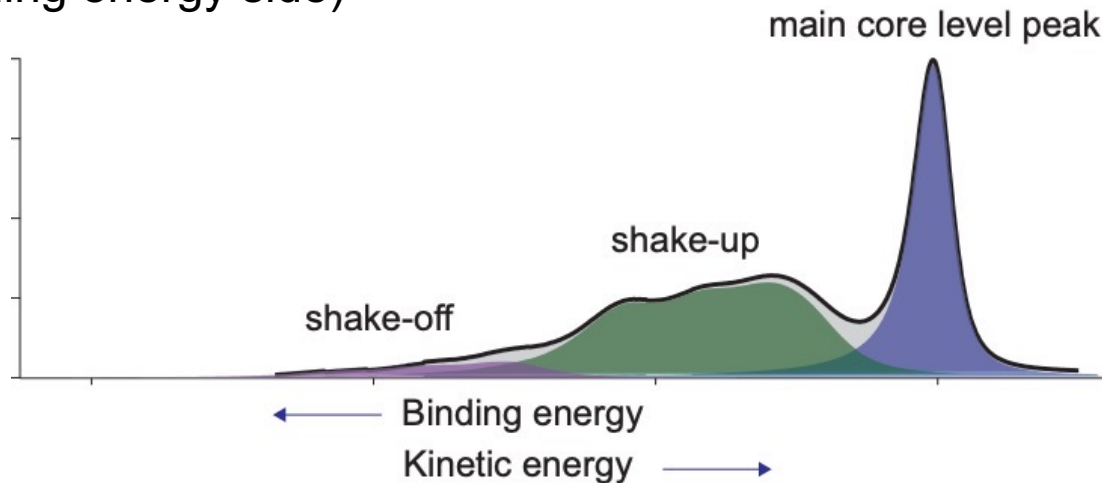
Other things to consider...

- Shake up/shake off
- Multiplet splitting
- Plasmon loss
- Charging

Shake up and Shake off

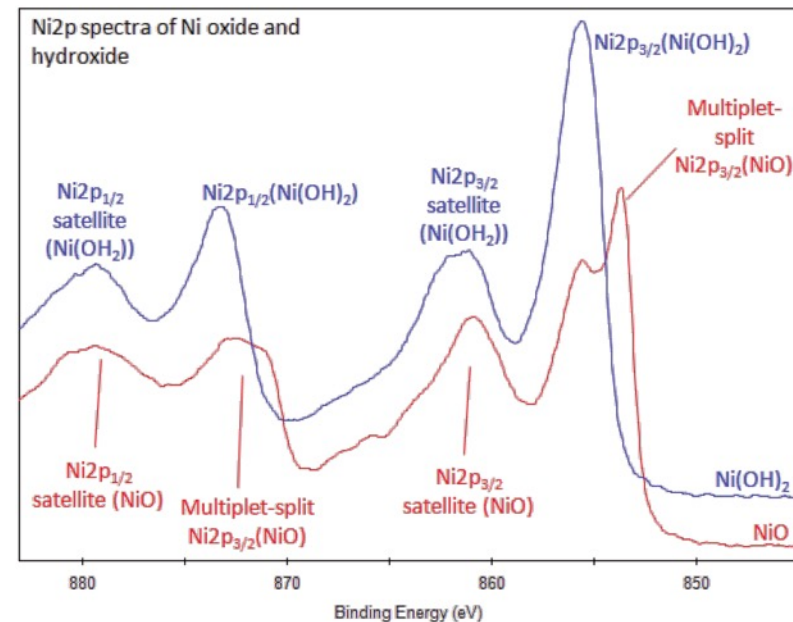
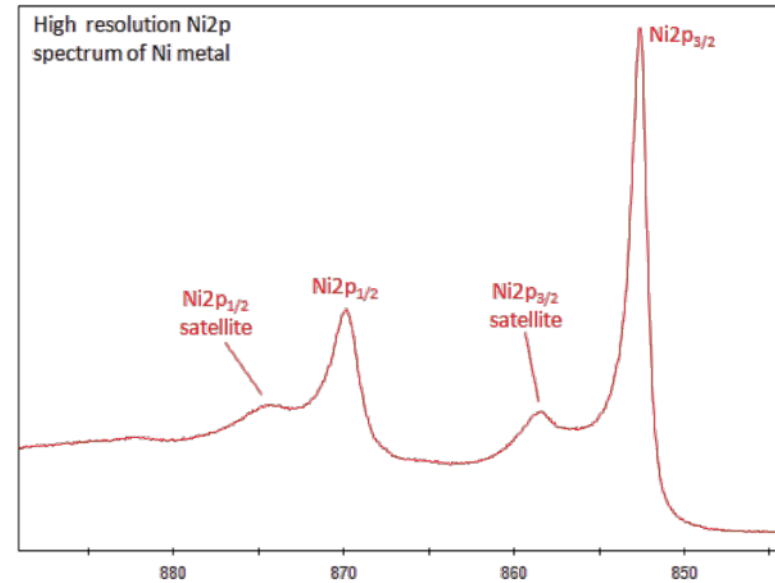
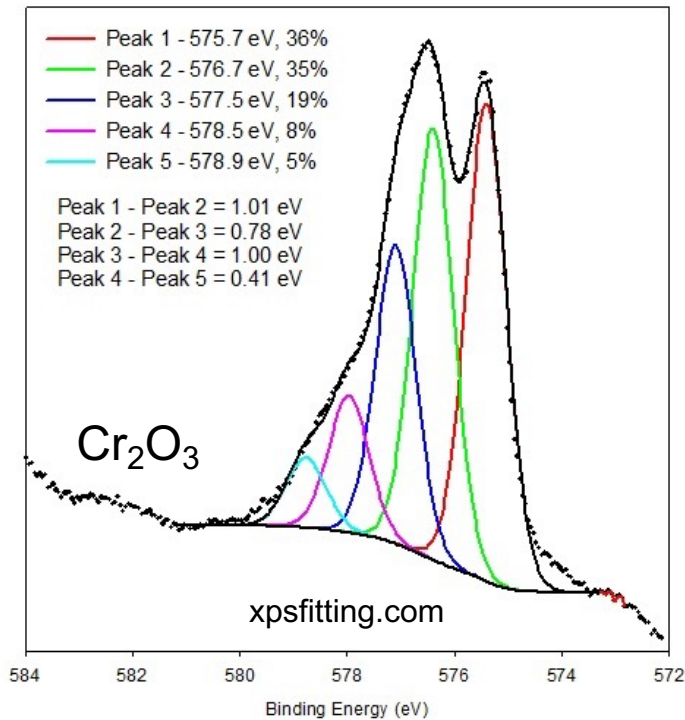


Extra “satellite” peaks appear on the lower kinetic energy (higher binding energy side)



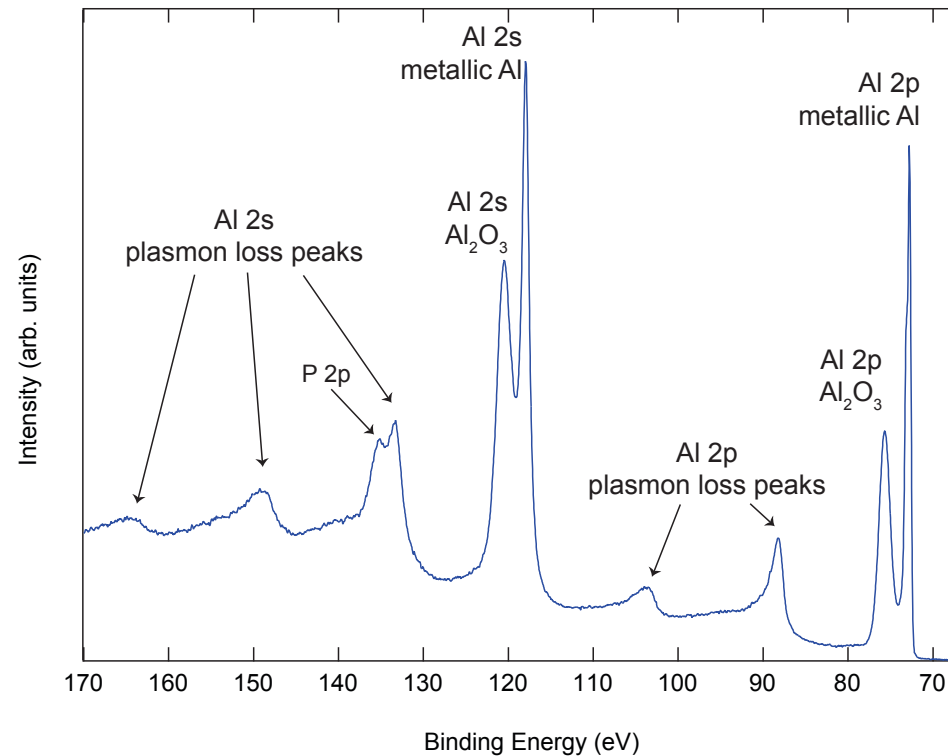
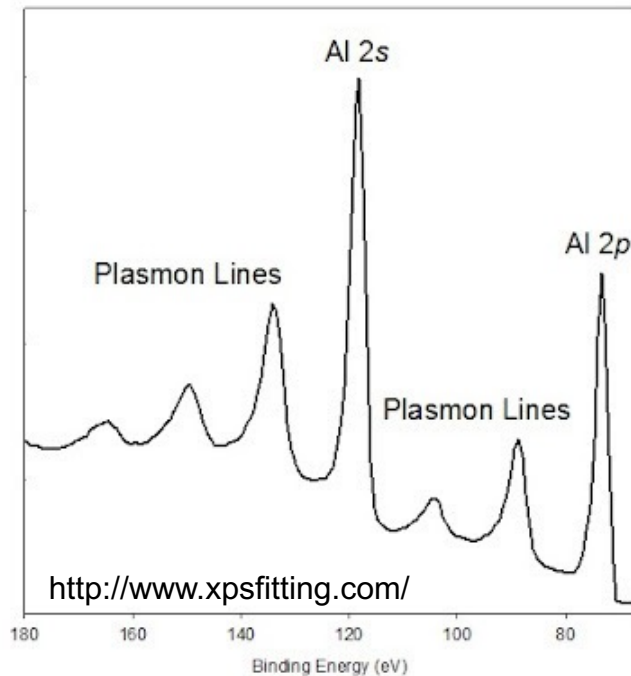
Multiplet Splitting

- Observed for compounds that have unpaired electrons in the valence band
- Unpaired core electron interacts with unpaired valence electron, creating multiple possible final states



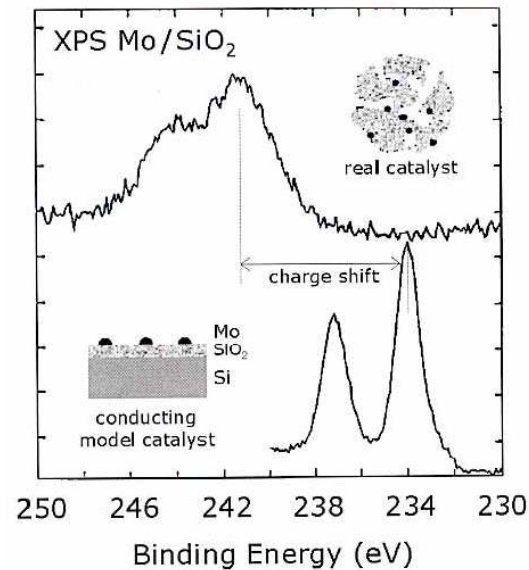
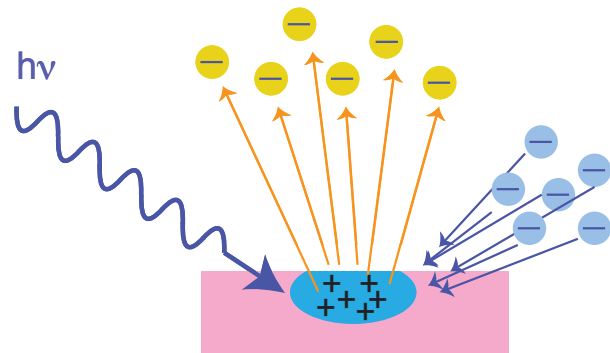
Plasmon Loss

- Usually observed for metallic surfaces
- Outgoing photoelectron excites collective oscillations of electrons in the conduction band
- Photoelectron suffers energy loss and extra peaks appear at low KE/high BE at discrete energy values
- Can be strong for Al, which can interfere with other peaks in the region

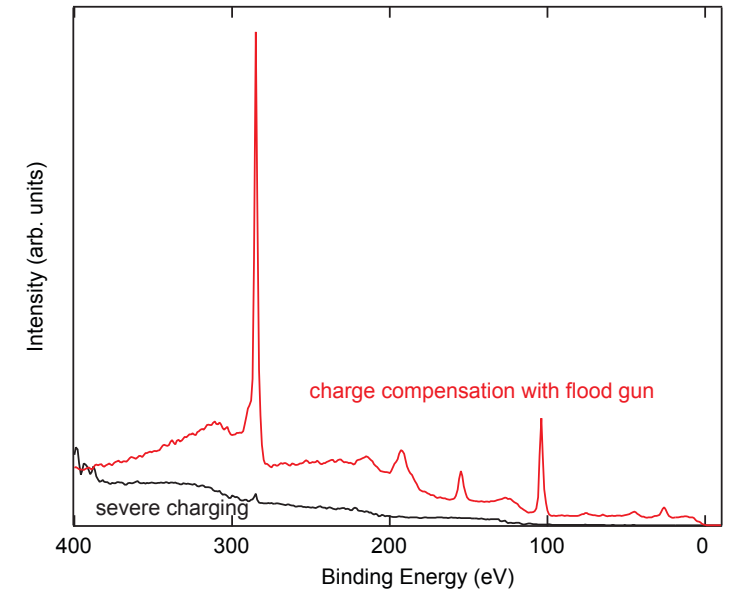


Charging and Charge Compensation

- Photoionization process causes positive charge on the surface
- For grounded electrically conductive samples, the charge is automatically neutralized
- For semi-conductive and insulating samples, the positive charge accumulates, photoelectron KE decreases
- Effect: shift to higher BE, peak broadening, double peaks, sometimes no peaks at all
- Charge compensation: add electrons back to the sample (use an electron flood gun, or with the presence of ambient gases)



J. W. Niemantsverdriet, Spectroscopy in Catalysis: An Introduction, 3rd. ed. Wiley (2007)



Spectra from IOS (23-ID-2) beamline, NSLS-II

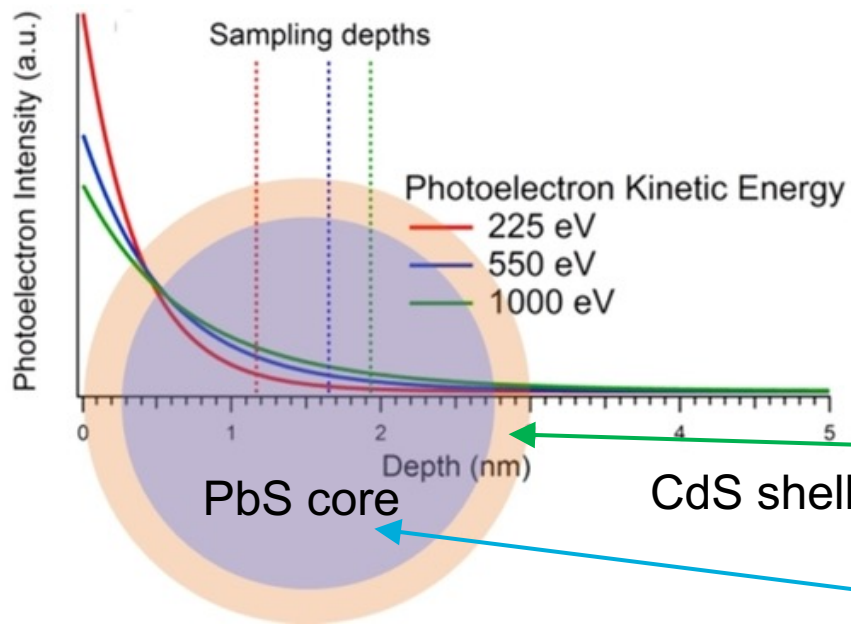
Part 3

Recent Research Examples

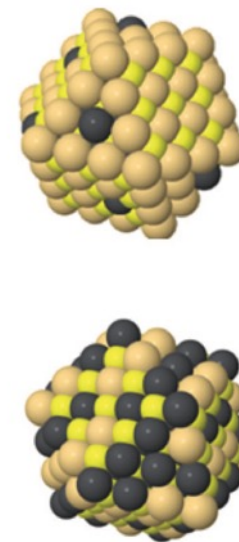
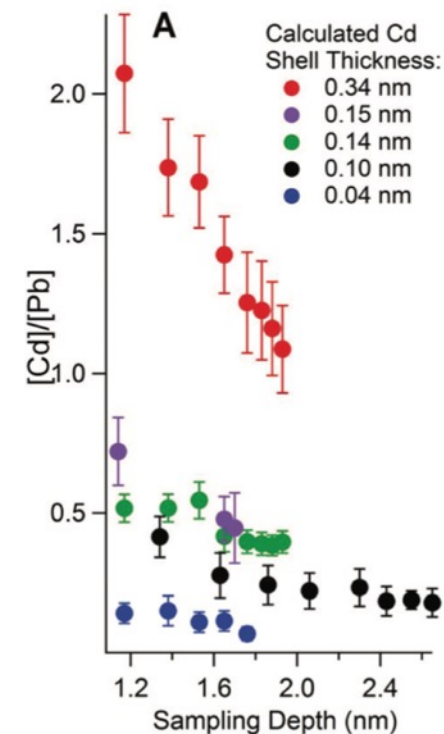
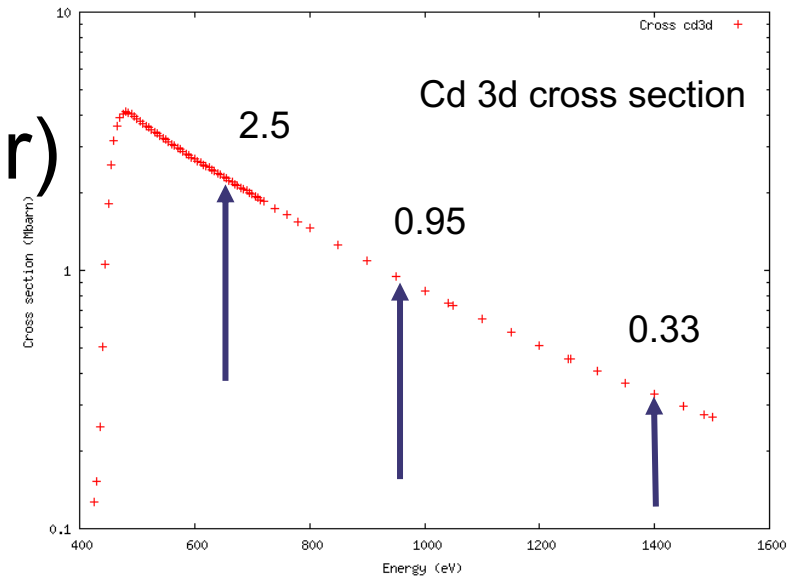
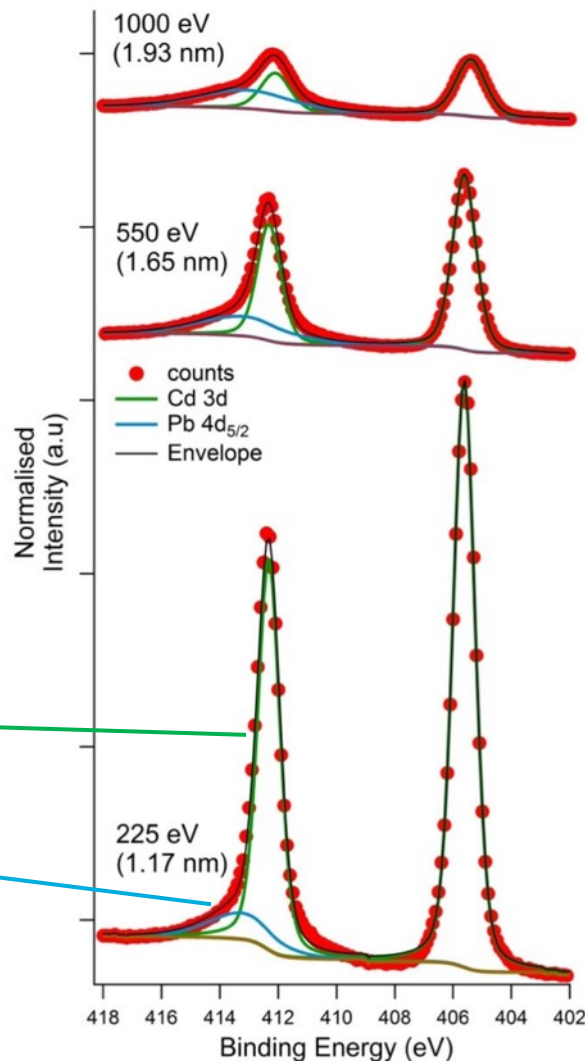
Studying Quantum Dots with XPS

(Wendy Flavell, University of Manchester)

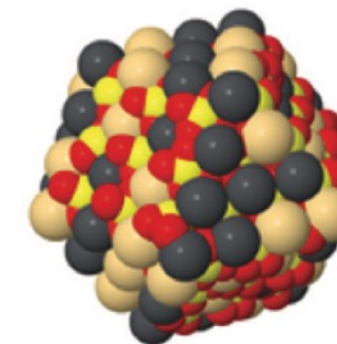
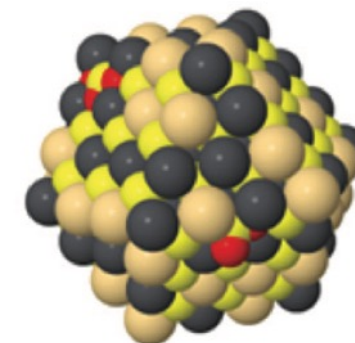
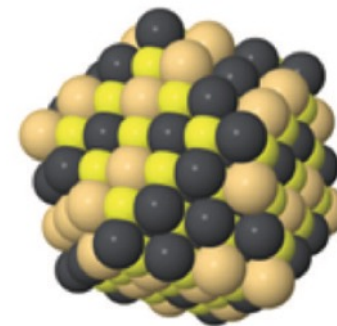
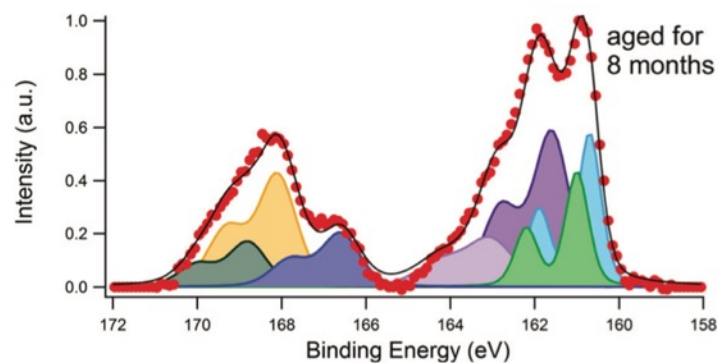
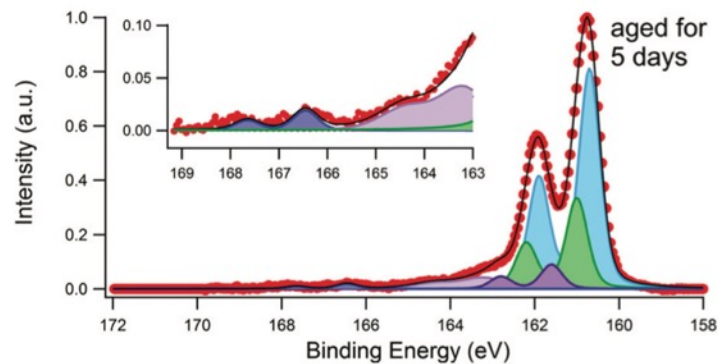
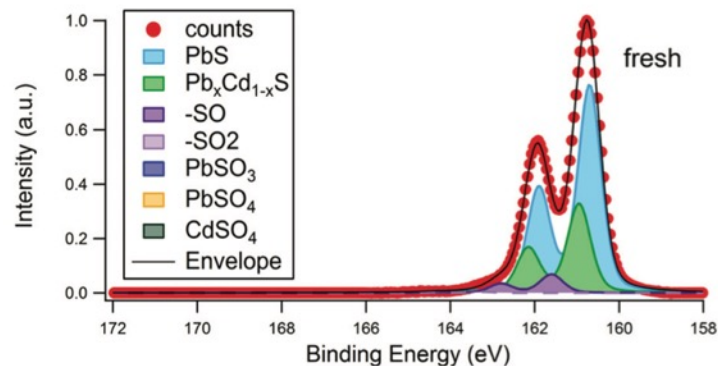
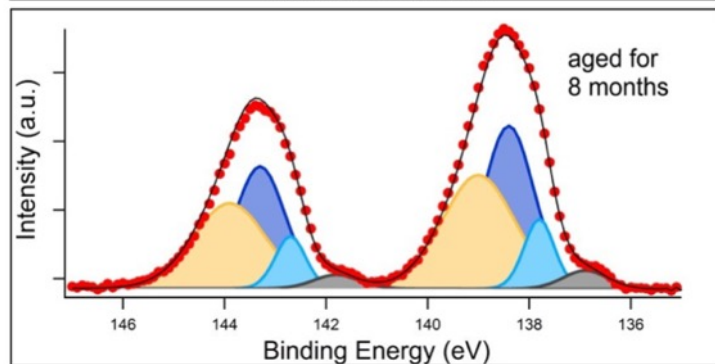
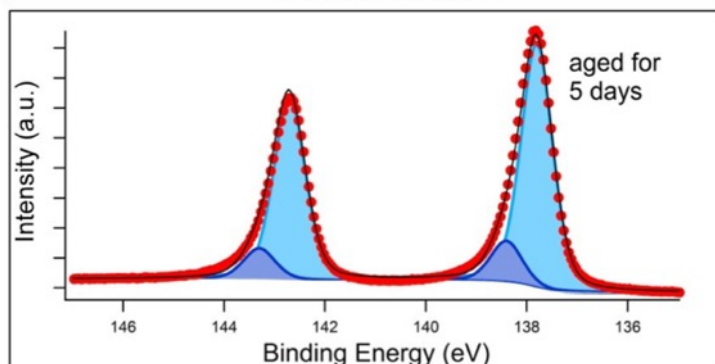
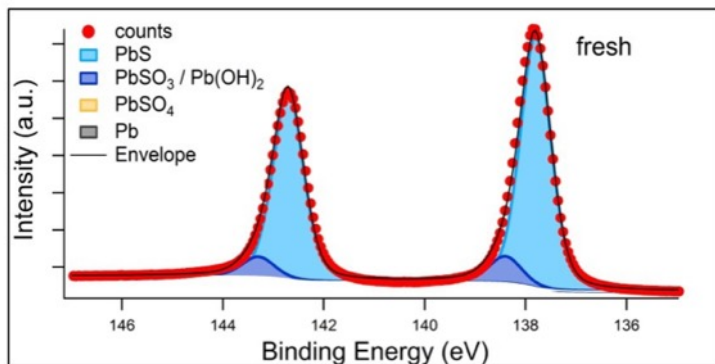
XPS was used to study the passivating effect of Cd in PbS/CdS colloidal quantum dots



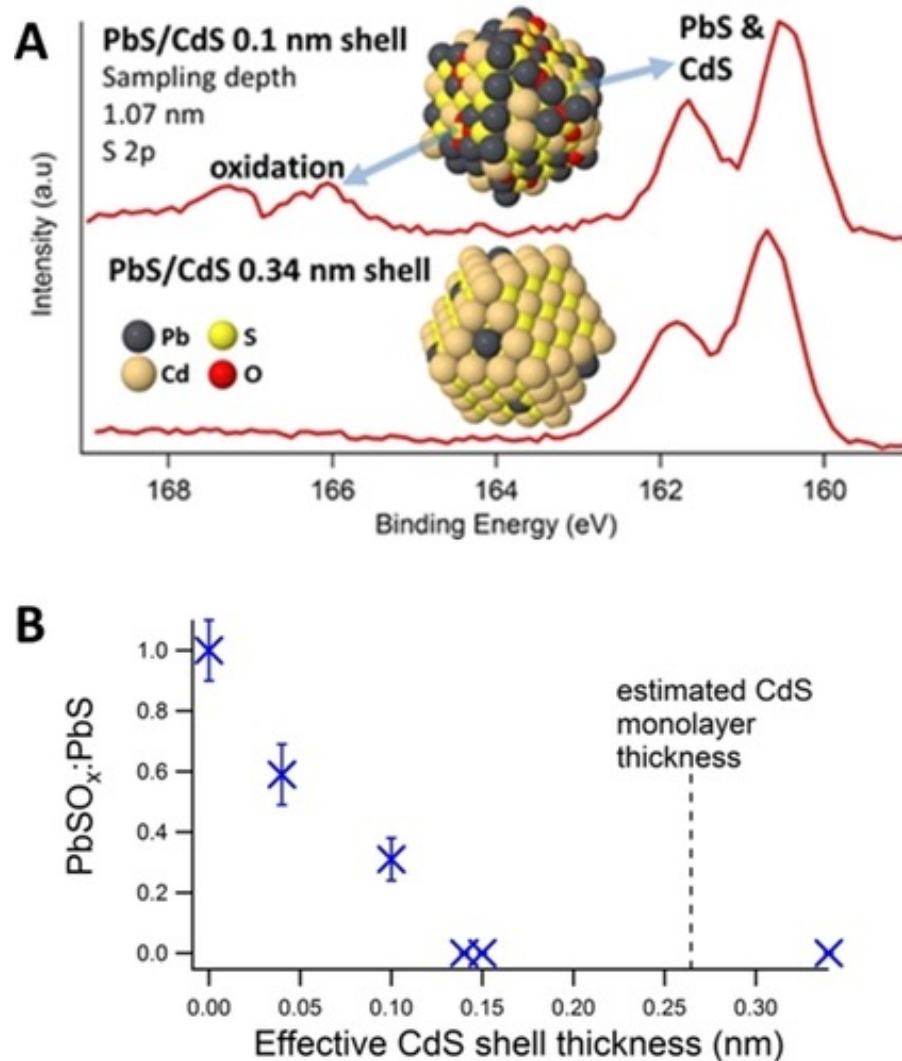
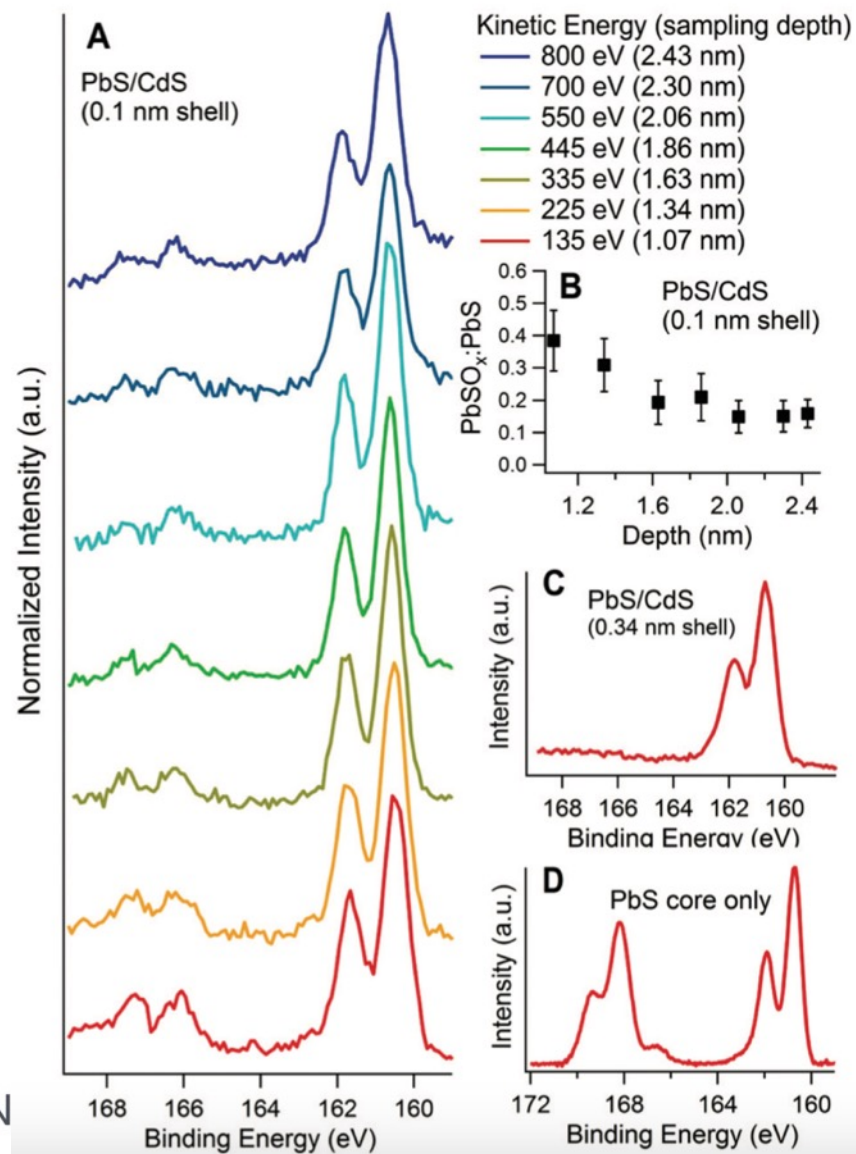
Clark et al. *Nanoscale*, 9, 6056–6067 (2017)
National Synchrotron Light Source II



The Effect of Aging in Air



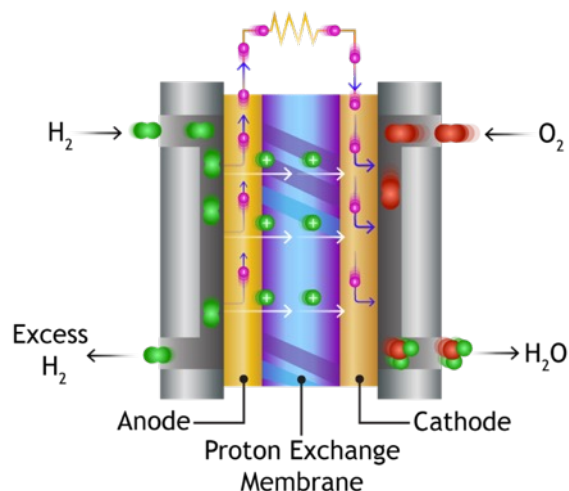
Passivating Effect of Cd



Single-Atom Catalysis

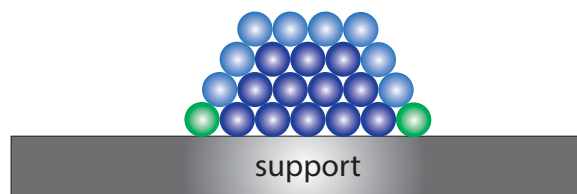


thermofisher.com



<https://web.stanford.edu/group/frankgroup/>

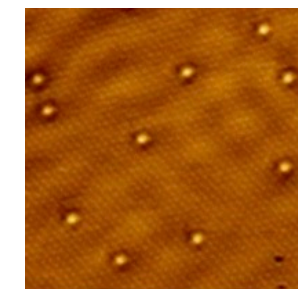
- Precious metals (e.g. Pt, Pd, Rh) are highly active but expensive catalysts
- Single-atom catalyst approach: minimize the amount of active but expensive catalyst (e.g. Pt) by supporting it on a cheaper and more abundant material
- Reduces cost and optimize catalytic efficiency



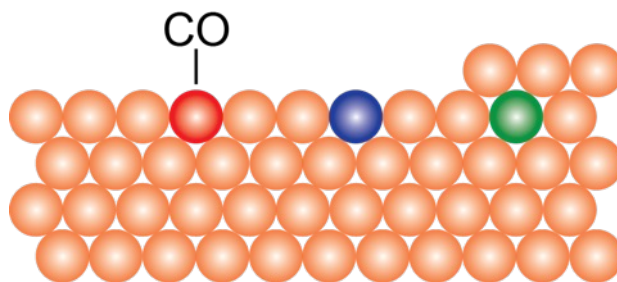
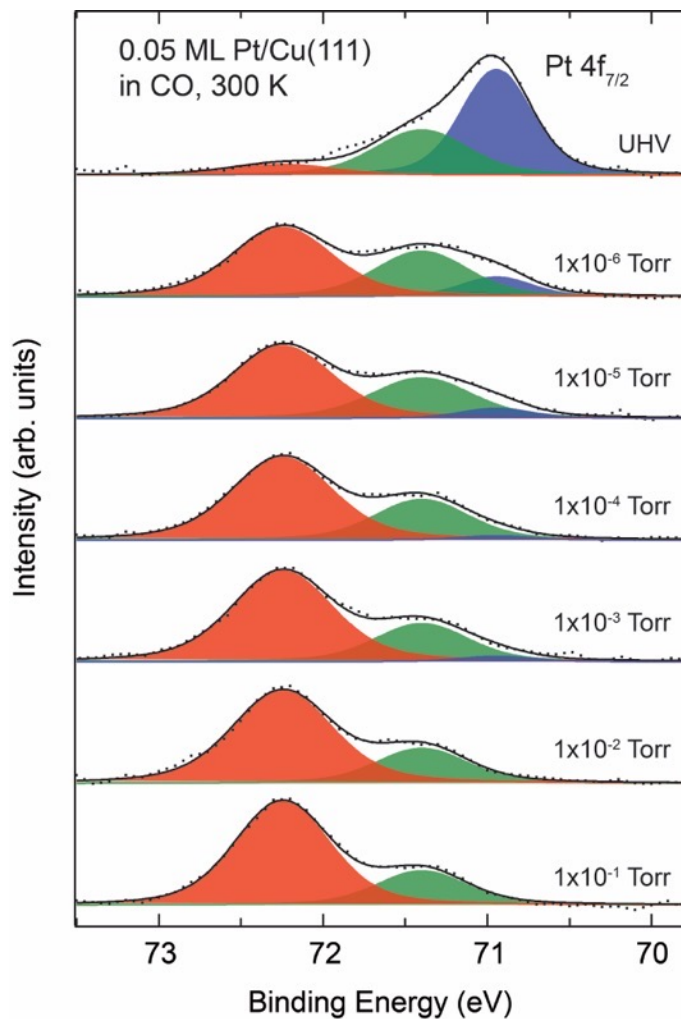
Metal	Price per oz
Pt	\$978
Pd	\$1,440
Rh	\$10,100
Ni	\$0.70
Cu	\$0.28

www.dailymetalprice.com (updated March 2023)

PtCu single atom alloy (SAA) → < 5% Pt forms isolated Pt atoms alloyed in the top layer of Cu metal

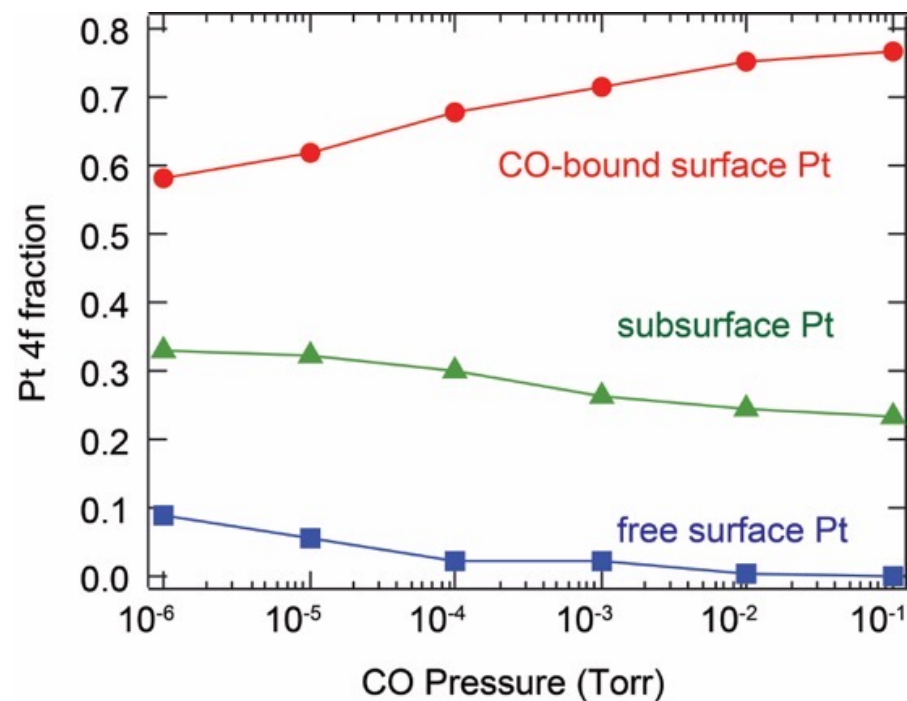


CO Adsorption on PtCu Single-Atom Alloy



Three types of Pt atoms:

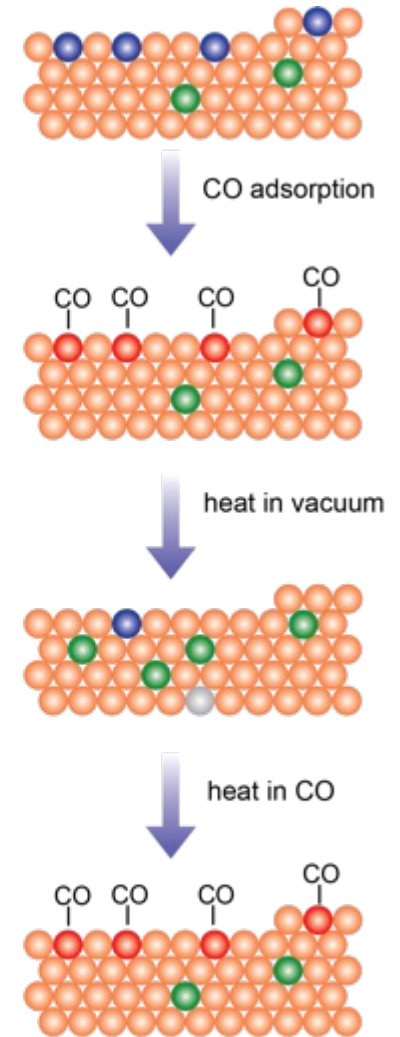
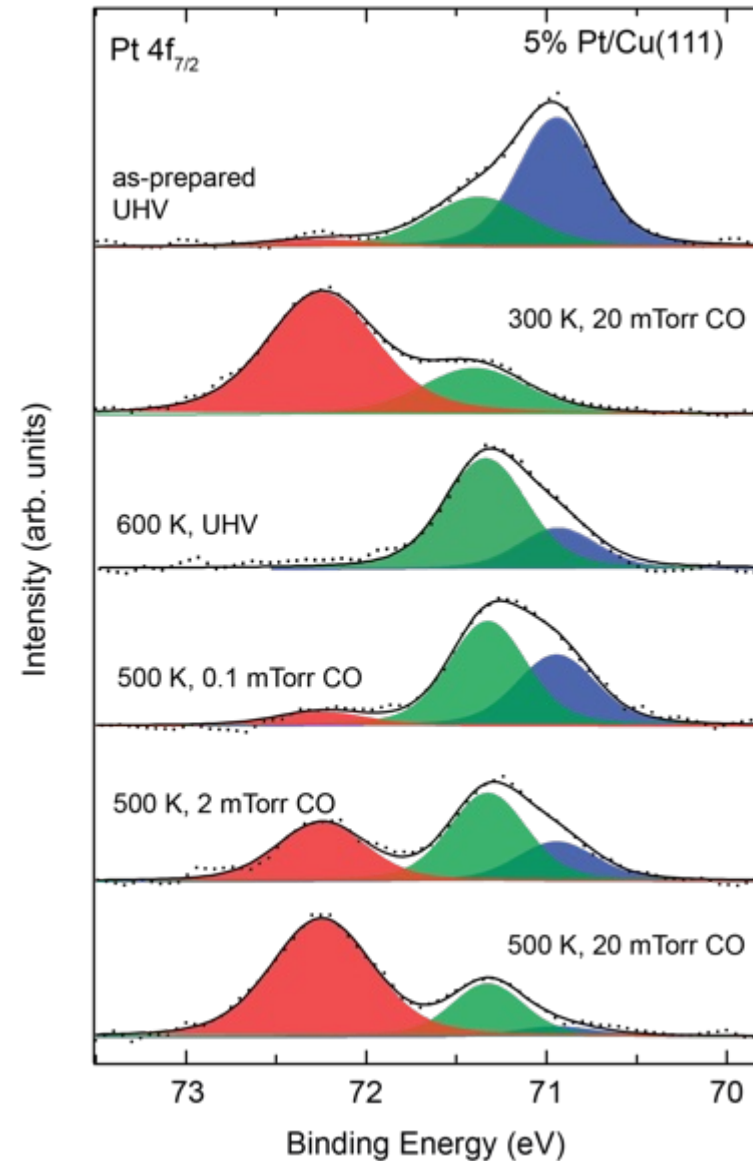
- Free surface Pt
- CO-bound surface Pt
- Subsurface Pt



Dynamic Surface State of PtCu SAA

- AP-XPS can track changes in the surface and near surface composition
- Heating in vacuum causes loss of active surface Pt
- Pt moves to subsurface and bulk of Cu
- Heating in CO causes surface segregation of Pt back up to the surface
- Initial surface composition is recovered

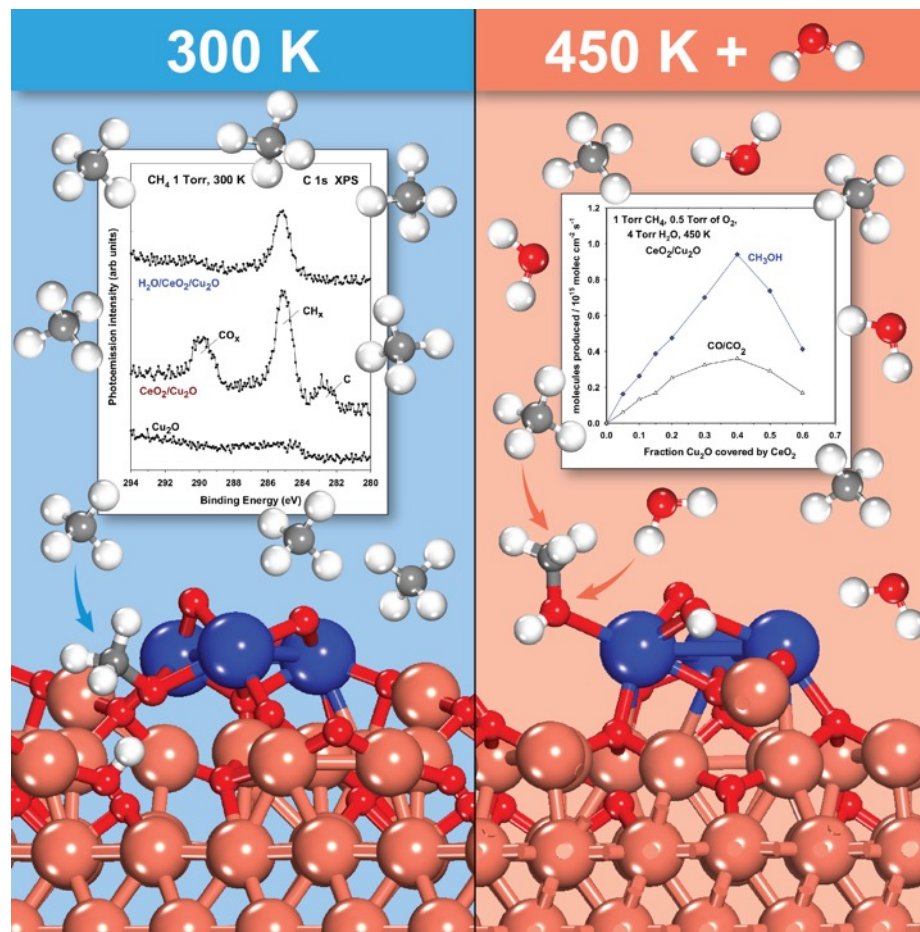
Simonovis et al. J. Phys. Chem. C 122, 4488 (2018)



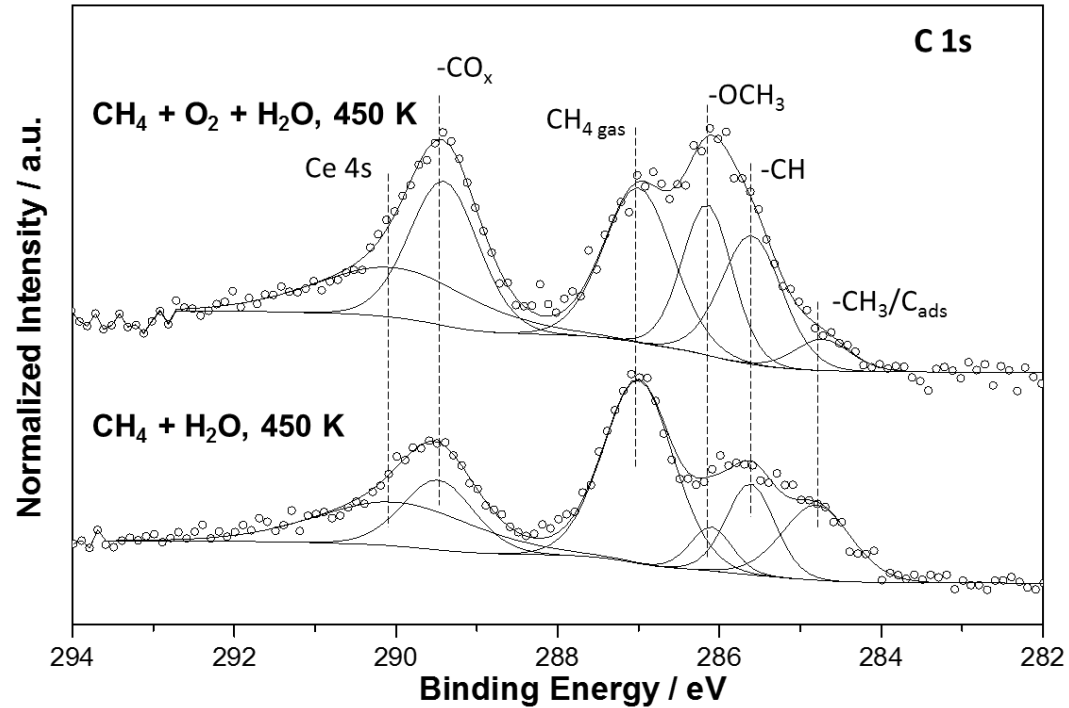
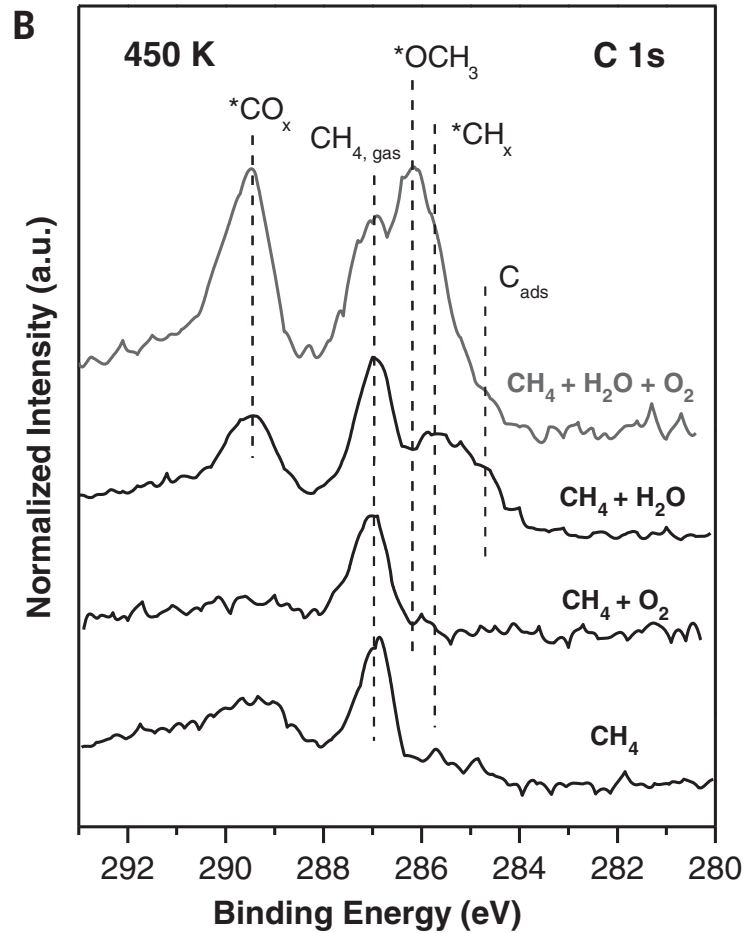
Watching Catalyst in Action (CRS Group, BNL Chemistry)

- Methane oxidation to methanol is a difficult process that requires high temperatures (600 K)
- A new catalyst was developed for low temperature methane oxidation promoted by water
- The catalyst: $\text{CeO}_2/\text{Cu}_2\text{O}/\text{Cu}(111)$
- The reactants: $\text{CH}_4 + \text{O}_2 + \text{H}_2\text{O}$
- How does this catalyst work?
- AP-XPS is a powerful tool for identifying reaction intermediates

Zuo et al. J. Am. Chem. Soc. 138, 13810 (2016)
<https://www.bnl.gov/newsroom/news.php?a=26694>

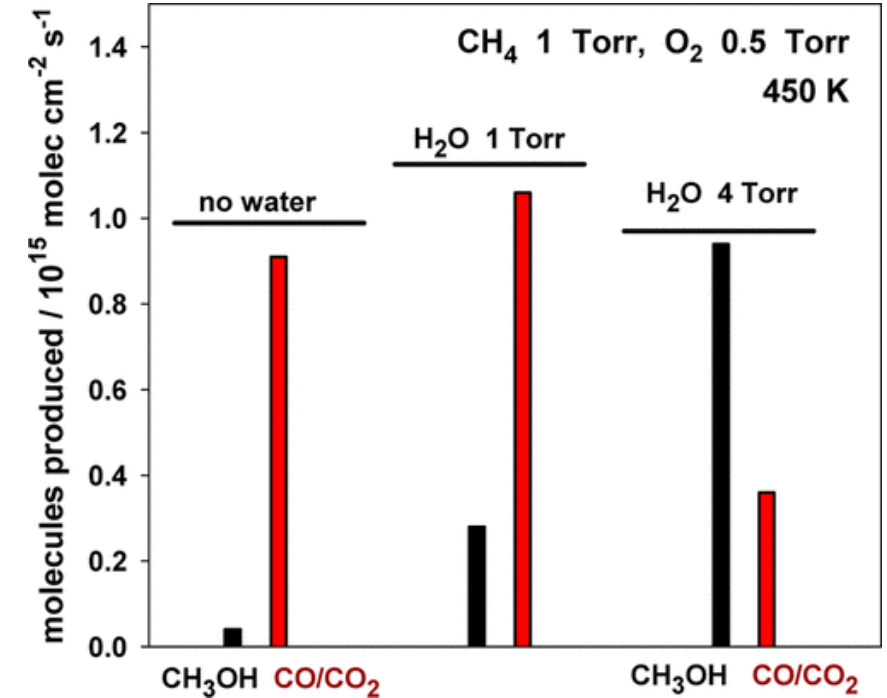
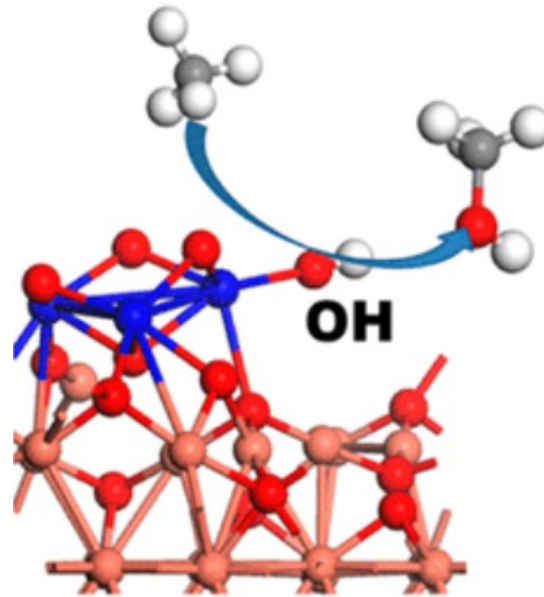
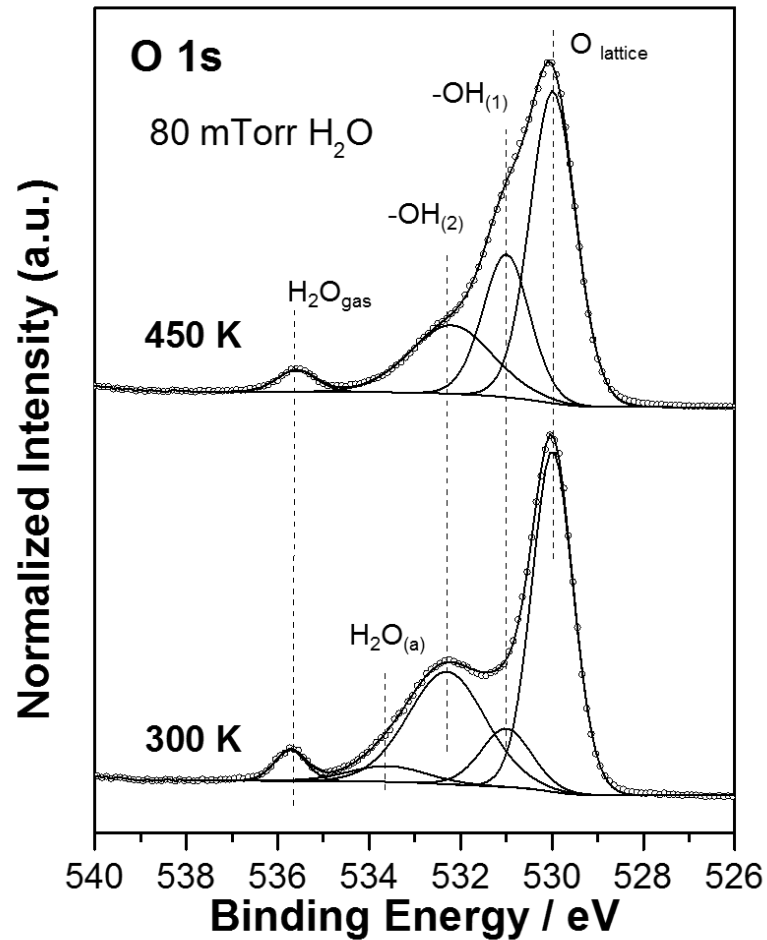


Converting Methane to Methanol



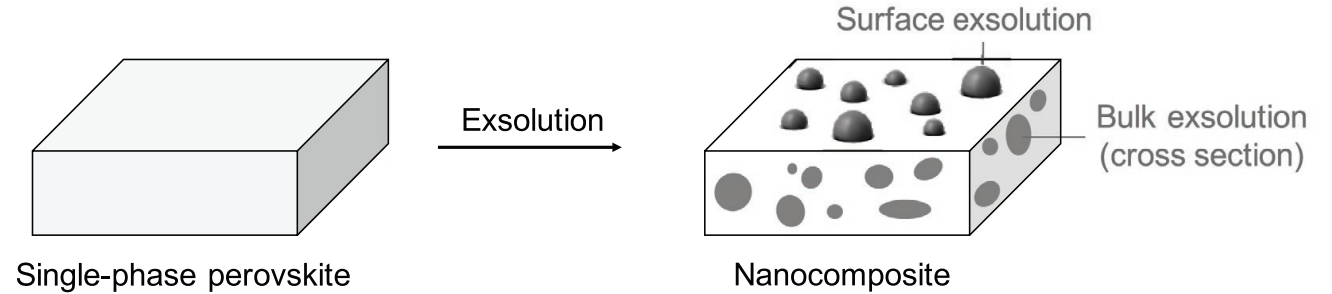
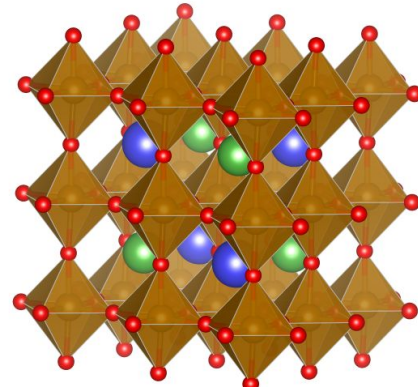
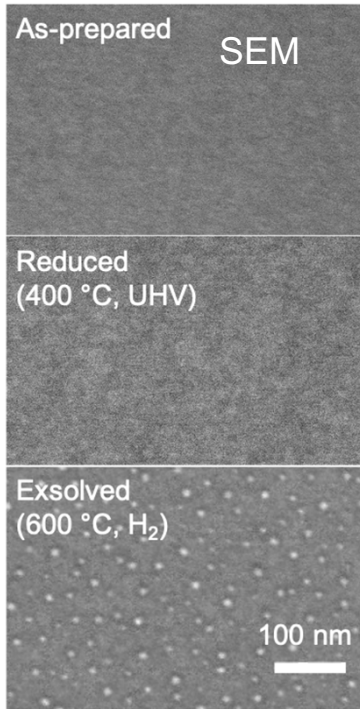
The formation of methoxy (precursor to methanol) is enhanced in the presence of water

Converting Methane to Methanol

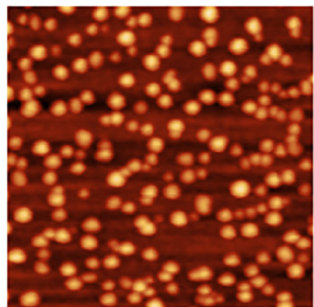


- Water is dissociated to hydroxide species on the surface

Metal exsolution from perovskites - Yildiz group (MIT)



- Metals can exsolve from bulk perovskite under high temperature reduction condition, forming stable nanoparticles on the surface
- Synthesis method for highly stable, oxide-supported metal nanoparticles with applications in energy conversion and storage technologies
- Metal nanoparticles are uniformly distributed and resistant to agglomeration

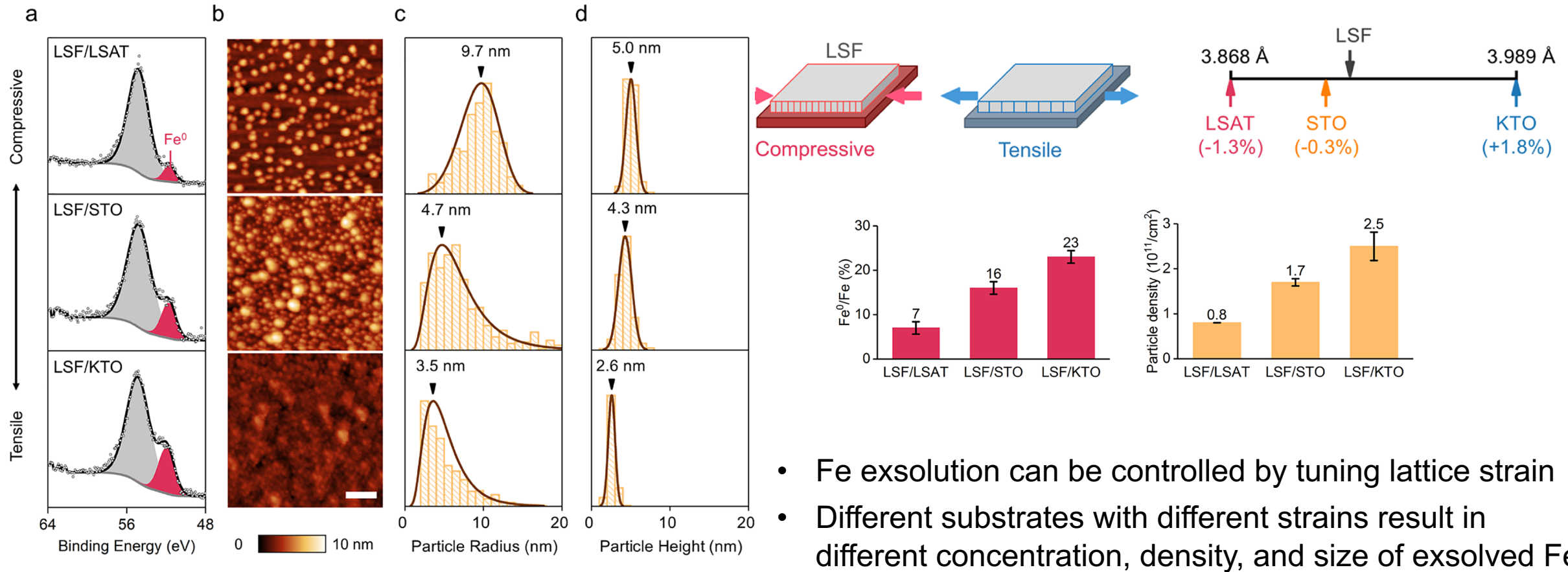


AFM

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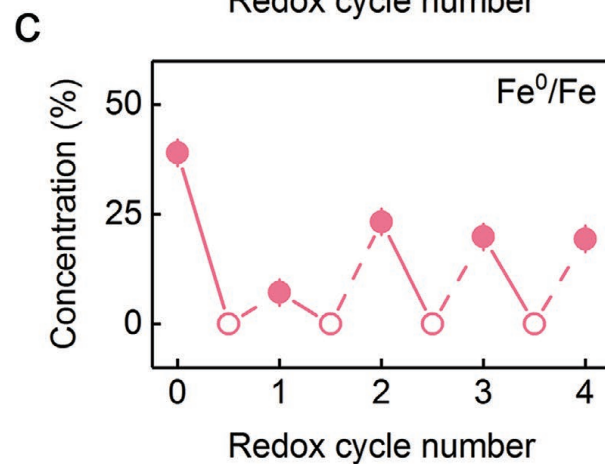
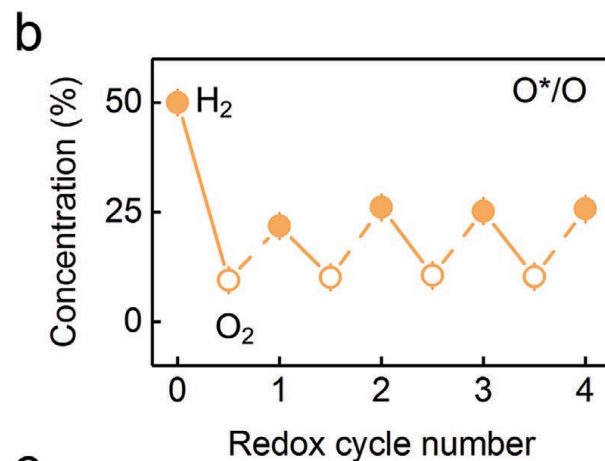
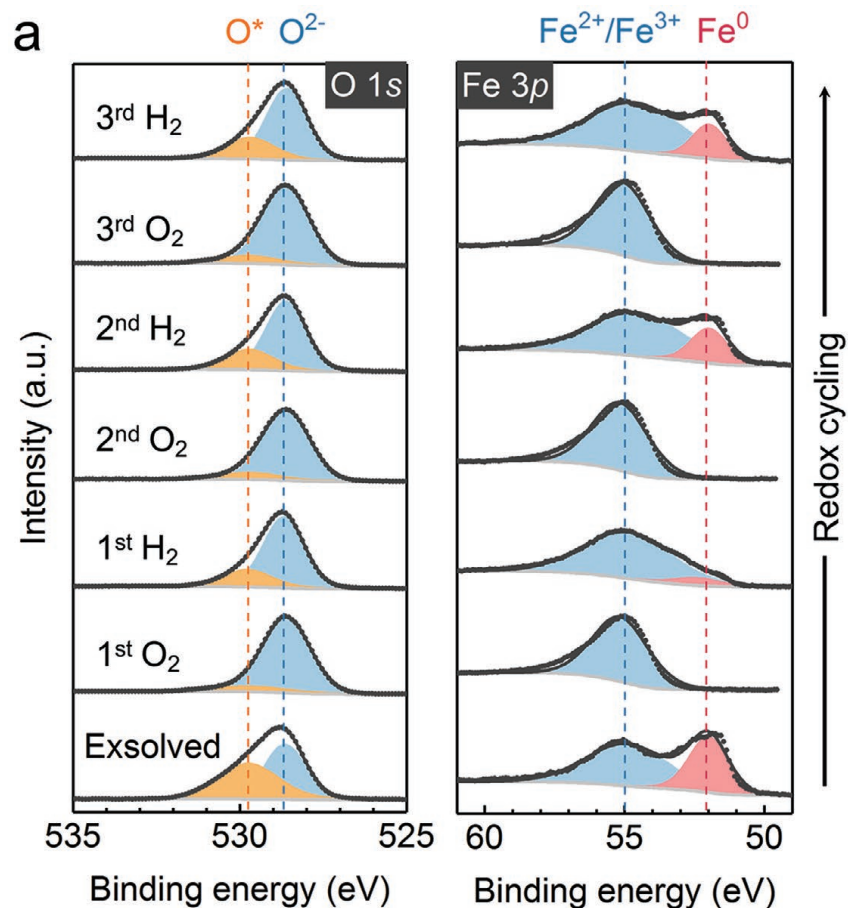
Wang et al. Chem. Mater. 33, 5021 (2021), Adv. Funct. Mater. 32, 2108005 (2022), Chem. Mater. 34, 5138 (2022)

Tuning Fe exsolution

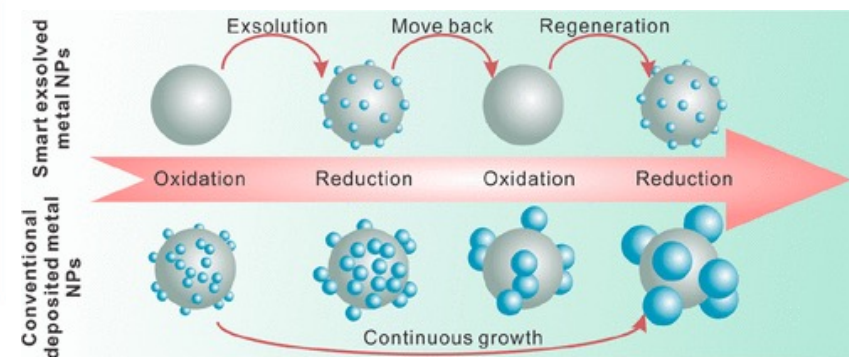


- Fe exsolution can be controlled by tuning lattice strain
- Different substrates with different strains result in different concentration, density, and size of exsolved Fe

Redox Cycling of Exsolved LSF



- Exsolved Fe on LSF is stable under repeated oxidation and reduction cycles



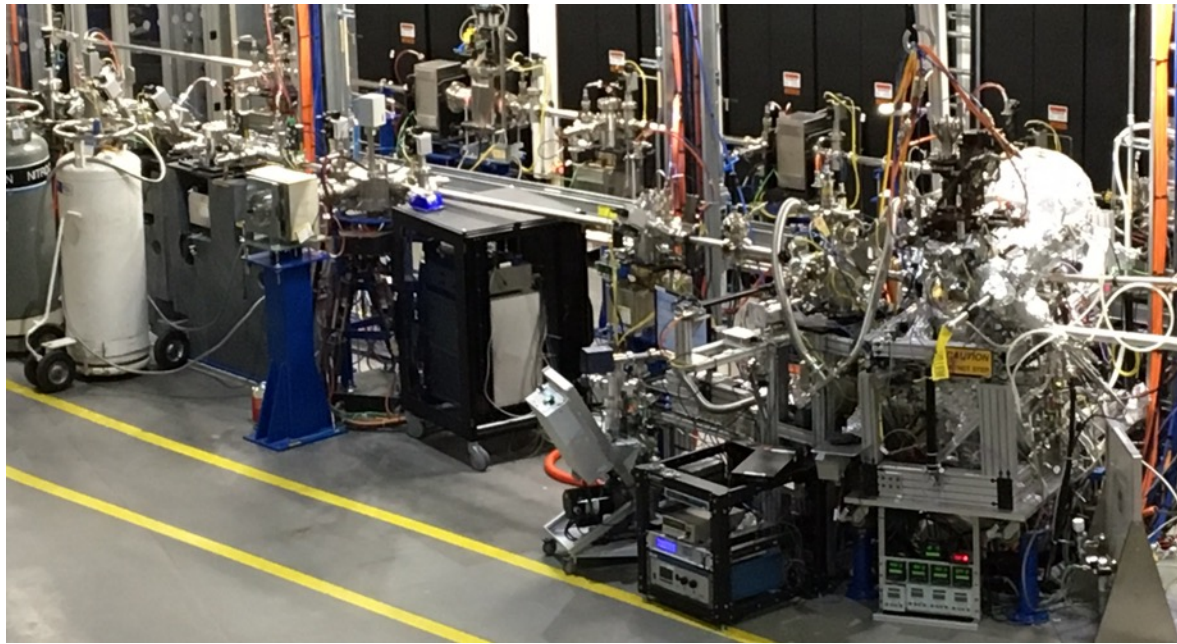
Summary

- XPS is a powerful technique for the surface characterization of materials
- It provides:
 - Elemental specificity
 - Chemical sensitivity
 - Depth profiling
 - Quantitative analysis
- Synchrotron-based XPS offers high flux, high resolution, and energy tunability
- Aspects that affect data interpretation: overlaps with Auger peaks, shake-up/off, multiplet splitting, plasmon peaks, charging
- XPS usually needs UHV conditions, but ambient pressure XPS can be performed for in situ/operando experiments

Useful Online Resources

- X-ray data booklet: <https://xdb.lbl.gov>
- Photoionization cross-section: <https://vuo.elettra.eu/services/elements/WebElements.html>
- NIST XPS Database: https://srdata.nist.gov/xps/main_search_menu.aspx
- <http://www.xpsfitting.com>
- <https://xpssimplified.com/periodictable.php>
- <http://www.casaxps.com/ebooks/XPS%20AES%20Book%20new%20margins%20rev%201.2%20for%20web.pdf> – CasaXPS is a popular XPS data analysis software. Their manual has a lot of useful basic information about XPS

AP-XPS at IOS (23-ID-2) Beamline, NSLS-II

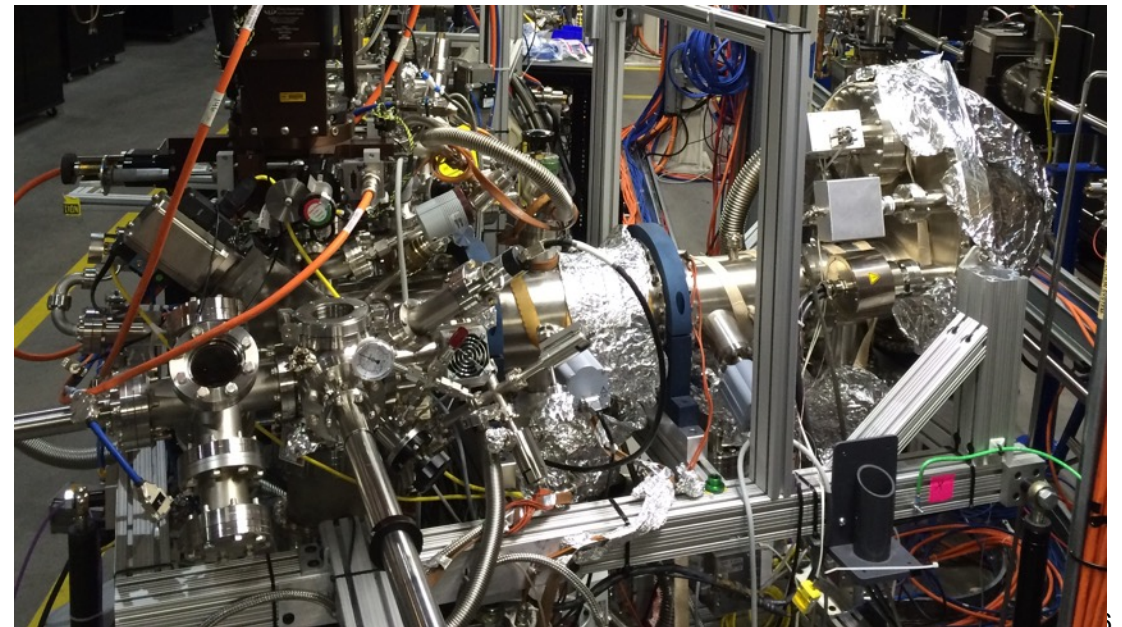


- Pressure = UHV to 10 Torr
- Sample temperature: RT to 900°C
- Sputter gun, flood gun, metal evaporator, RGA mass spec

- Samples: single crystals, thin films, powders
- Gases: H₂, O₂, CO, CO₂, noble gases, C1-C4 hydrocarbons, water vapor, C1-C3 alcohol vapors

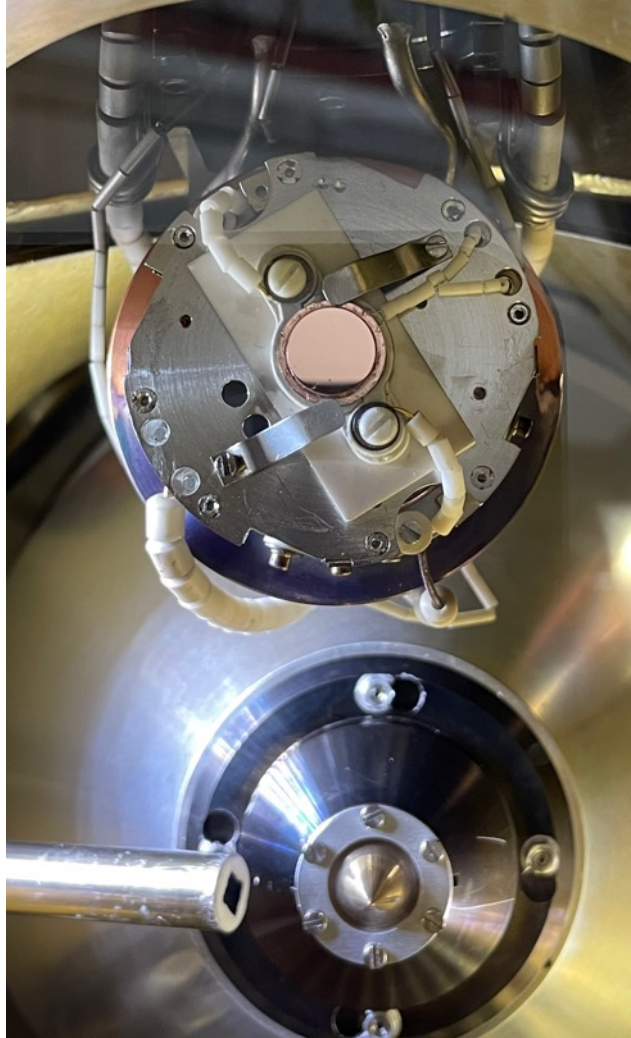
<https://www.bnl.gov/nsls2/beamlines/beamline.php?r=23-ID-2>

National Synchrotron Light Source II

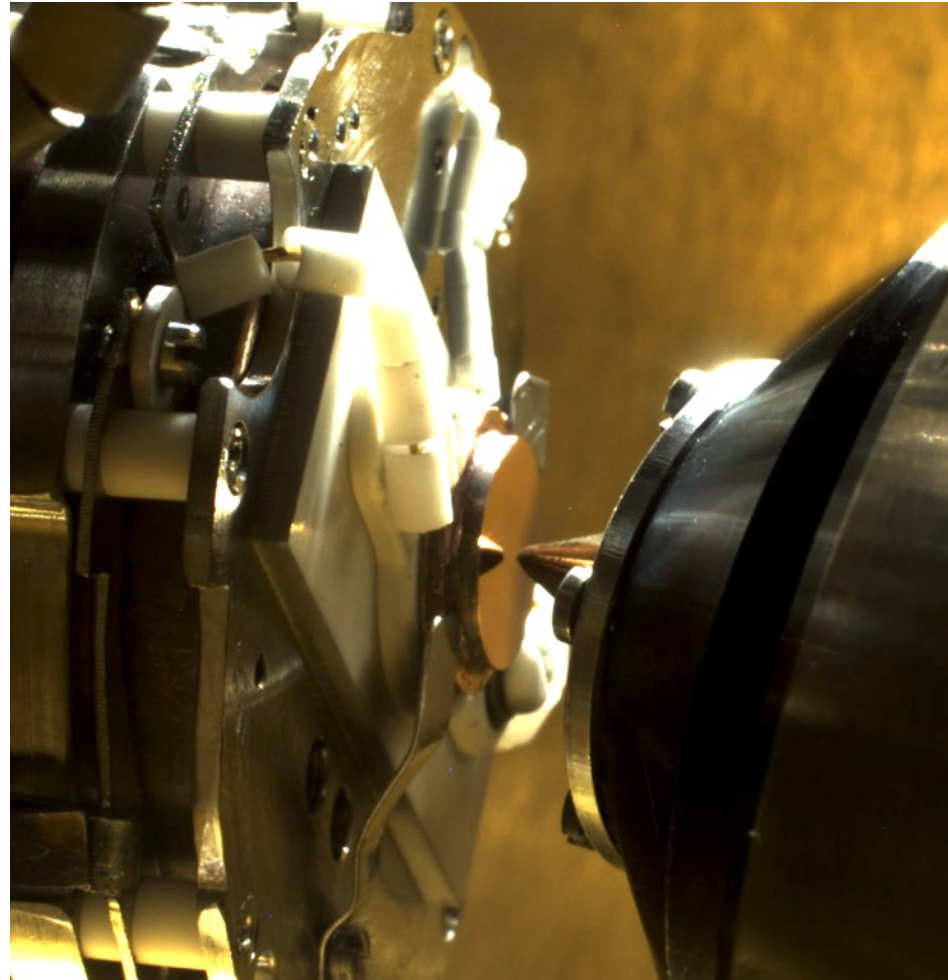


Photos from IOS (23-ID-2) beamline, NSLS-II

AP-XPS at IOS Beamline, NSLS-II

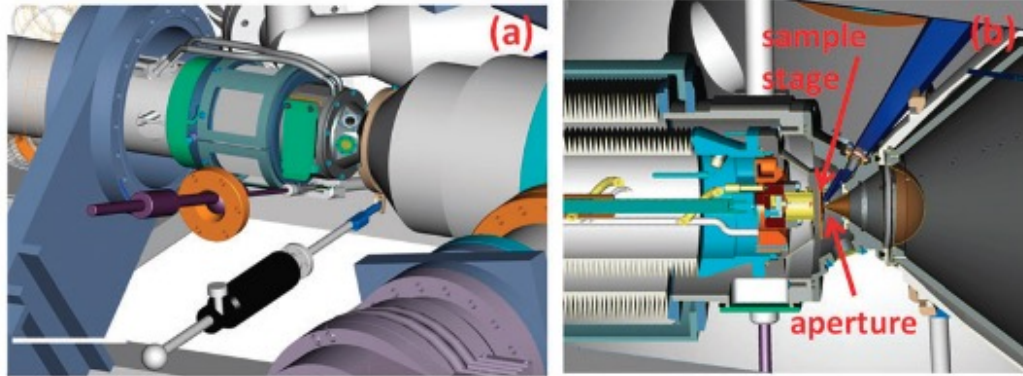


National Synchrotron Light Source II

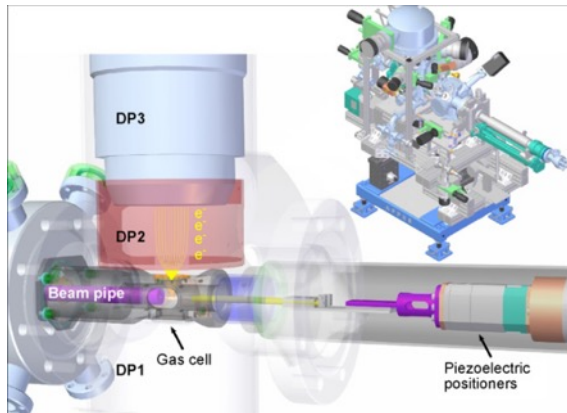


Photos from IOS (23-ID-2) beamline, NSLS-II

Other AP-XPS Setups

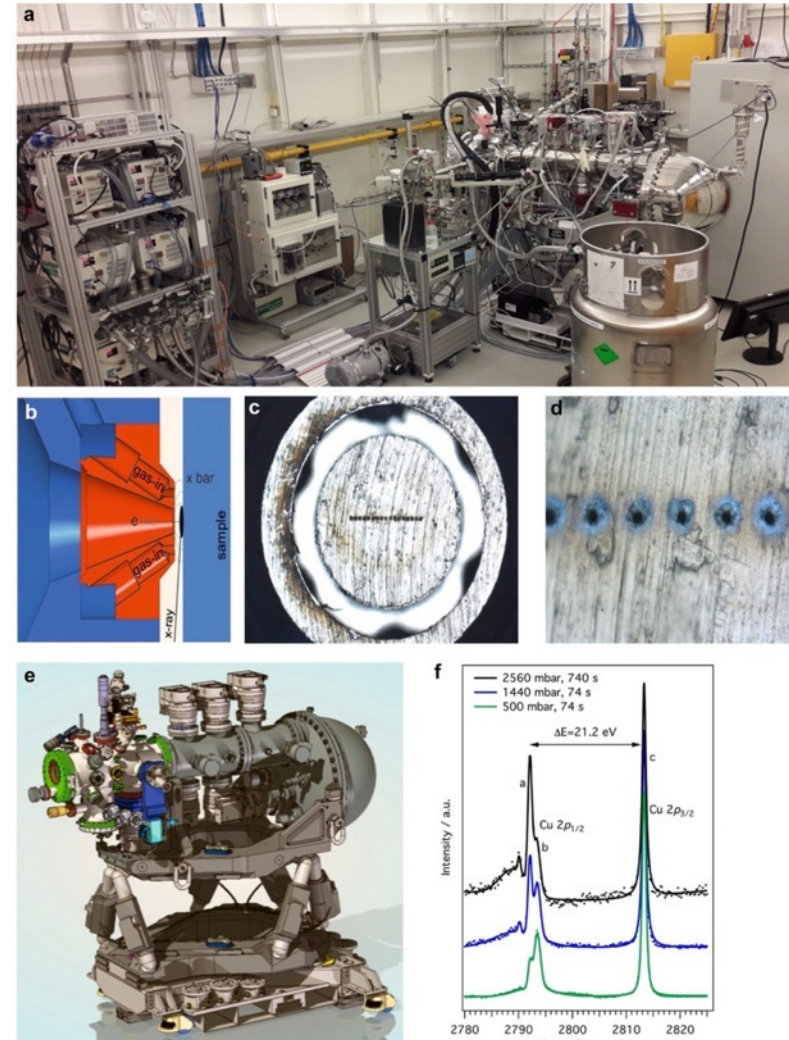


commercial high pressure cell from SPECS
 specs-group.com



custom high pressure cell at SSRL
 Kaya et al, Catal. Today 205, 101 (2013)

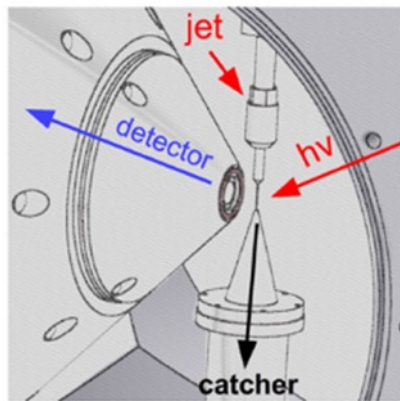
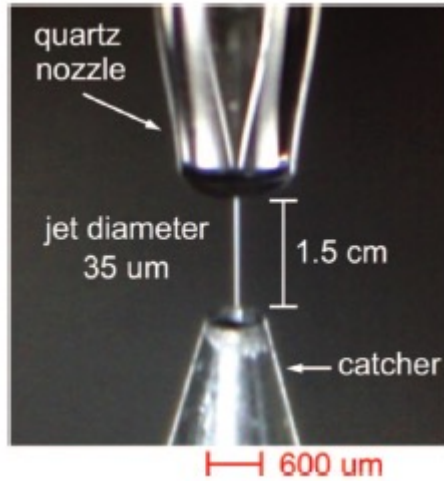
National Synchrotron Light Source II



POLARIS AP-HAXPES at PETRA III, DESY
 Degerman et al. Synchrotron Radiat. News, 35, 11-18 (2022)

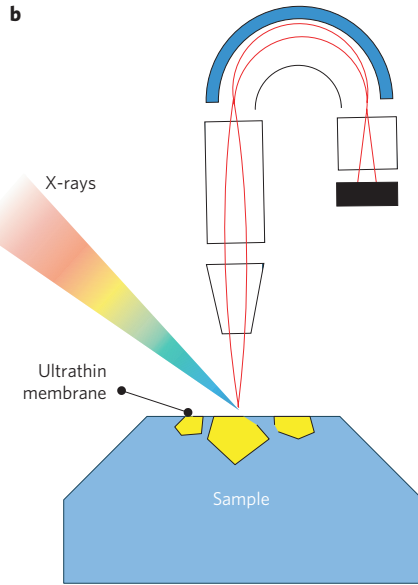
Liquid AP-XPS Setups

Liquid microjet

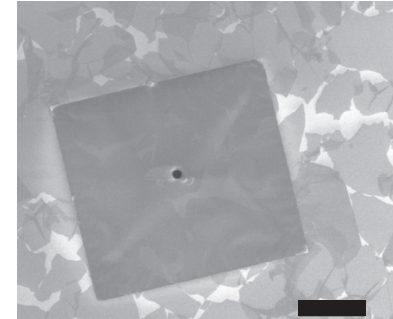


Brown et al., Nano Letters 13, 5403 (2013)

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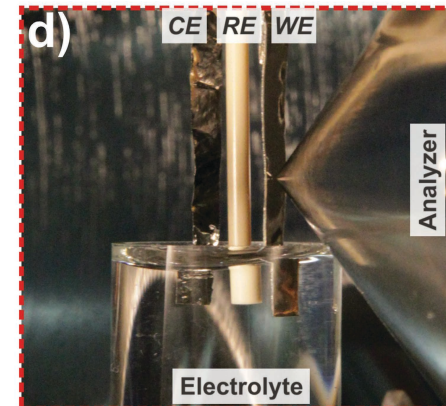
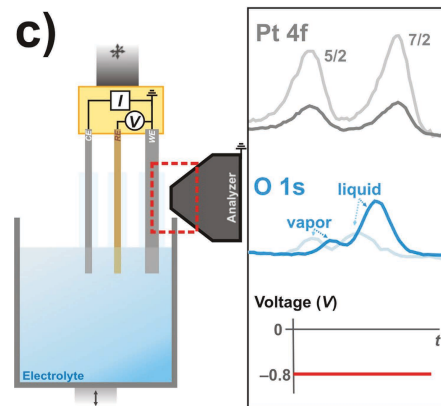


Graphene oxide window



Kolmakov et al. Nature Nanotech. 6, 651 (2011)

“Dip and pull” method



Axnanda et al. Scientific Reports 5, 09788 (2015)